Appendix A. Plots of System Verification

The plots for system verification are shown as follows.

.

Measurement Report
S01 System Check H835_240507
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.92	42.5

Hardware Setup

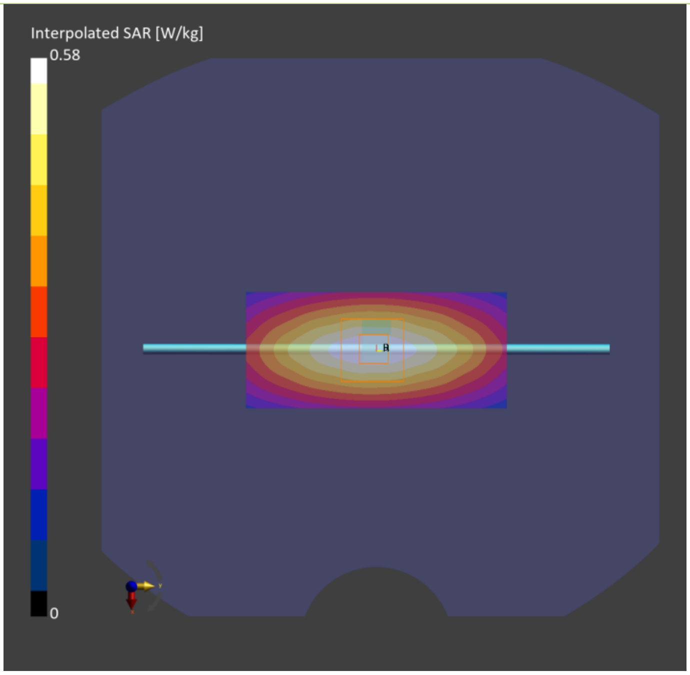
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.500	0.504
psSAR10g [W/kg]	0.329	0.335
Power Drift [dB]	0.01	0.05



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Measurement Report

S02 System Check H1900_240507

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.43	41.1

Hardware Setup

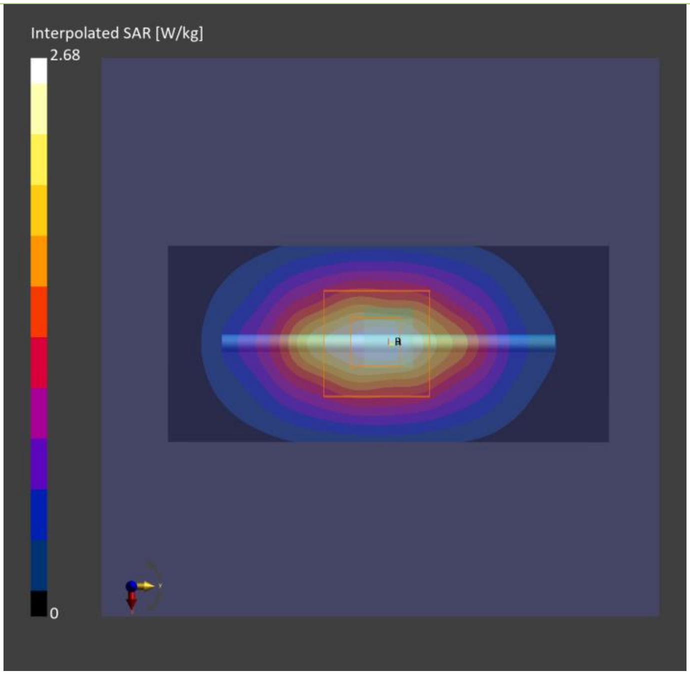
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	2.13	2.14
psSAR10g [W/kg]	1.11	1.14
Power Drift [dB]	0.04	-0.00



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Measurement Report

S03 System Check H1900_240415

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.46	40.9

Hardware Setup

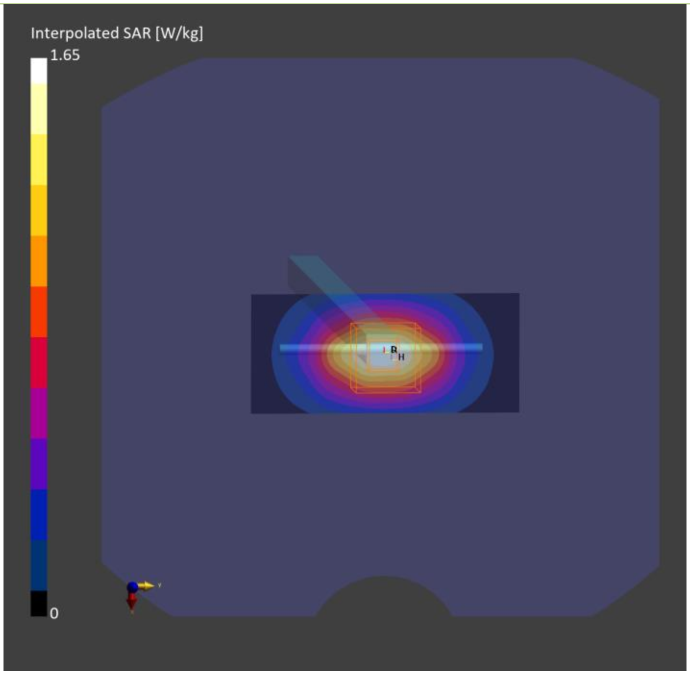
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	1.78	1.83
psSAR10g [W/kg]	1.071	1.079
Power Drift [dB]	-0.14	-0.03



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Measurement Report

S04 System Check H1750_240415

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.37	41.0

Hardware Setup

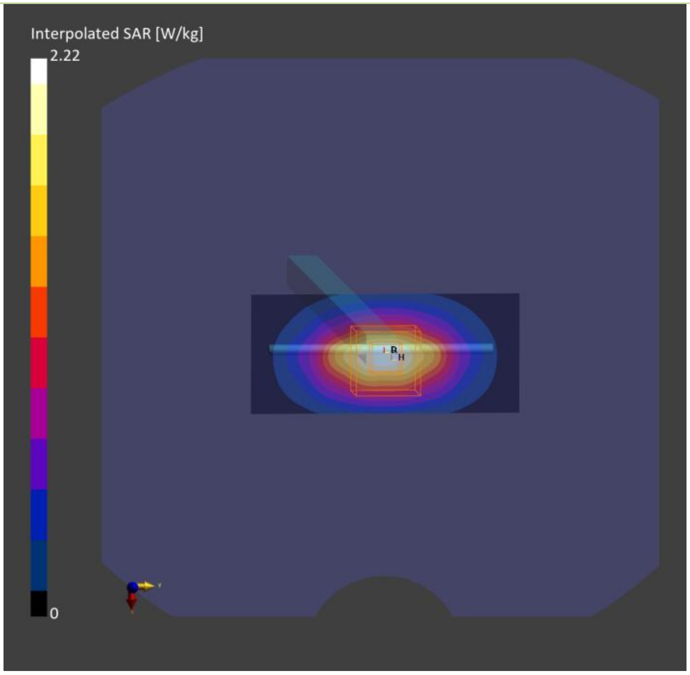
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	1.77	1.76
psSAR10g [W/kg]	0.938	0.933
Power Drift [dB]	-0.00	-0.00



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Measurement Report

S05 System Check H835_240415

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.94	43.1

Hardware Setup

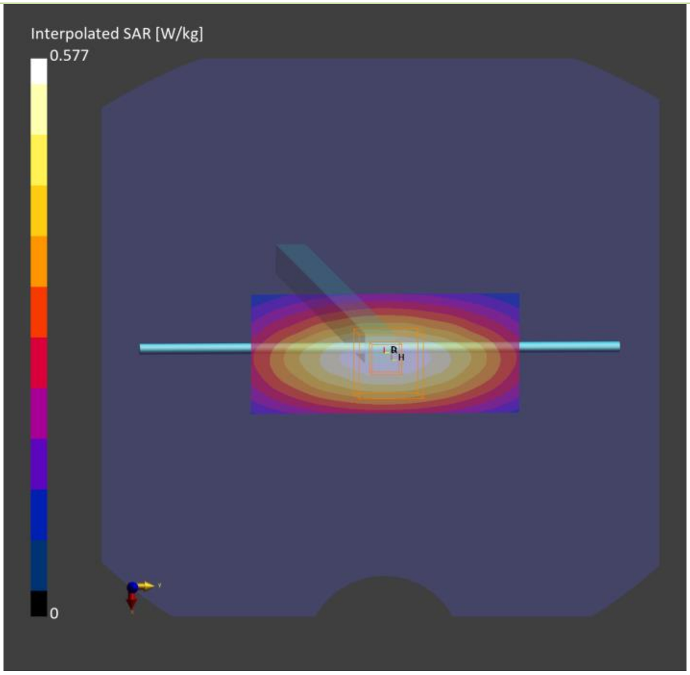
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.499	0.498
psSAR10g [W/kg]	0.328	0.325
Power Drift [dB]	0.01	0.00



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Measurement Report

S06 System Check H1900_240418

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	40.7

Hardware Setup

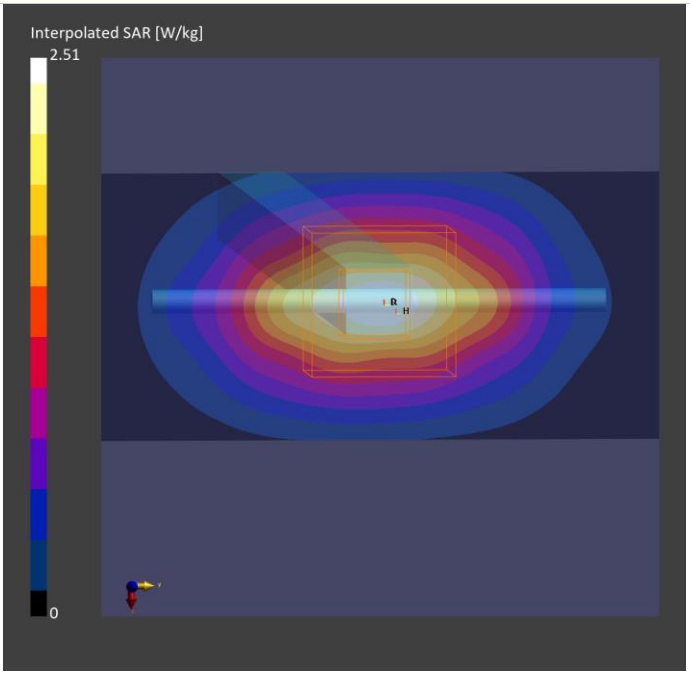
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	1.99	2.00
psSAR10g [W/kg]	1.02	1.03
Power Drift [dB]	-0.04	-0.14



Plots of System Verification

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S07 System Check H1750_240418

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.36	40.9

Hardware Setup

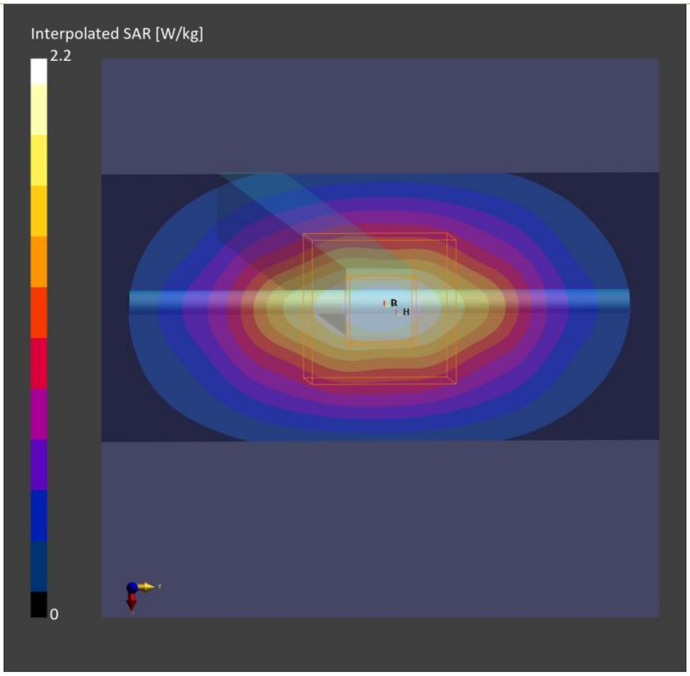
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	1.75	1.75
psSAR10g [W/kg]	0.925	0.928
Power Drift [dB]	-0.02	-0.05



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Measurement Report

S08 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

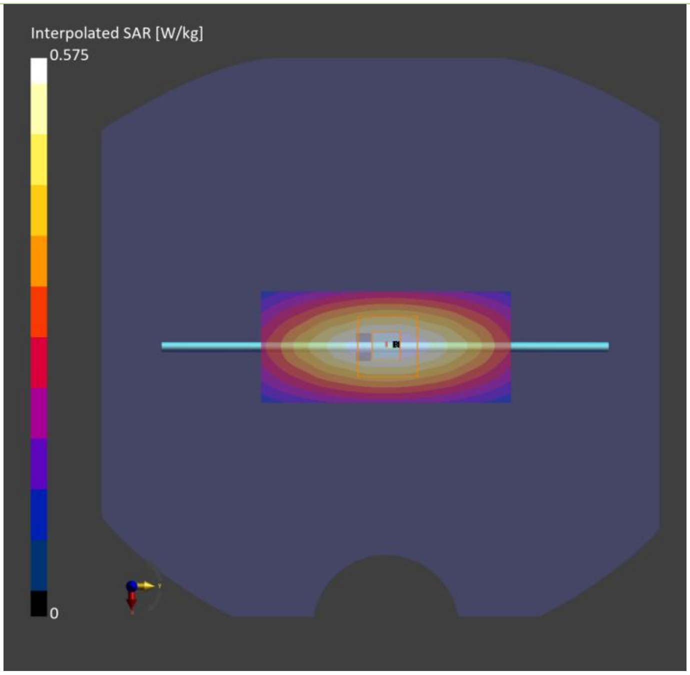
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



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Measurement Report

S09 System Check H2600_240418

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.94	39.7

Hardware Setup

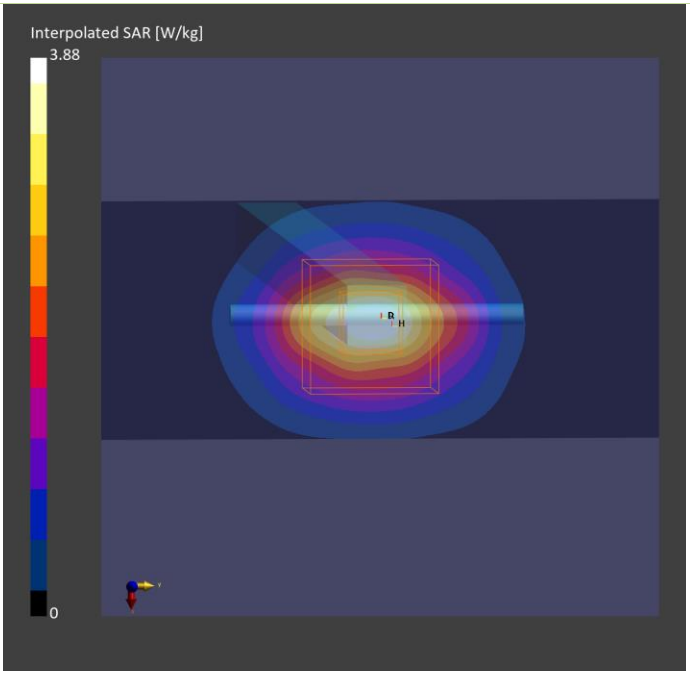
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	2.89	2.79
psSAR10g [W/kg]	1.28	1.24
Power Drift [dB]	-0.09	-0.19



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Measurement Report

S10 System Check H750_240416

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

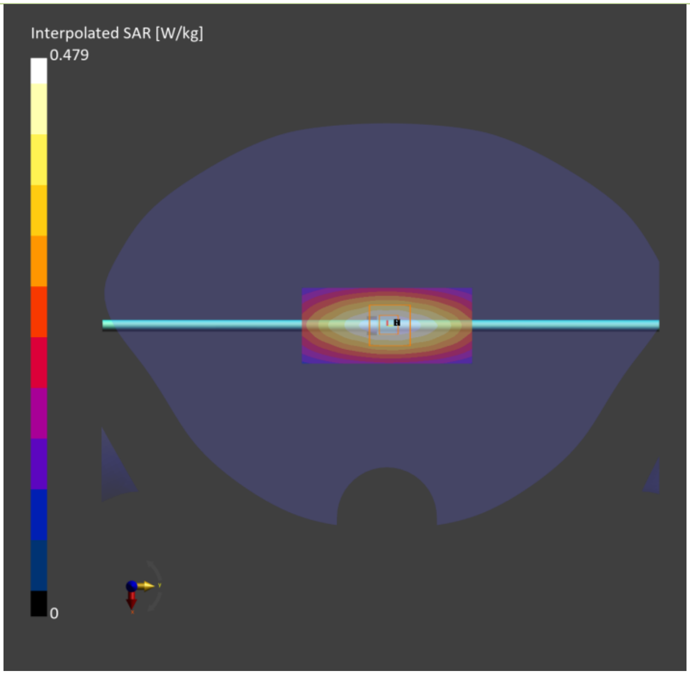
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



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Measurement Report

S11 System Check H750_240416

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

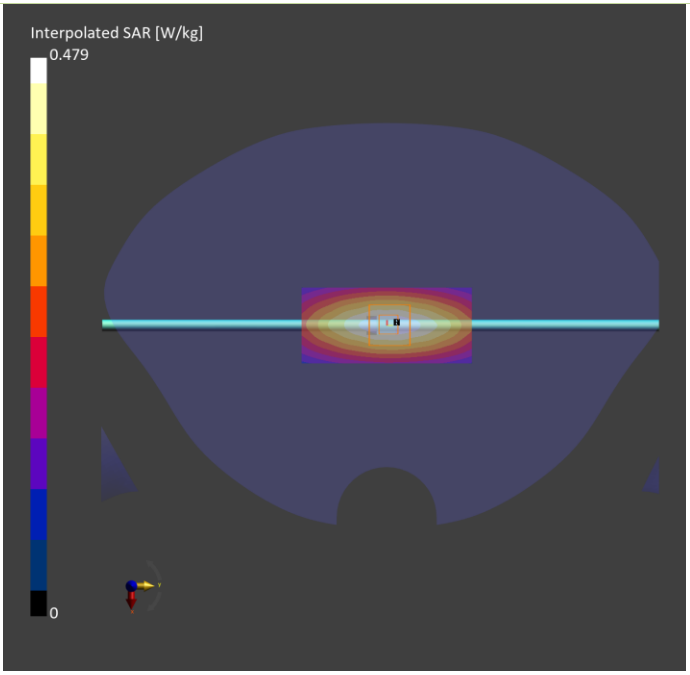
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

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Measurement Report

S12 System Check H750_240416

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

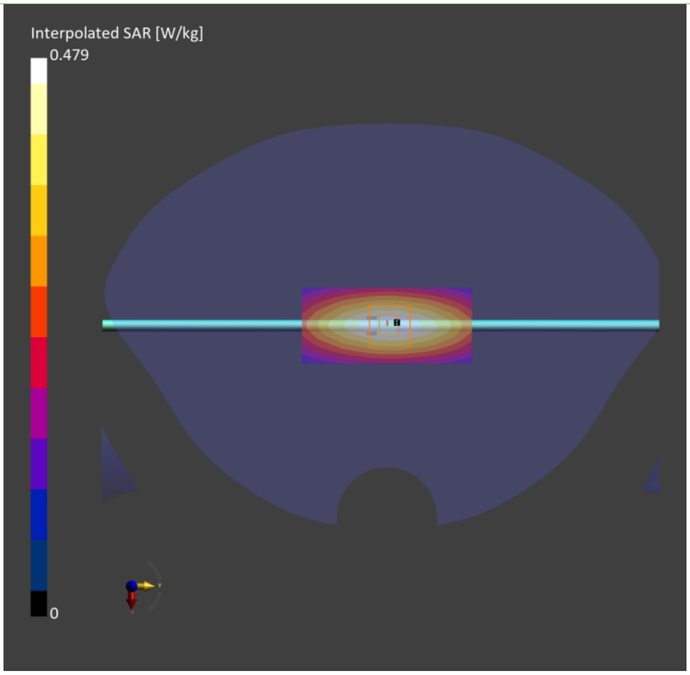
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



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Measurement Report

S13 System Check H750_240416

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

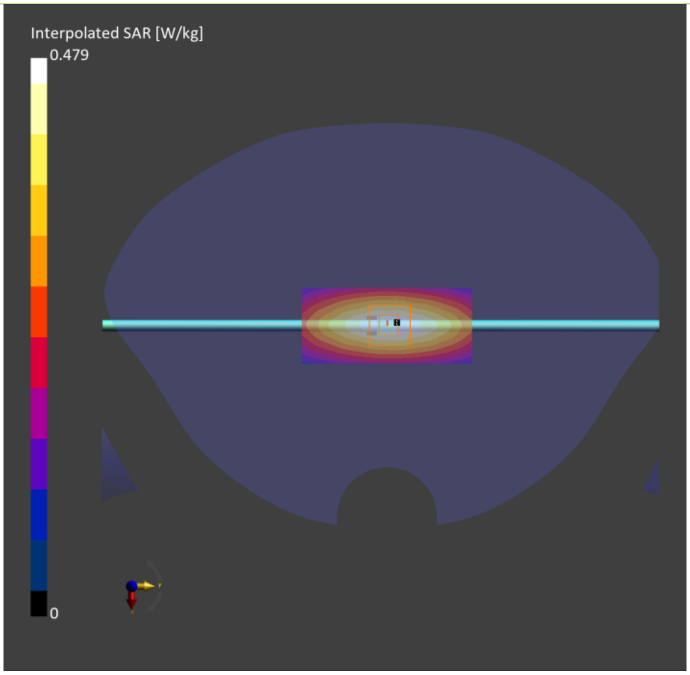
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



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Measurement Report

S14 System Check H1900_240518

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.34	40.0

Hardware Setup

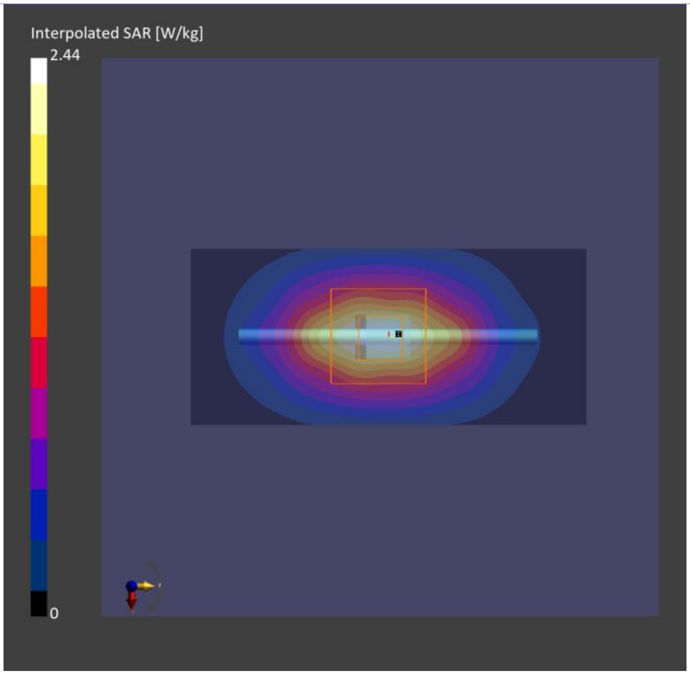
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-18	2024-05-18
psSAR1g [W/kg]	1.94	1.93
psSAR10g [W/kg]	0.998	1.02
Power Drift [dB]	0.01	0.01



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Measurement Report

S15 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

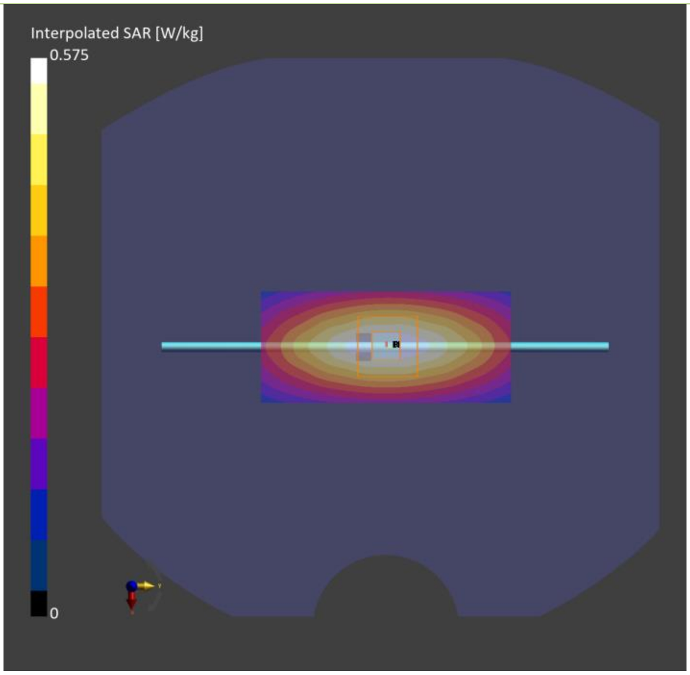
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



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Measurement Report

S16 System Check_H2300_240424

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2300

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2300.000, 0	8.12	1.72	39.0

Hardware Setup

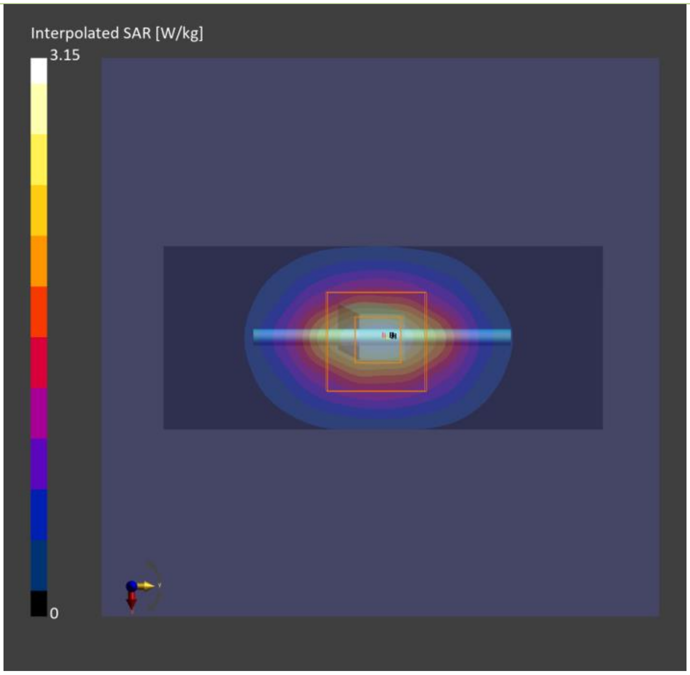
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	2.40	2.39
psSAR10g [W/kg]	1.13	1.14
Power Drift [dB]	0.01	0.02



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Measurement Report

S17 System Check H2600_240419

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.92	37.5

Hardware Setup

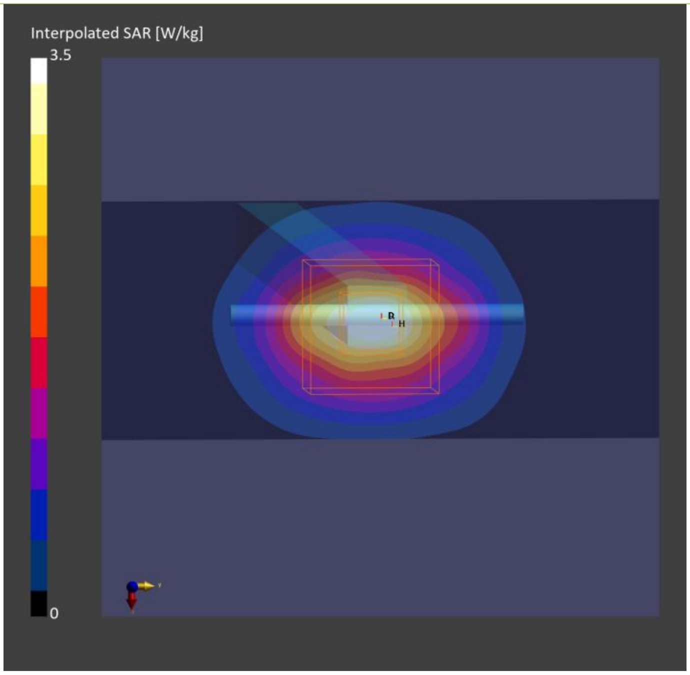
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-19	2024-04-19
psSAR1g [W/kg]	2.61	2.65
psSAR10g [W/kg]	1.15	1.17
Power Drift [dB]	-0.00	0.01



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Measurement Report

S18 System Check H2600_240503

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.97	40.2

Hardware Setup

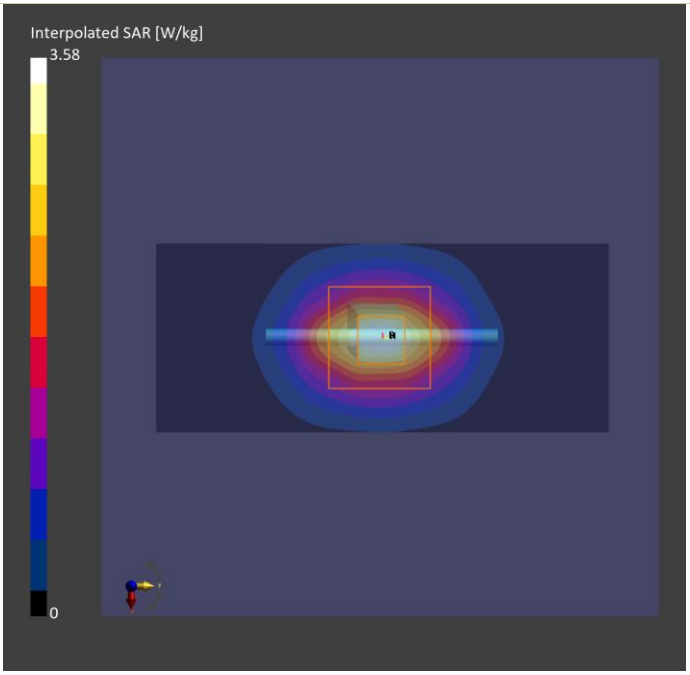
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	2.64	2.69
psSAR10g [W/kg]	1.16	1.19
Power Drift [dB]	0.01	-0.11



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Measurement Report

S19 System Check H3500_240503

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	38.5

Hardware Setup

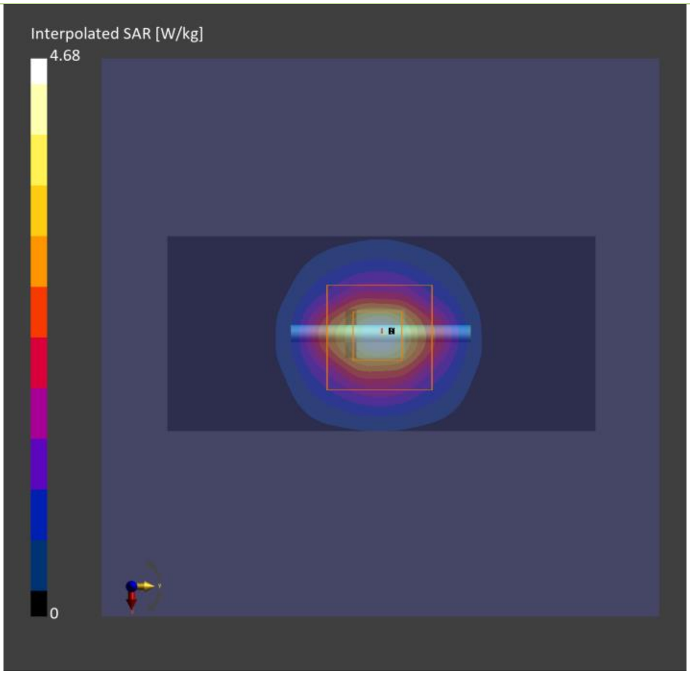
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	3.25	3.30
psSAR10g [W/kg]	1.22	1.27
Power Drift [dB]	-0.01	-0.13



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Measurement Report

S20 System Check H3700_240503

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	38.2

Hardware Setup

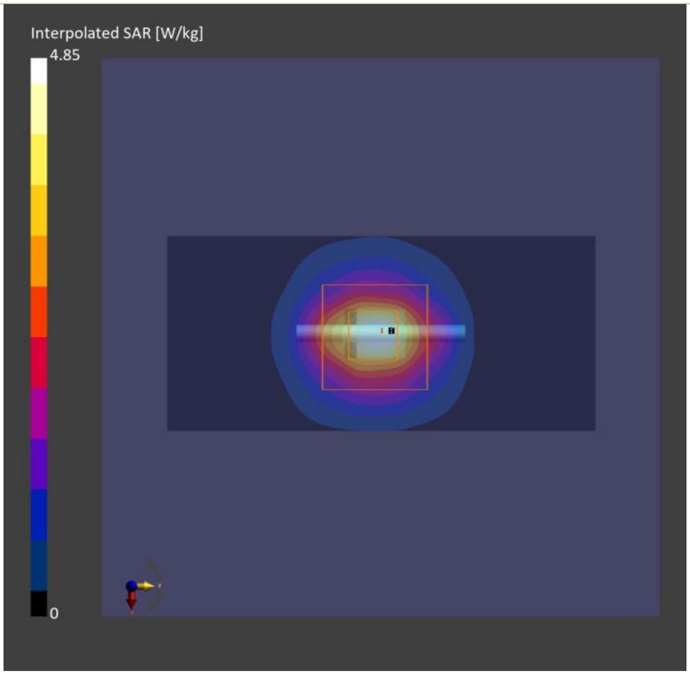
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	3.33	3.33
psSAR10g [W/kg]	1.22	1.25
Power Drift [dB]	0.01	-0.03



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Measurement Report

S21a System Check H3500_240505

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	38.9

Hardware Setup

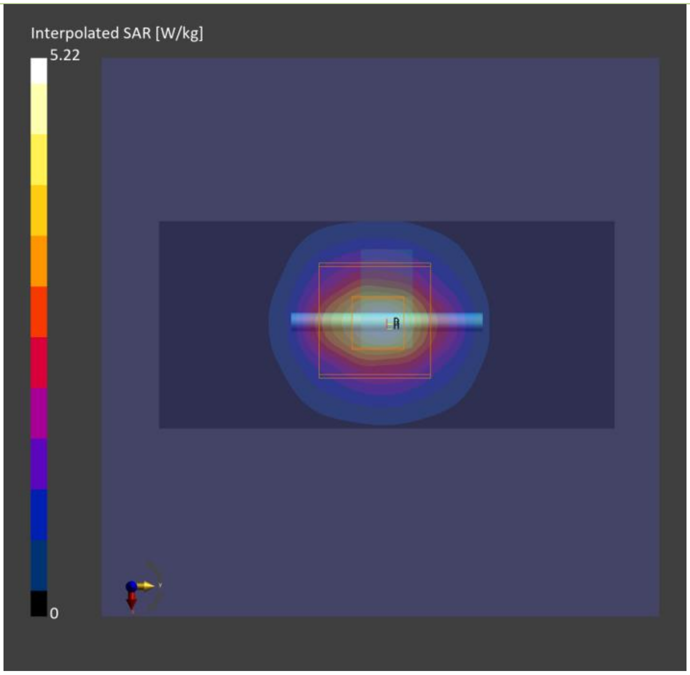
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.53	3.57
psSAR10g [W/kg]	1.37	1.45
Power Drift [dB]	0.02	-0.01



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Measurement Report

S21b System Check H3700_240505

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.98	38.6

Hardware Setup

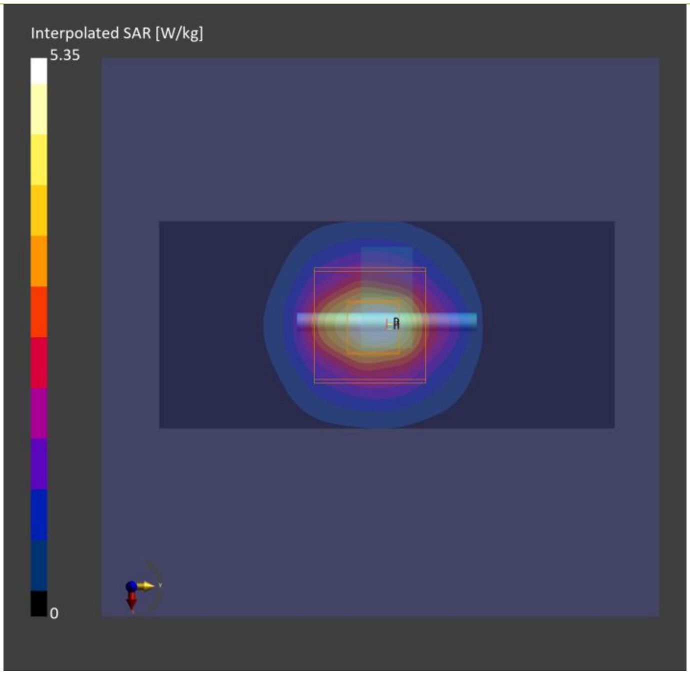
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.71	3.56
psSAR10g [W/kg]	1.38	1.35
Power Drift [dB]	0.02	0.01



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Measurement Report

S22 System Check_H1750_240424

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	9.0	1.37	39.8

Hardware Setup

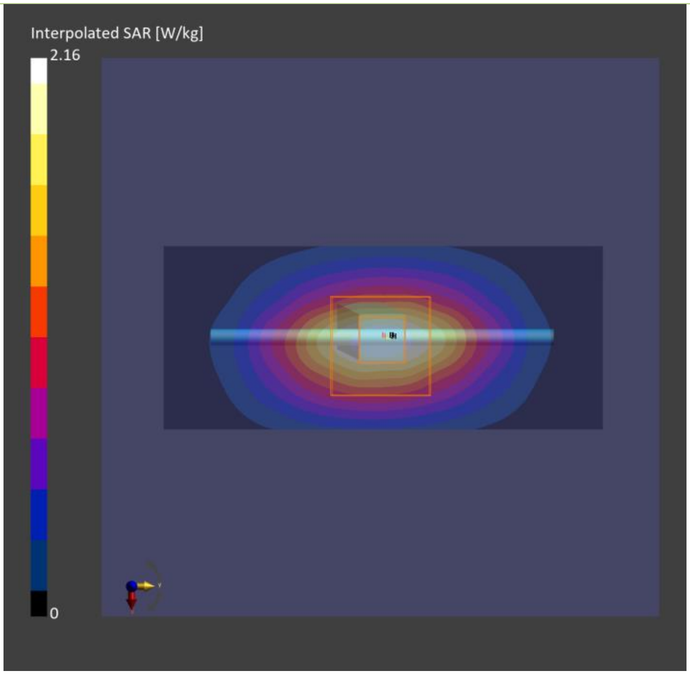
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	1.72	1.72
psSAR10g [W/kg]	0.917	0.913
Power Drift [dB]	0.01	0.01



Plots of System Verification

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Measurement Report

S23 System Check H750_240416

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

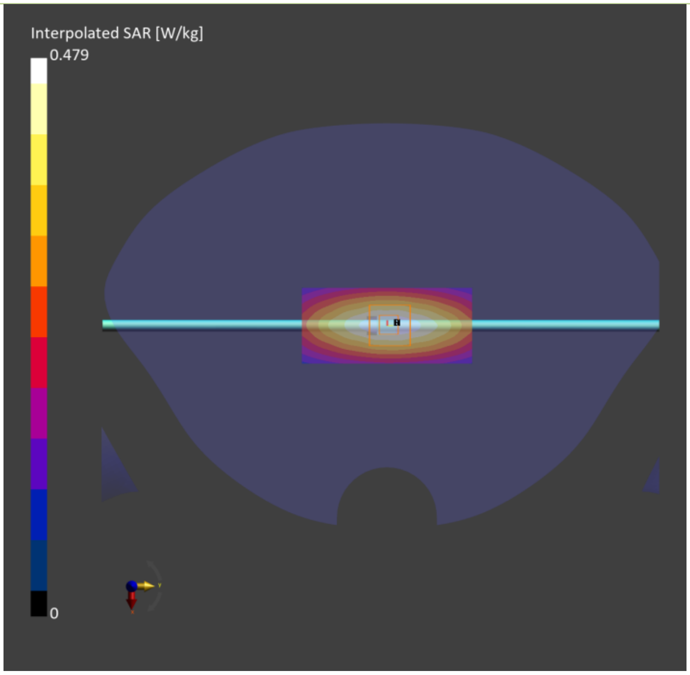
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



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Measurement Report

S24 System Check_H1900_240426

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.37	1.45	39.6

Hardware Setup

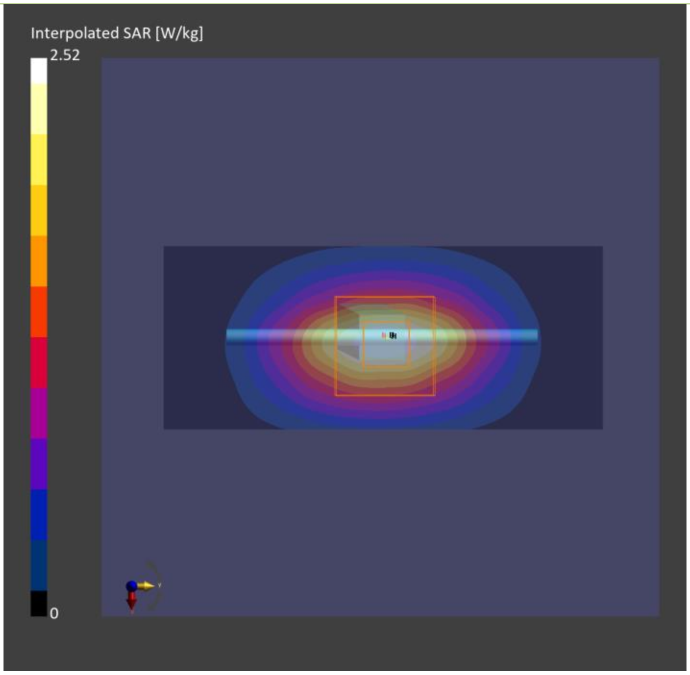
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	2.00	2.00
psSAR10g [W/kg]	1.04	1.04
Power Drift [dB]	0.01	-0.01



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Measurement Report

S25 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

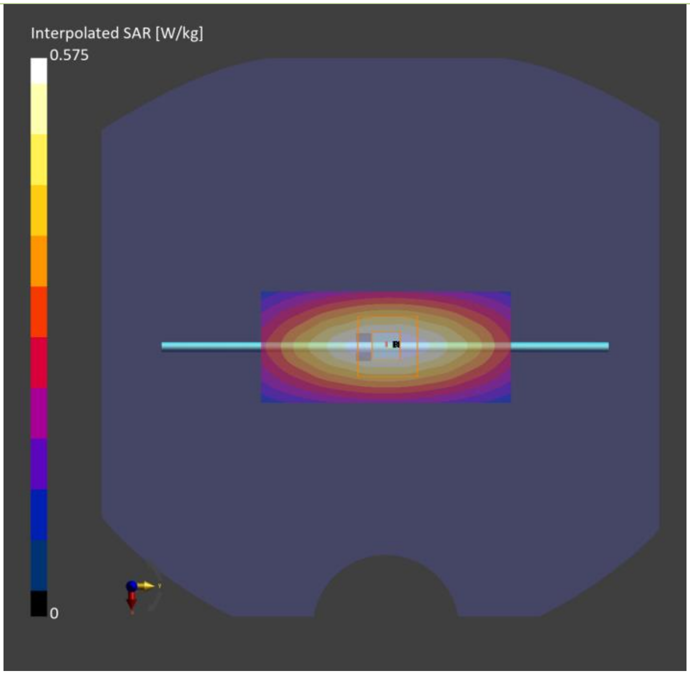
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



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Measurement Report

S26 System Check H2600_240505

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.95	39.9

Hardware Setup

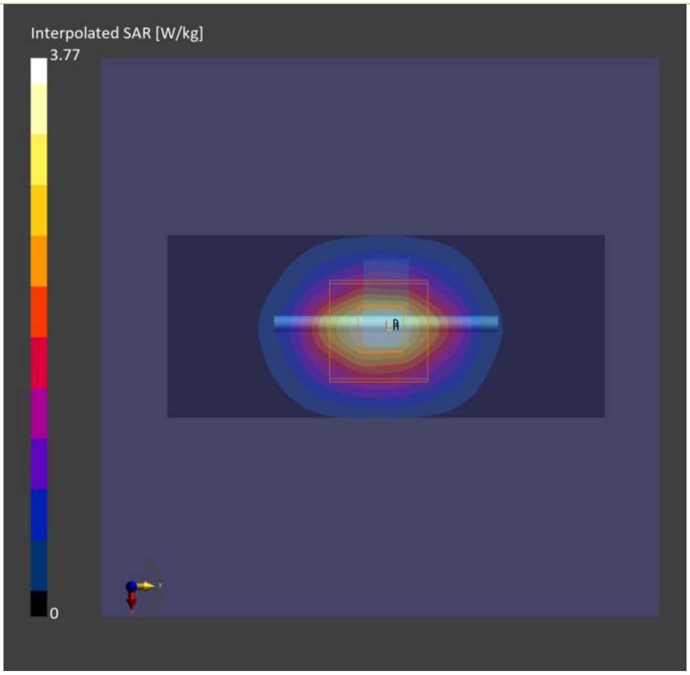
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	2.82	2.90
psSAR10g [W/kg]	1.26	1.32
Power Drift [dB]	0.03	-0.02



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Measurement Report

S27 System Check_H750_240425

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.35	0.891	40.2

Hardware Setup

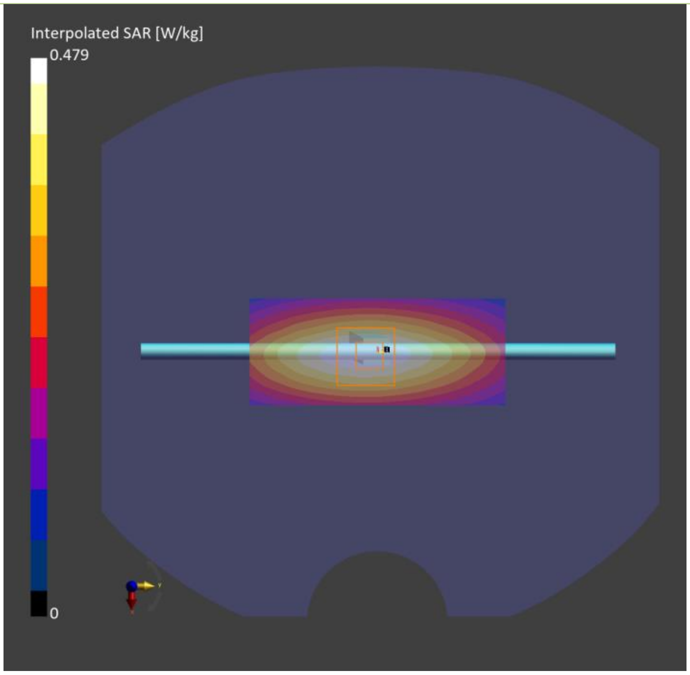
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.415	0.415
psSAR10g [W/kg]	0.277	0.275
Power Drift [dB]	0.01	0.02



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Measurement Report

S28 System Check_H750_240425

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.35	0.891	40.2

Hardware Setup

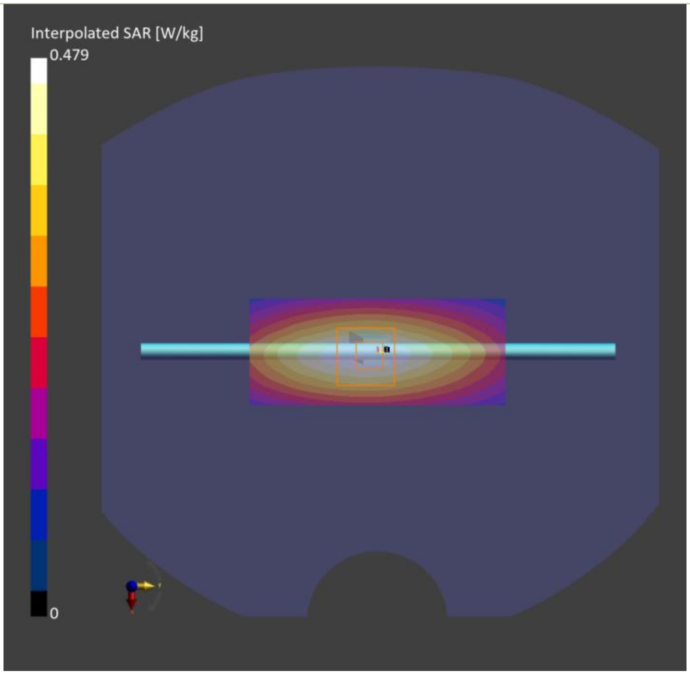
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.415	0.415
psSAR10g [W/kg]	0.277	0.275
Power Drift [dB]	0.01	0.02



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Measurement Report

S29 System Check_H1900_240426

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.37	1.45	39.6

Hardware Setup

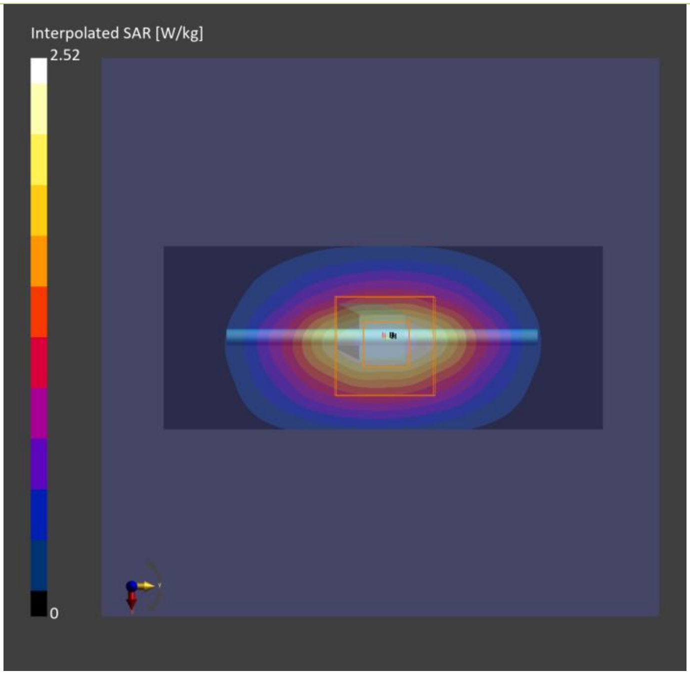
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	2.00	2.00
psSAR10g [W/kg]	1.04	1.04
Power Drift [dB]	0.01	-0.01



Measurement Report

S30 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

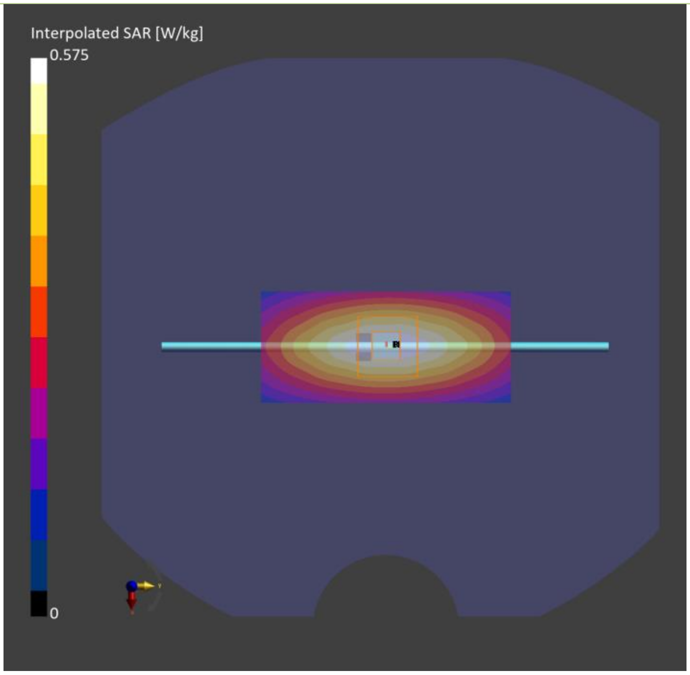
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



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Measurement Report

S31 System Check H2600_240507

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	40.2

Hardware Setup

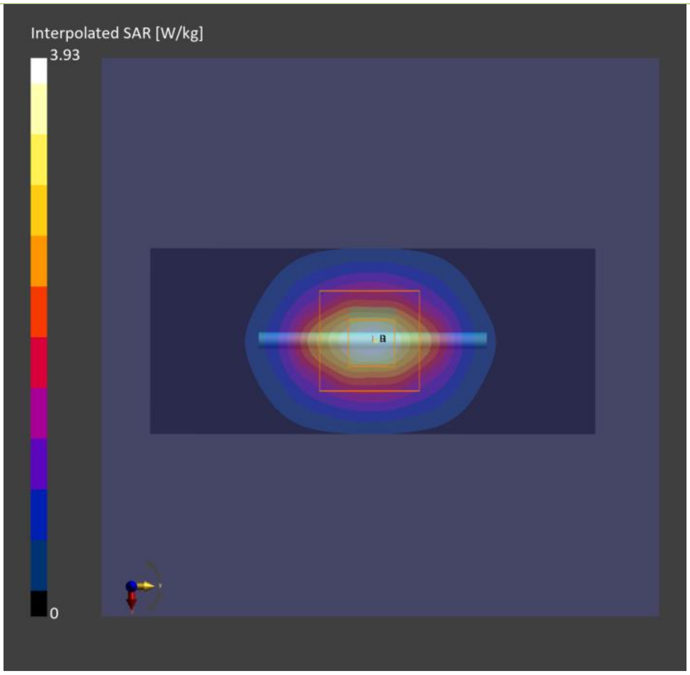
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	2.92	2.97
psSAR10g [W/kg]	1.30	1.36
Power Drift [dB]	0.02	-0.02



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Measurement Report

S32 System Check H2600_240507

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	40.2

Hardware Setup

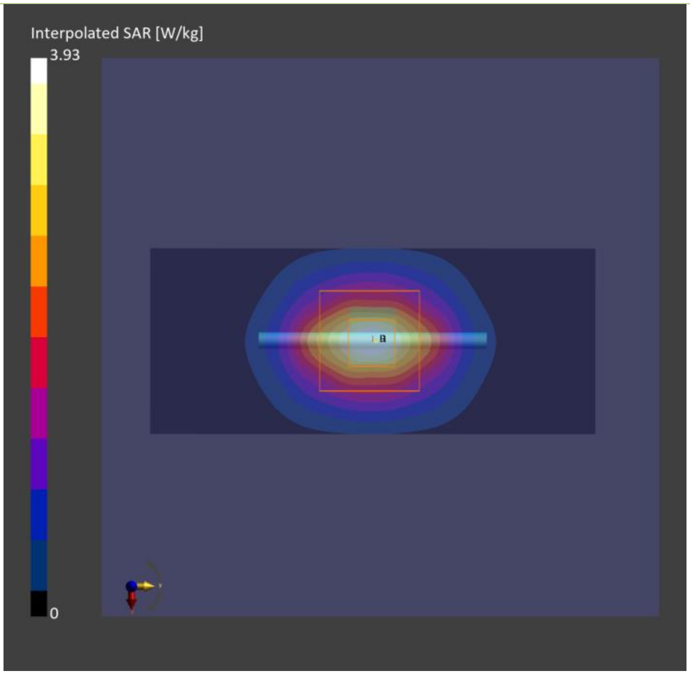
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	2.92	2.97
psSAR10g [W/kg]	1.30	1.36
Power Drift [dB]	0.02	-0.02



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Measurement Report

S33a System Check H3500_240505

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	38.9

Hardware Setup

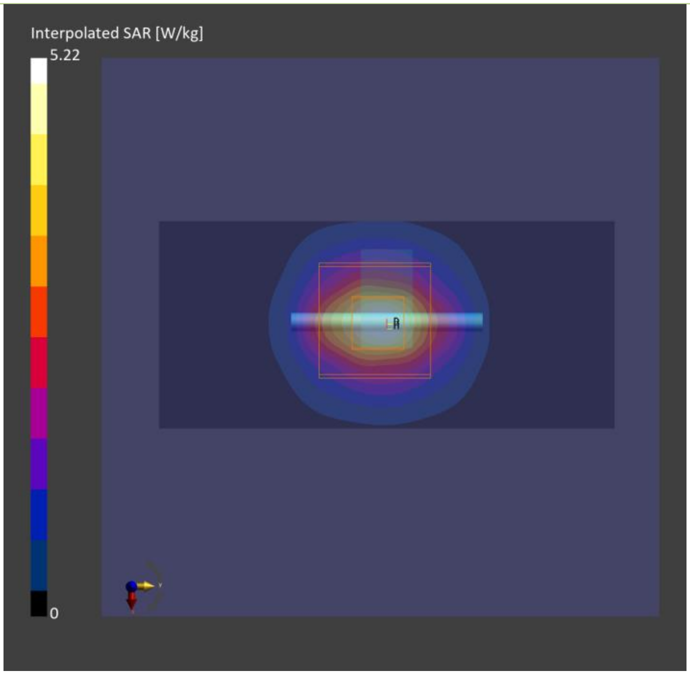
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.53	3.57
psSAR10g [W/kg]	1.37	1.45
Power Drift [dB]	0.02	-0.01



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Measurement Report

S33b System Check H3700_240505

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.98	38.6

Hardware Setup

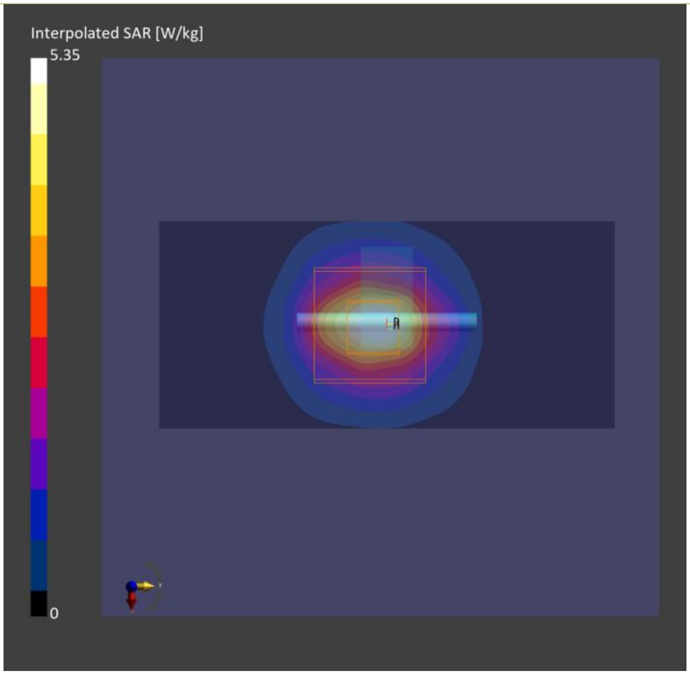
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.71	3.56
psSAR10g [W/kg]	1.38	1.35
Power Drift [dB]	0.02	0.01



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Measurement Report

S34 System Check H1750_240514

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.38	41.3

Hardware Setup

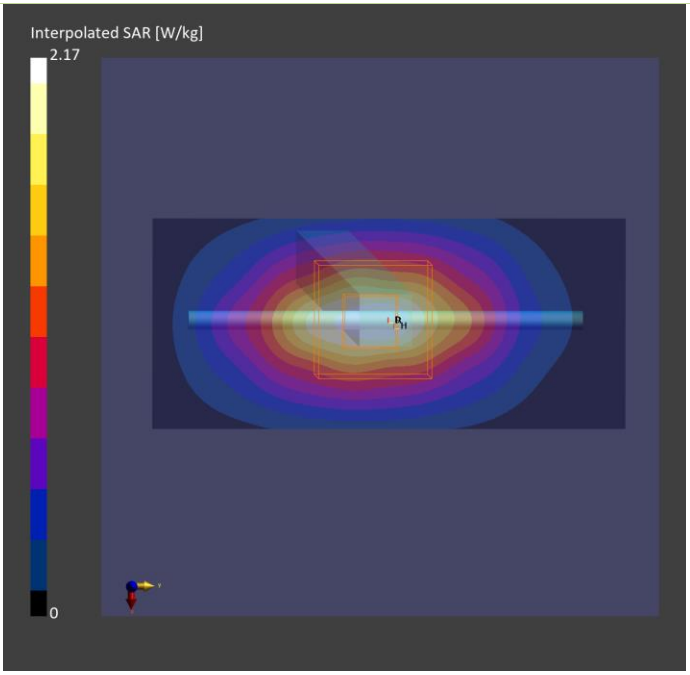
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-14	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-14	2024-05-14
psSAR1g [W/kg]	1.75	1.81
psSAR10g [W/kg]	0.933	0.977
Power Drift [dB]	-0.01	-0.18



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Measurement Report

S35 System Check_H750_240425

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.35	0.891	40.2

Hardware Setup

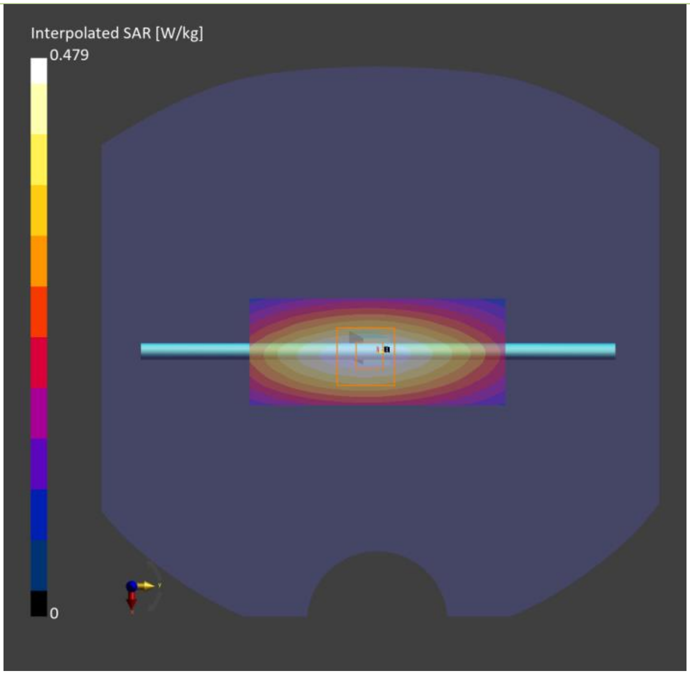
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.415	0.415
psSAR10g [W/kg]	0.277	0.275
Power Drift [dB]	0.01	0.02



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Measurement Report

S36a System Check H3500_240509

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.83	39.2

Hardware Setup

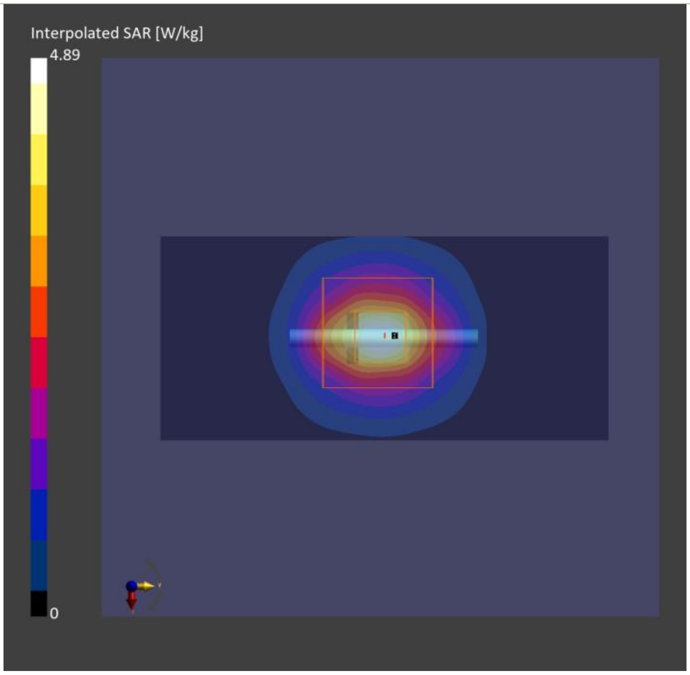
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	3.40	3.44
psSAR10g [W/kg]	1.28	1.35
Power Drift [dB]	0.01	-0.03



Plots of System Verification

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Measurement Report

S36b System Check H3700_240509

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.01	39.0

Hardware Setup

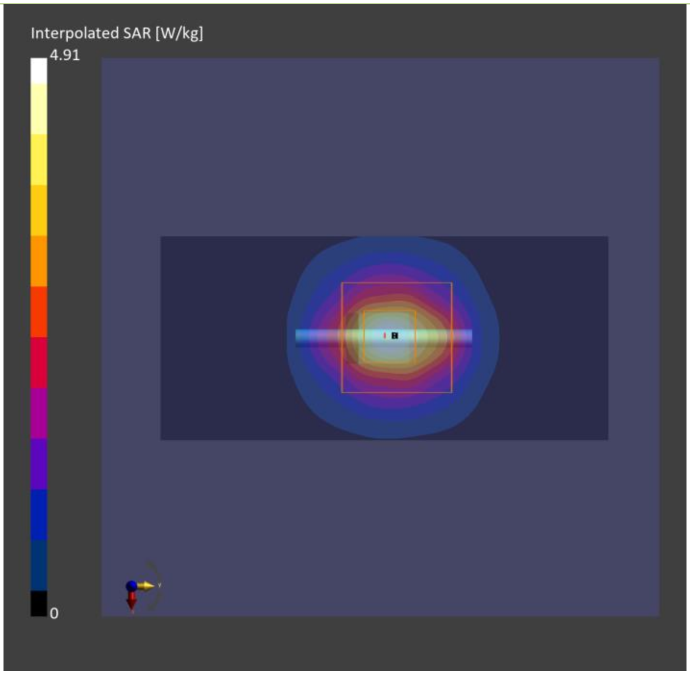
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	3.37	3.47
psSAR10g [W/kg]	1.25	1.34
Power Drift [dB]	0.02	0.01



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Measurement Report

S36c System Check H3900_240509

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3900.000, 0	6.53	3.20	38.7

Hardware Setup

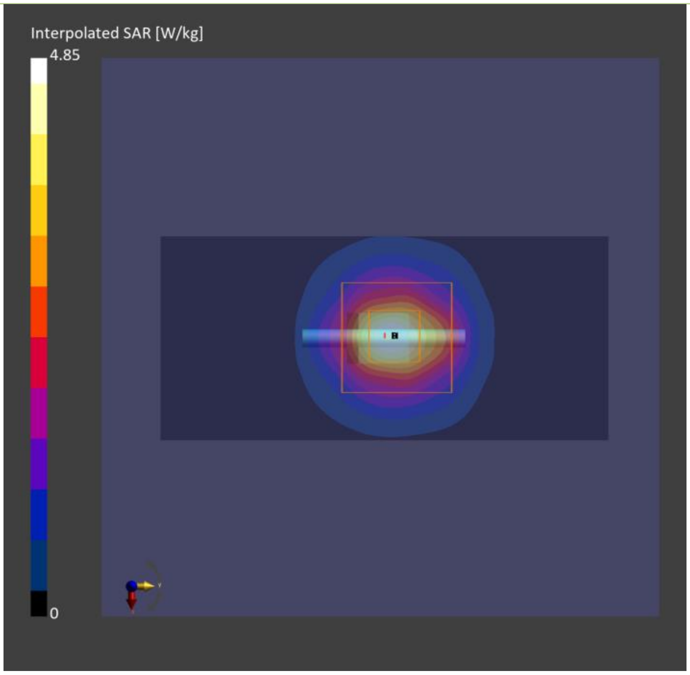
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	3.27	3.38
psSAR10g [W/kg]	1.15	1.24
Power Drift [dB]	0.01	0.03



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Measurement Report

S38a System Check H3500_240510

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

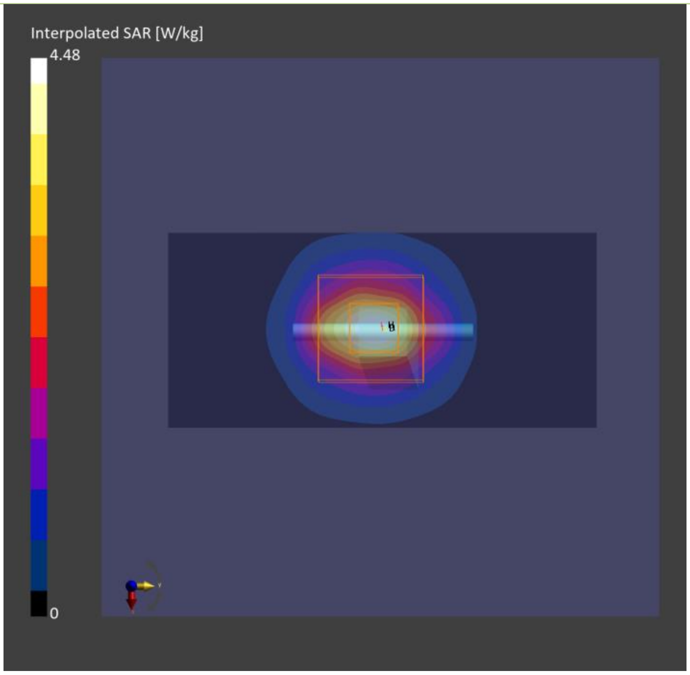
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-10	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-10	2024-05-10
psSAR1g [W/kg]	3.13	3.21
psSAR10g [W/kg]	1.18	1.26
Power Drift [dB]	0.03	0.02



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Measurement Report

S38b System Check H3700_240510

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.2

Hardware Setup

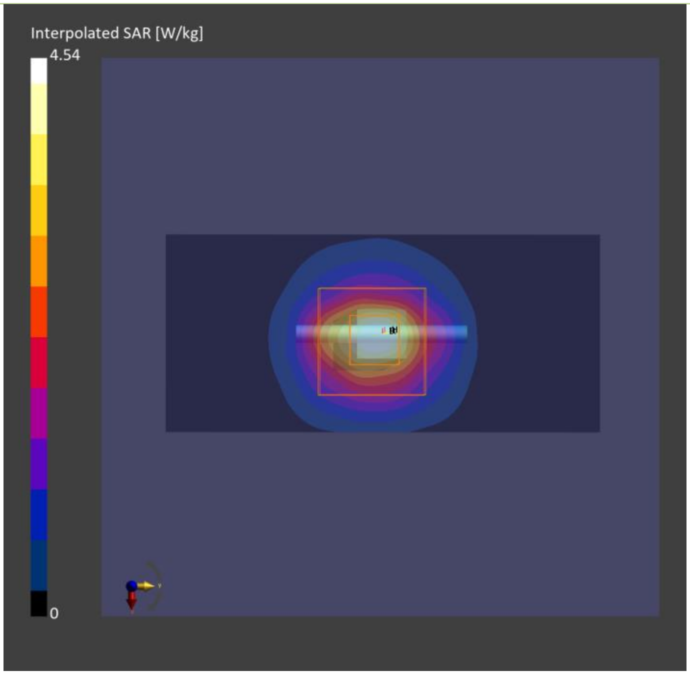
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-10	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-10	2024-05-10
psSAR1g [W/kg]	3.14	3.22
psSAR10g [W/kg]	1.17	1.23
Power Drift [dB]	0.03	0.01



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Measurement Report

S40 System Check H2450_240428

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.000, 0	7.65	1.83	39.7

Hardware Setup

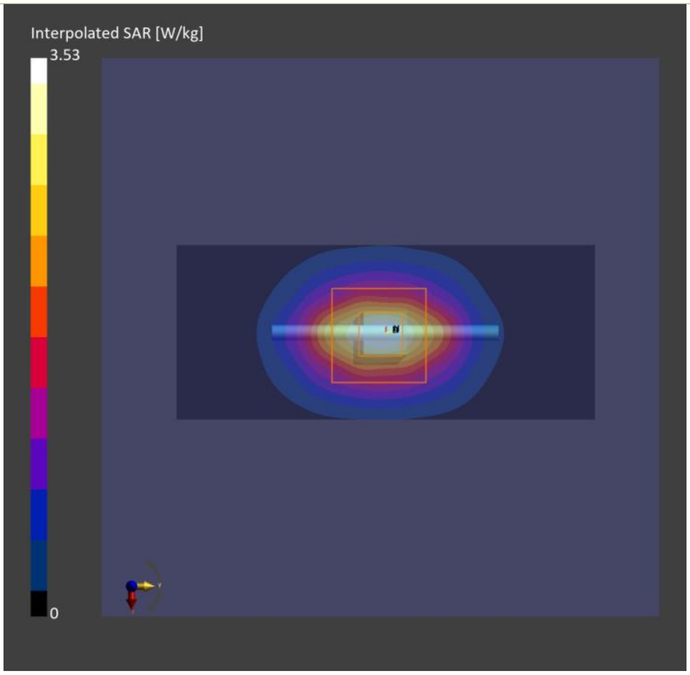
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	2.67	2.66
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	-0.02	-0.11



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Measurement Report

S41 System Check H5250_240427

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5250

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5250.000, 0	5.52	4.64	37.3

Hardware Setup

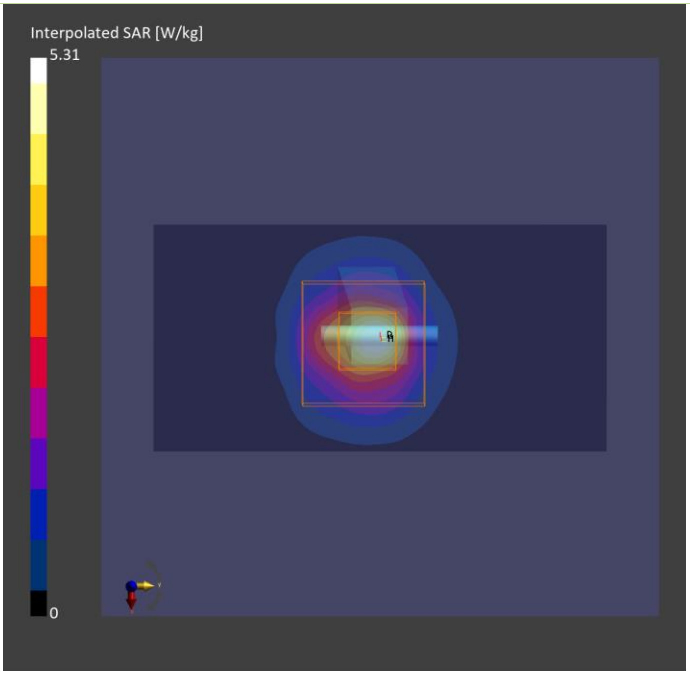
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	3.36	3.62
psSAR10g [W/kg]	0.978	1.06
Power Drift [dB]	-0.01	-0.11



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Measurement Report

S42 System Check H5600_240427

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5600.000, 0	4.8	4.97	35.2

Hardware Setup

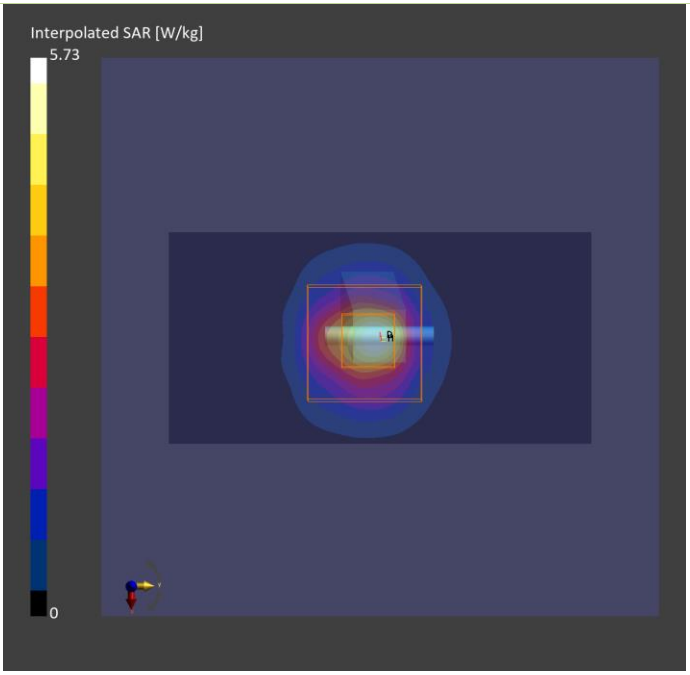
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	3.68	3.93
psSAR10g [W/kg]	1.06	1.10
Power Drift [dB]	-0.00	-0.11



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Measurement Report

S43 System Check H5750_240427

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5750.000, 0	4.96	5.14	35.0

Hardware Setup

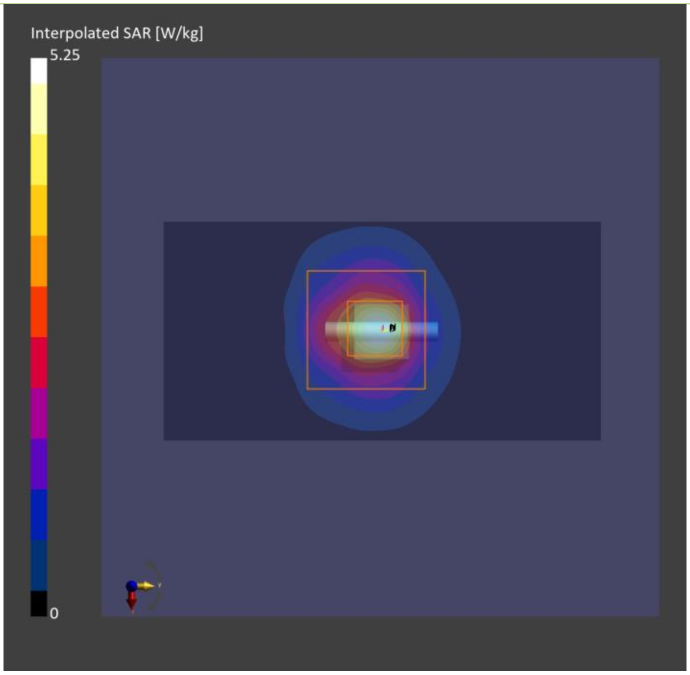
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	3.32	3.60
psSAR10g [W/kg]	0.945	1.01
Power Drift [dB]	-0.03	-0.12



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Measurement Report

S44 System Check H2450_240428

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.000, 0	7.65	1.83	39.7

Hardware Setup

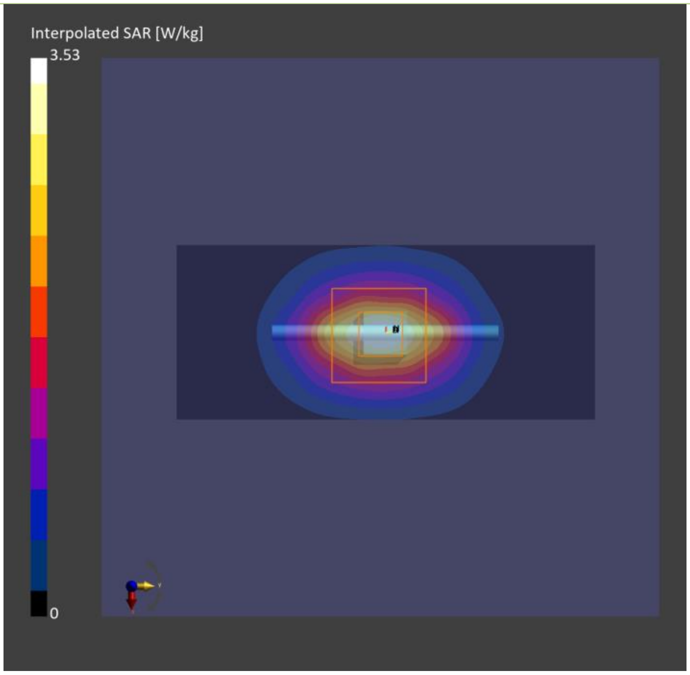
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	2.67	2.66
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	-0.02	-0.11



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Measurement Report

S137 System Check H6.5GHz_240429

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		6500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	,		, 0--	6500.0, 0	5.4	5.95	35.2

Hardware Setup

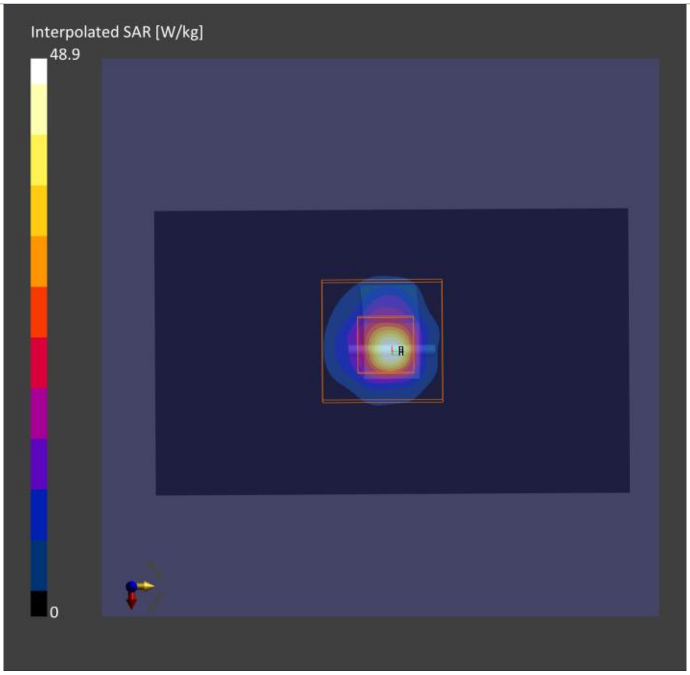
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-29	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2023-04-29	2023-04-29
psSAR1g [W/kg]	25.5	29.9
psSAR10g [W/kg]	5.03	5.48
psPDab (1.0cm2, sq) [W/m2]		299
psPDab (4.0cm2, sq) [W/m2]		134
Power Drift [dB]	0.01	-0.03



Plots of System Verification

Measurement Report

S137 PD_System Check_10 GHz_240515

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
SPEAG, 5G Verification Source 10 GHz	100.0 x 100.0 x 170.0	SN: 1025	

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	Front Face 10.00	Validation band	CW, 0--	10000.0, 10000	1.0

Hardware Setup

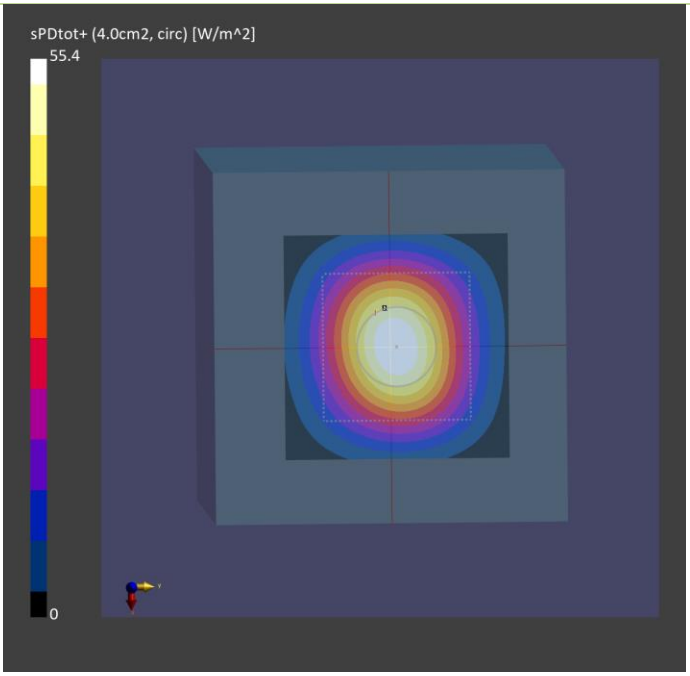
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	---Air	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan
Grid Extents [mm]	60.0 x 60.0
Grid Steps [lambda]	0.125 x 0.125
Sensor Surface [mm]	10.0

Measurement Results

	5G Scan
Date	2024-05-15
Avg. Area [cm^2]	4.00
psPDn+ [W/m^2]	55.0
psPDtot+ [W/m^2]	55.4
psPDmod+ [W/m^2]	55.5
E$_{max}$ [V/m]	151
Power Drift [dB]	-0.08



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Measurement Report

S45 System Check H835_240506

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.86	42.6

Hardware Setup

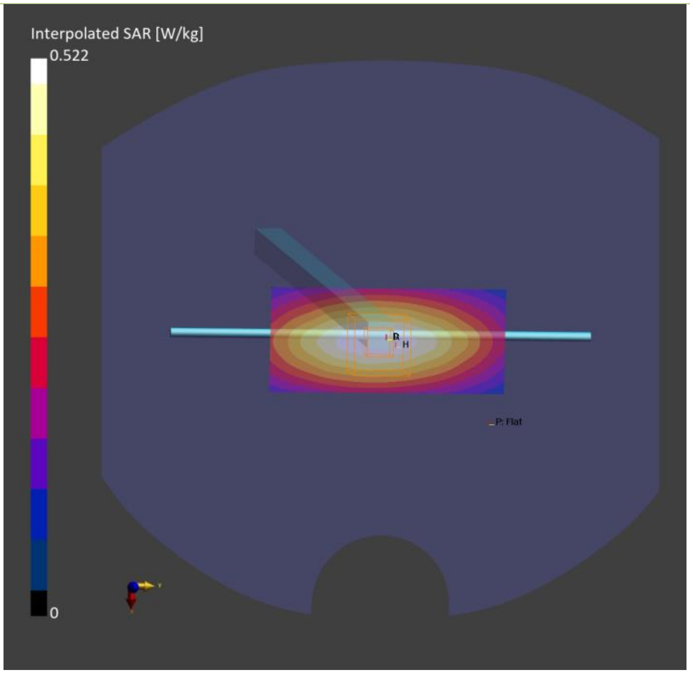
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	0.453	0.456
psSAR10g [W/kg]	0.299	0.300
Power Drift [dB]	-0.02	0.03



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Measurement Report

S46 System Check H1900_240506

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.35	40.8

Hardware Setup

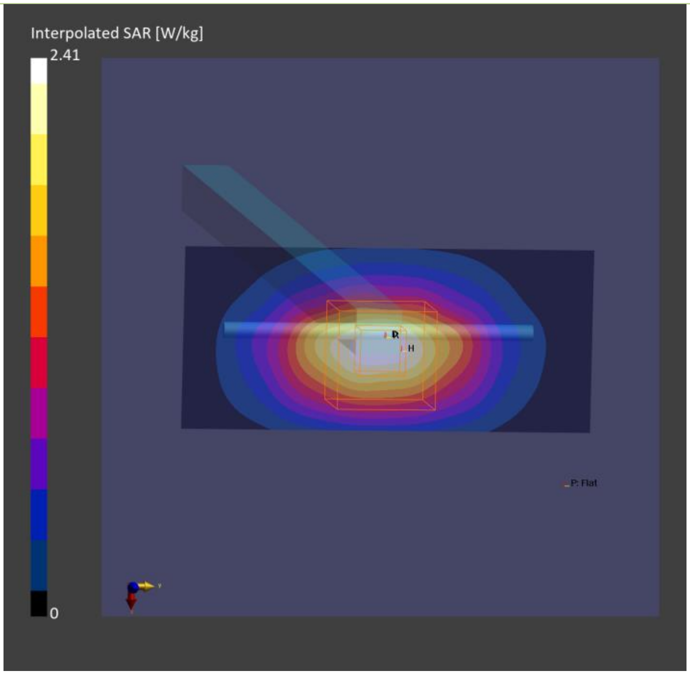
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	1.94	1.96
psSAR10g [W/kg]	1.02	1.04
Power Drift [dB]	0.01	0.02



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Measurement Report

S47 System Check H1900_240508

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.42	41.1

Hardware Setup

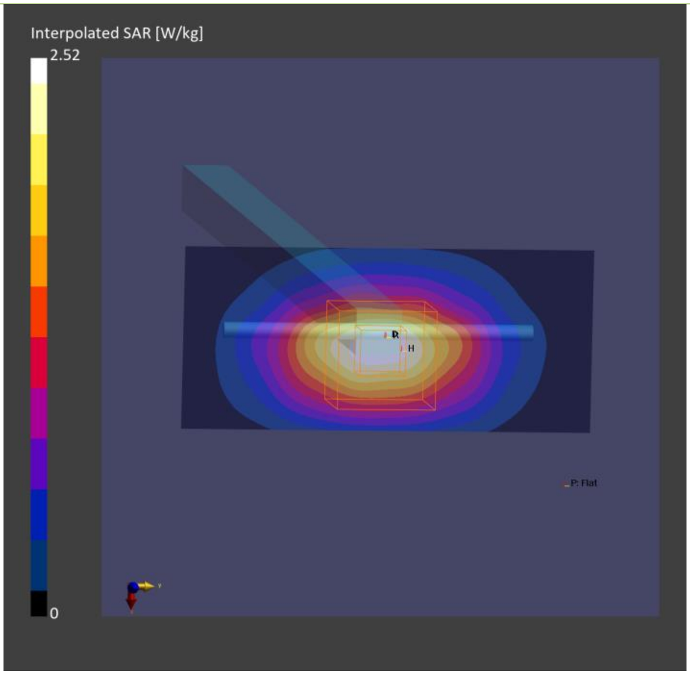
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	2.03	2.06
psSAR10g [W/kg]	1.07	1.09
Power Drift [dB]	0.02	0.02



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Measurement Report

S48 System Check H1750_240508

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.34	41.3

Hardware Setup

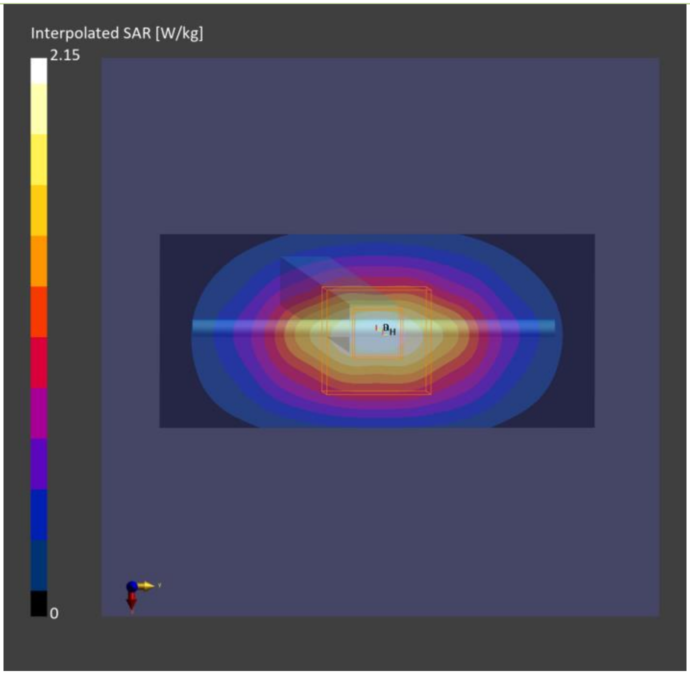
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	1.72	1.80
psSAR10g [W/kg]	0.913	0.979
Power Drift [dB]	0.10	0.13



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Measurement Report

S49 System Check H835_240508

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	43.1

Hardware Setup

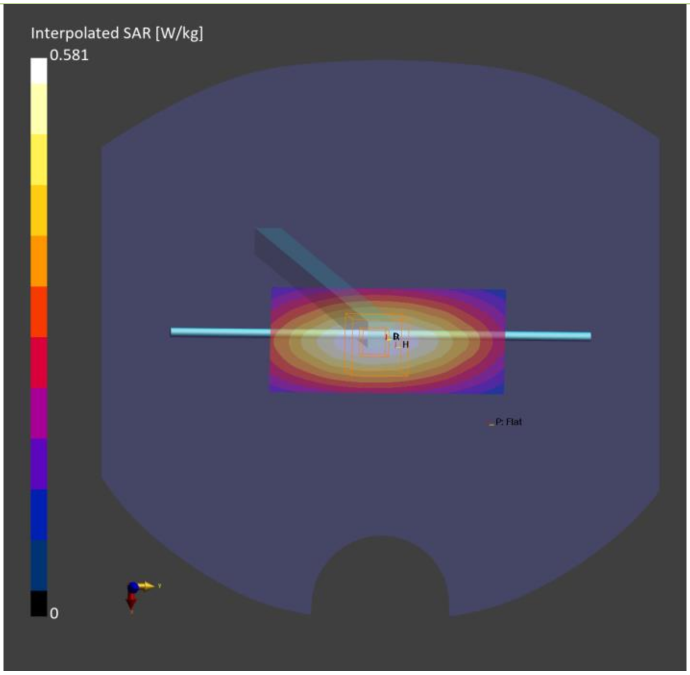
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.506	0.500
psSAR10g [W/kg]	0.334	0.330
Power Drift [dB]	-0.02	-0.05



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Measurement Report

S50 System Check H1900_240511

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.2

Hardware Setup

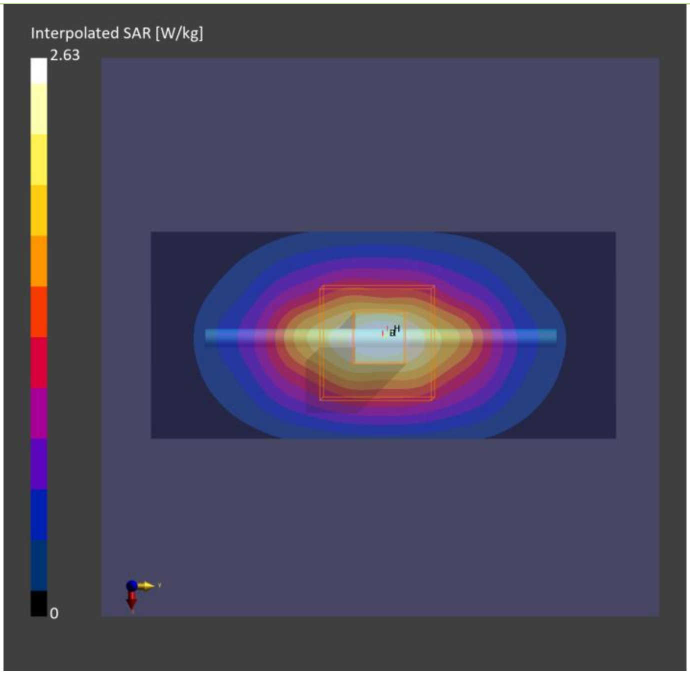
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	2.08	2.10
psSAR10g [W/kg]	1.08	1.11
Power Drift [dB]	0.02	0.01



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Measurement Report

S51 System Check H1750_240511

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.38	38.4

Hardware Setup

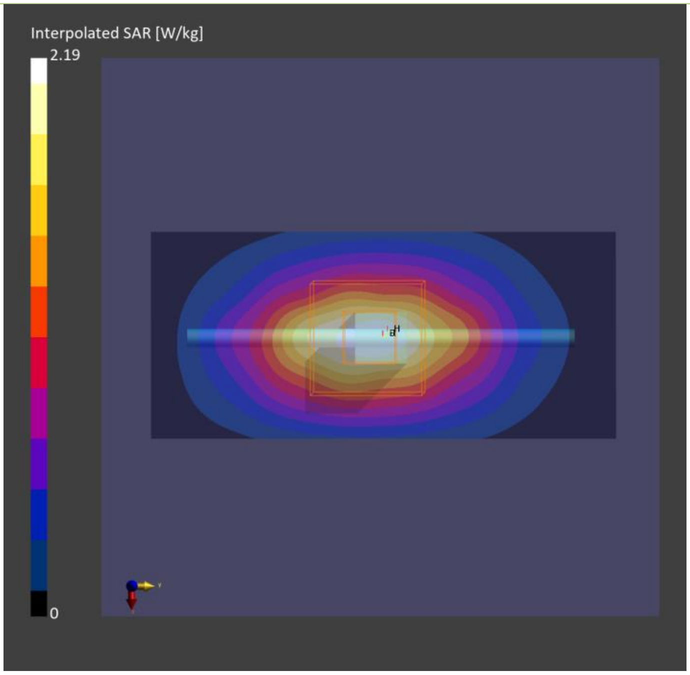
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	1.77	1.78
psSAR10g [W/kg]	0.940	0.959
Power Drift [dB]	0.04	0.06



Measurement Report
S52 System Check H835_240512
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.94	43.3

Hardware Setup

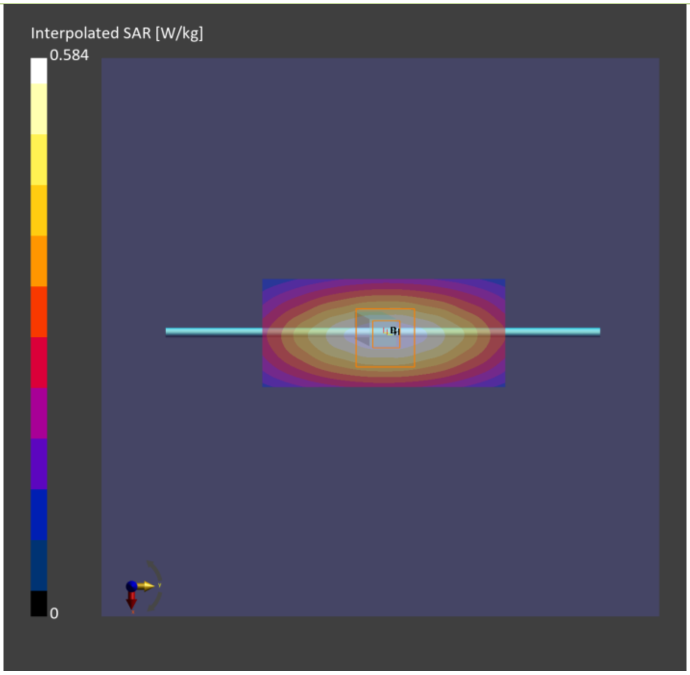
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.507	0.506
psSAR10g [W/kg]	0.334	0.333
Power Drift [dB]	-0.01	0.05



Plots of System Verification

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Measurement Report

S53 System Check H2600_240516

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

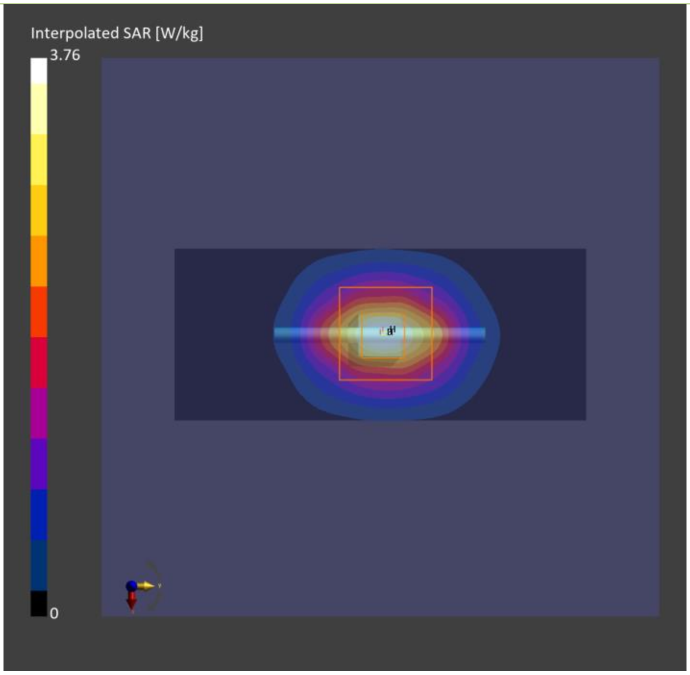
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.79	2.74
psSAR10g [W/kg]	1.23	1.23
Power Drift [dB]	0.01	0.01



Measurement Report

S54 System Check H750_240512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

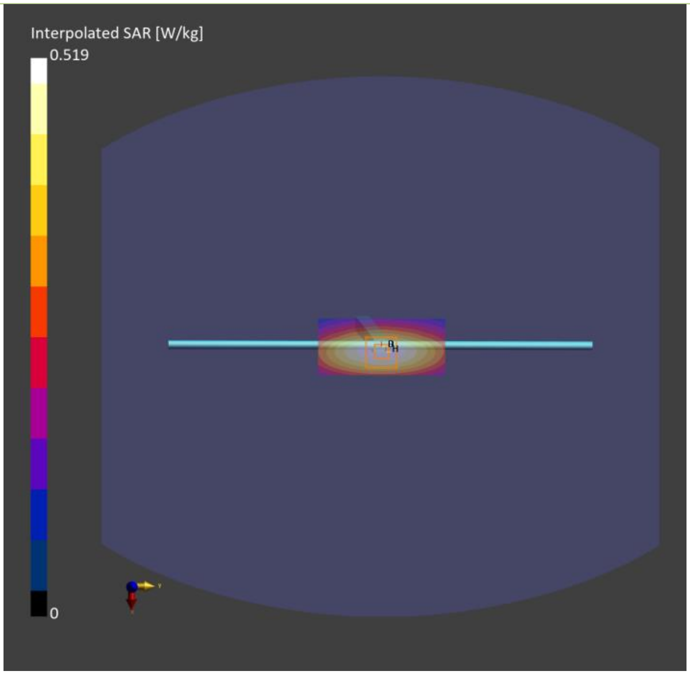
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



Measurement Report

S55 System Check H750_240512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

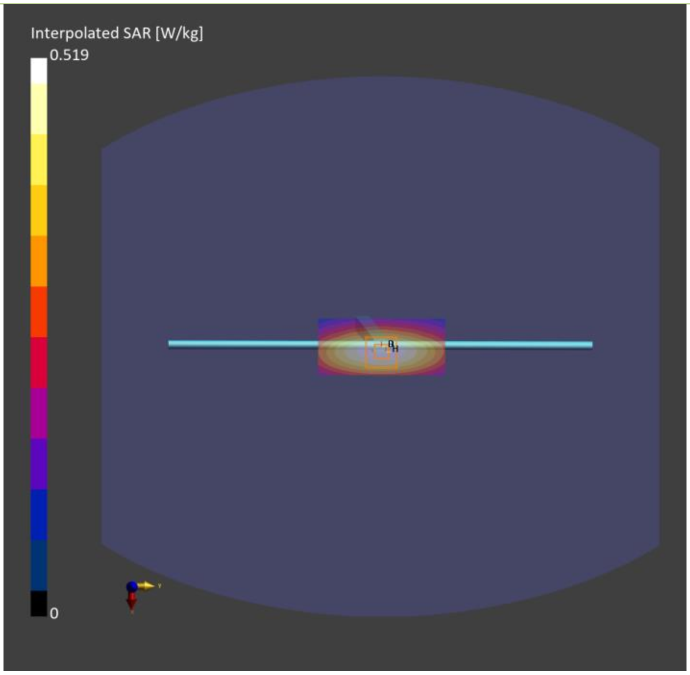
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



Measurement Report
S56 System Check H750_240512
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

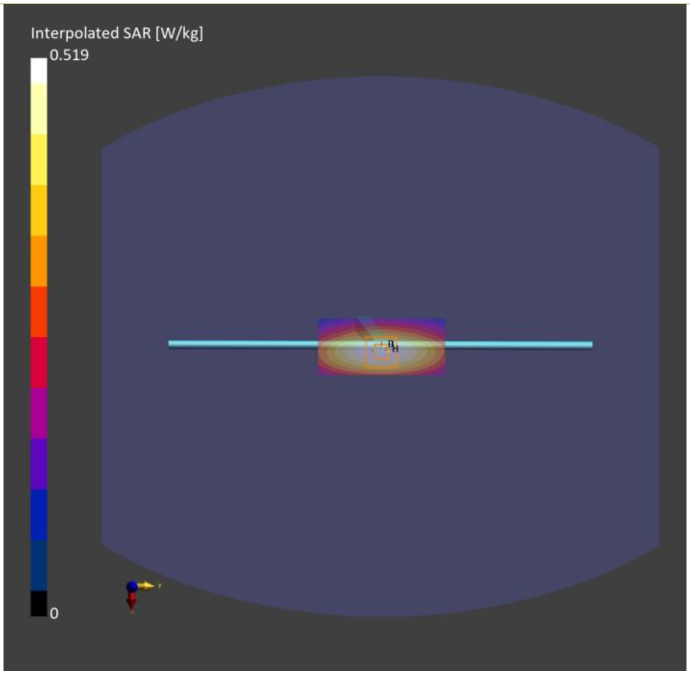
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



Measurement Report

S57 System Check H750_240512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

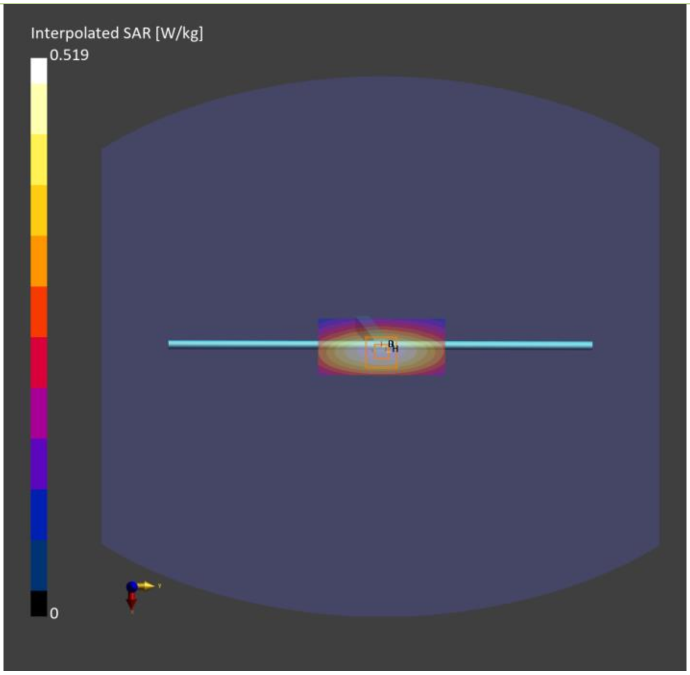
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



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Measurement Report

S58 System Check H1900_240511

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.2

Hardware Setup

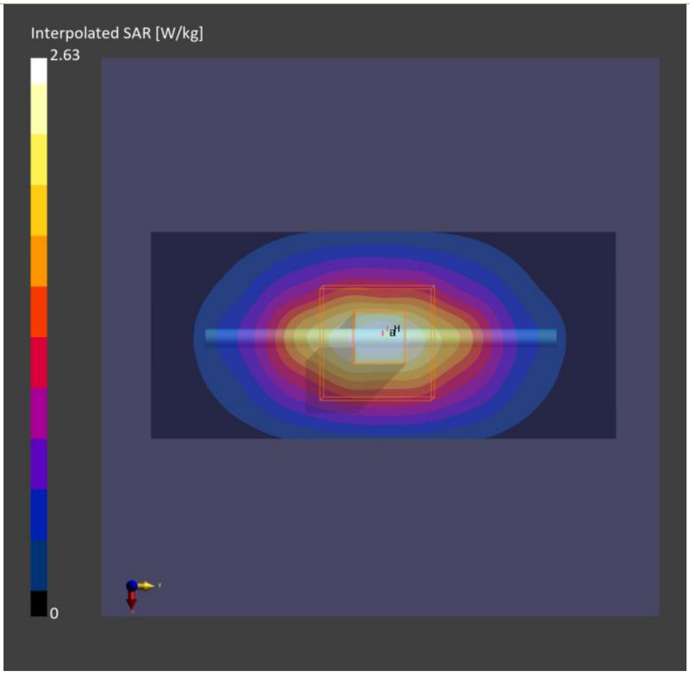
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	2.08	2.10
psSAR10g [W/kg]	1.08	1.11
Power Drift [dB]	0.02	0.01



Plots of System Verification

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Measurement Report

S59 System Check H835_240513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.87	42.8

Hardware Setup

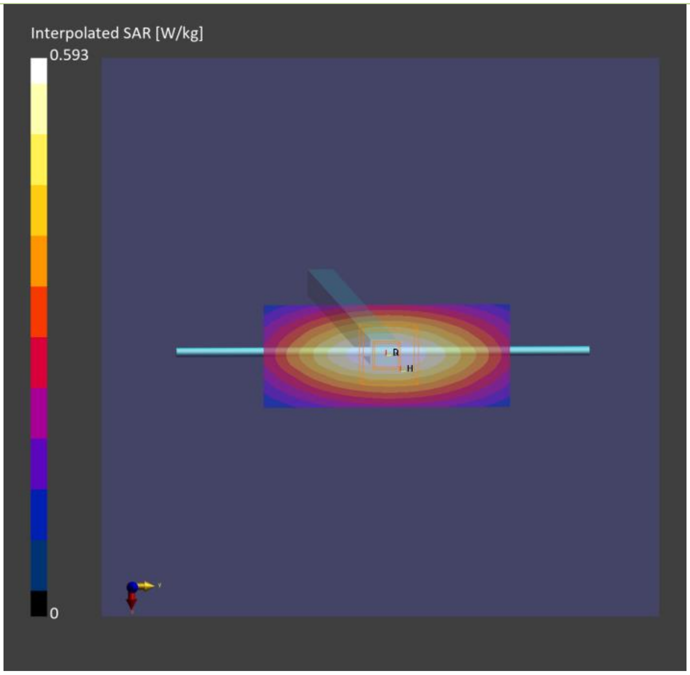
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.511	0.508
psSAR10g [W/kg]	0.333	0.335
Power Drift [dB]	0.01	0.05



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Measurement Report

S60 System Check H2300_240516

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2300.000, 0	7.95	1.75	37.6

Hardware Setup

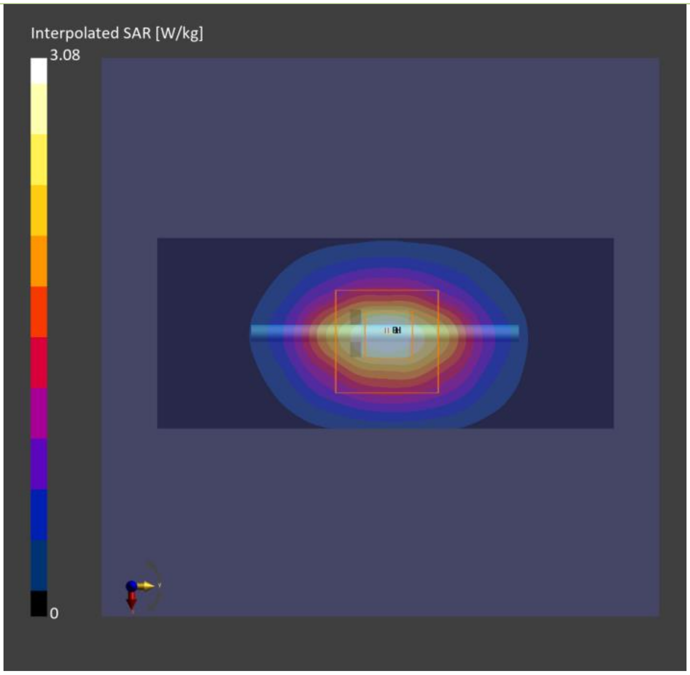
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.35	2.33
psSAR10g [W/kg]	1.12	1.11
Power Drift [dB]	0.02	0.01



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Measurement Report

S61 System Check H2600_240516

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

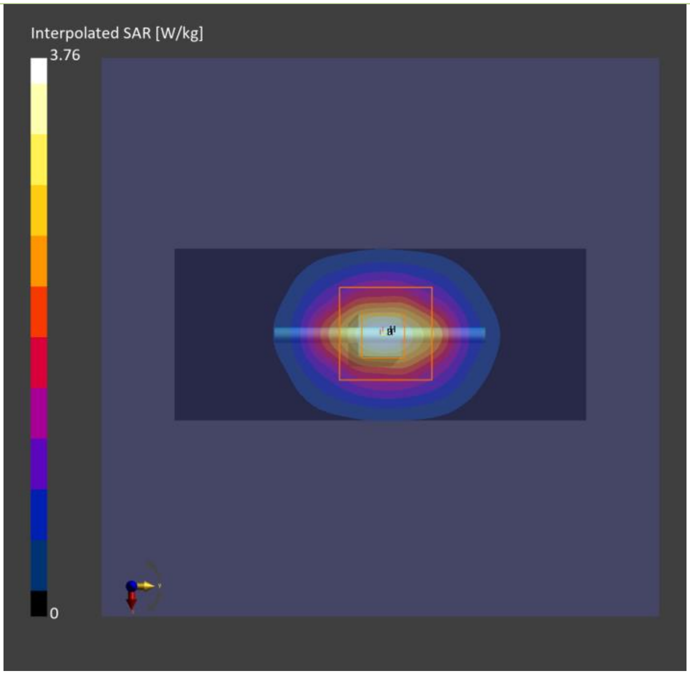
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.79	2.74
psSAR10g [W/kg]	1.23	1.23
Power Drift [dB]	0.01	0.01



Measurement Report
S62 System Check H2600_240516
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

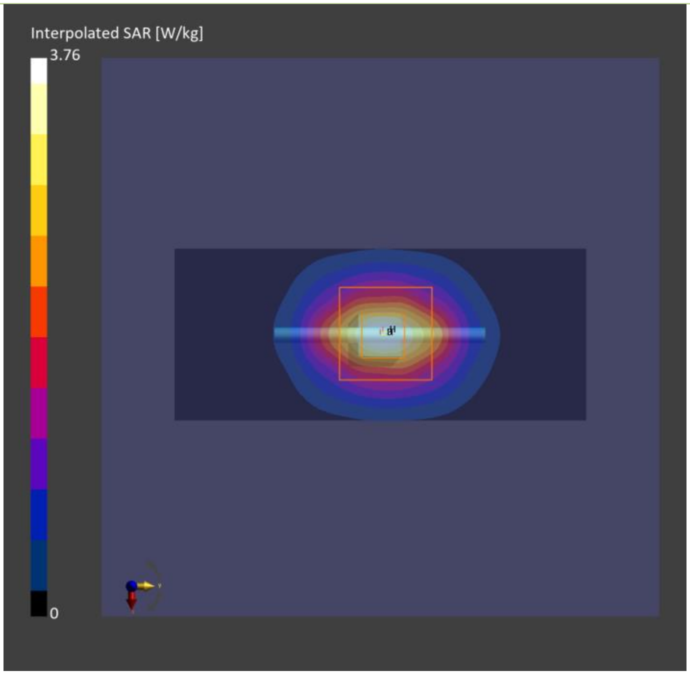
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.79	2.74
psSAR10g [W/kg]	1.23	1.23
Power Drift [dB]	0.01	0.01



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Measurement Report

S63 System Check H3500_2400513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

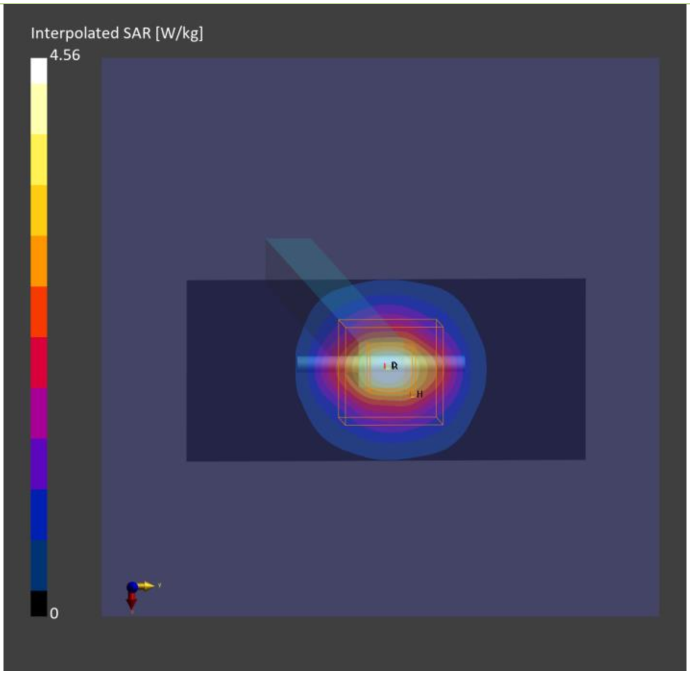
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	3.15	3.12
psSAR10g [W/kg]	1.19	1.20
Power Drift [dB]	-0.01	-0.01



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Measurement Report

S64 System Check H3700_2400513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

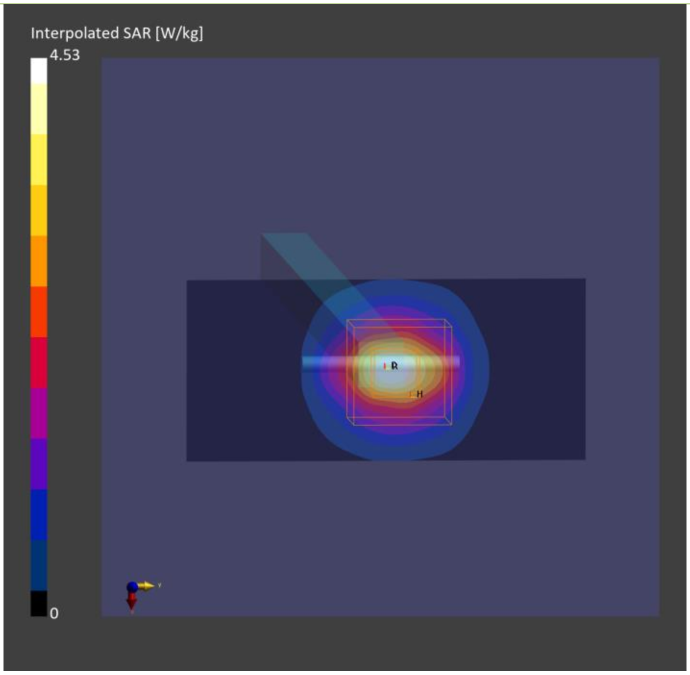
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	3.11	3.11
psSAR10g [W/kg]	1.15	1.16
Power Drift [dB]	-0.02	-0.00



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Measurement Report

S65a System Check H3500_240515

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.83	39.4

Hardware Setup

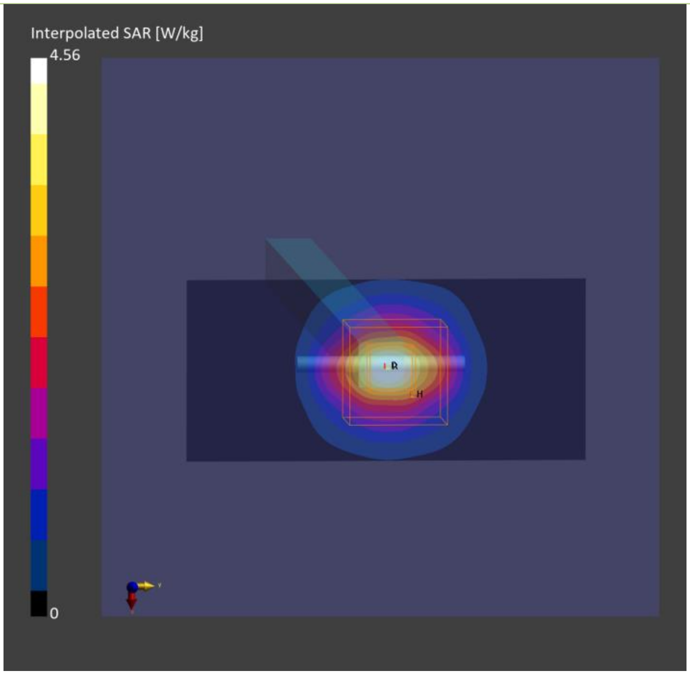
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	3.16	3.15
psSAR10g [W/kg]	1.19	1.22
Power Drift [dB]	0.01	-0.01



Plots of System Verification

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Measurement Report

S65b System Check H3700_240515

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.01	39.3

Hardware Setup

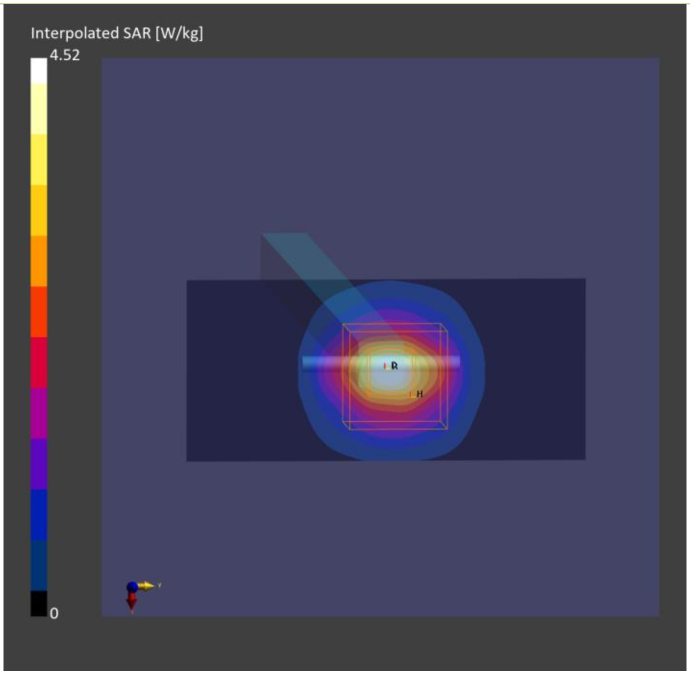
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00



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Measurement Report

S66 System Check H1750_240515

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.41	42.1

Hardware Setup

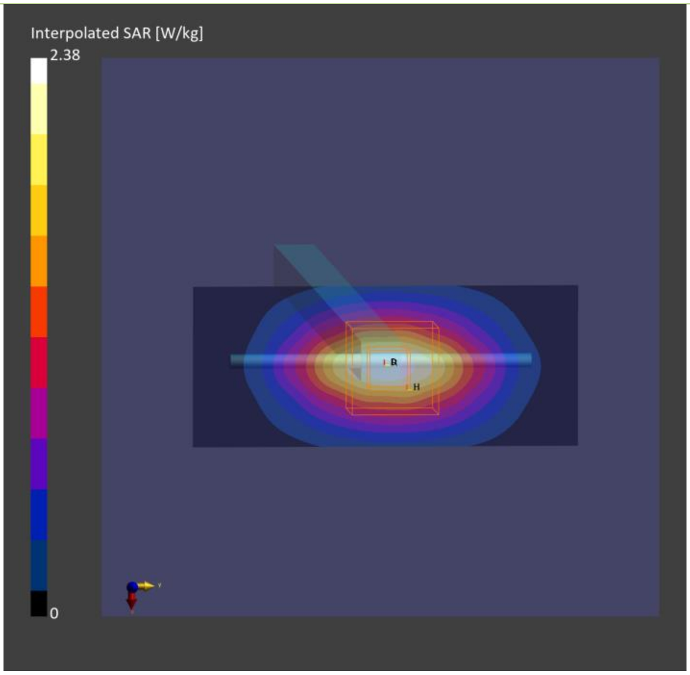
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	1.83	1.84
psSAR10g [W/kg]	0.97	0.962
Power Drift [dB]	0.00	0.01



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Measurement Report

S67 System Check H750_240515

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.89	43.9

Hardware Setup

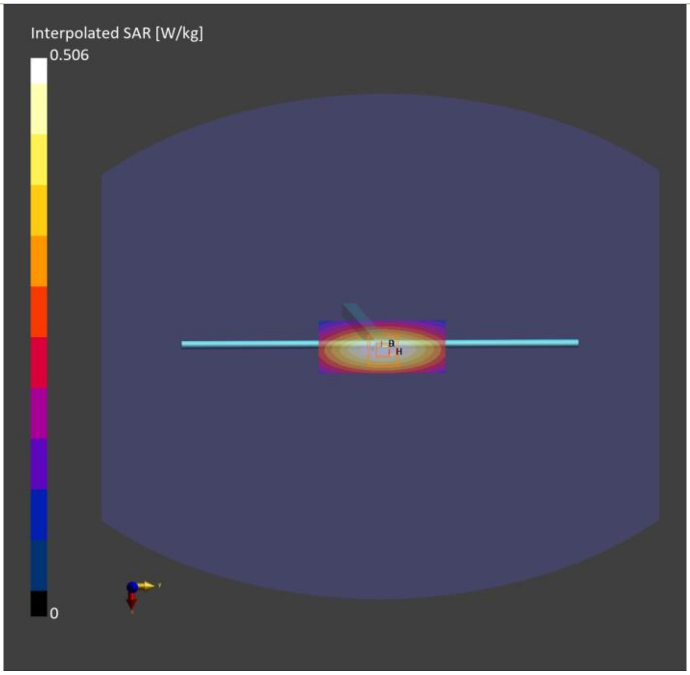
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	0.441	0.438
psSAR10g [W/kg]	0.298	0.291
Power Drift [dB]	0.00	0.05



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Measurement Report

S68 System Check H1900_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.5

Hardware Setup

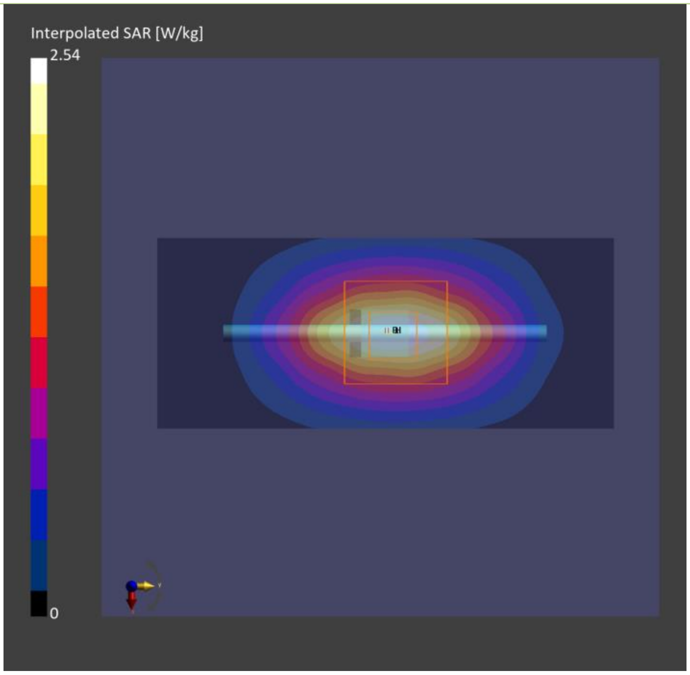
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	2.02	1.98
psSAR10g [W/kg]	1.04	1.03
Power Drift [dB]	-0.01	0.02



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Measurement Report

S69 System Check H835_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.9

Hardware Setup

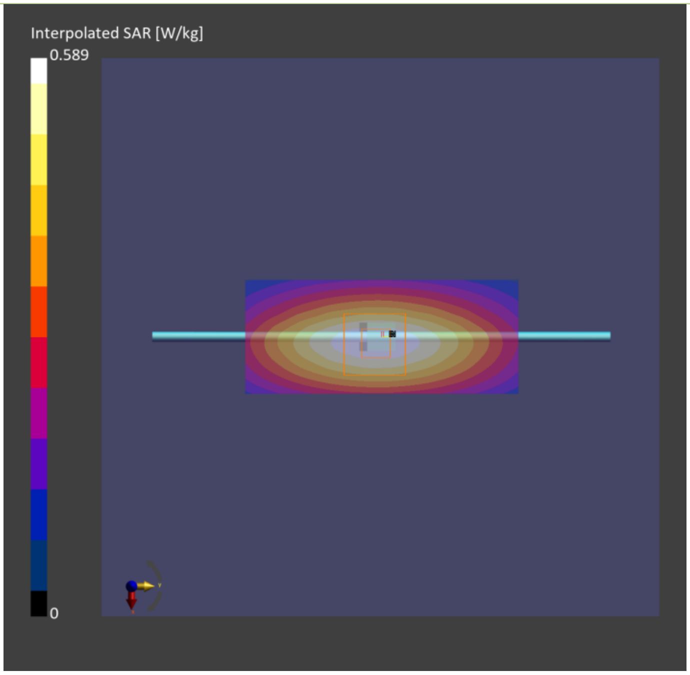
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	0.510	0.508
psSAR10g [W/kg]	0.337	0.334
Power Drift [dB]	0.02	-0.01



Measurement Report

S70 System Check H2600_240520

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.96	37.5

Hardware Setup

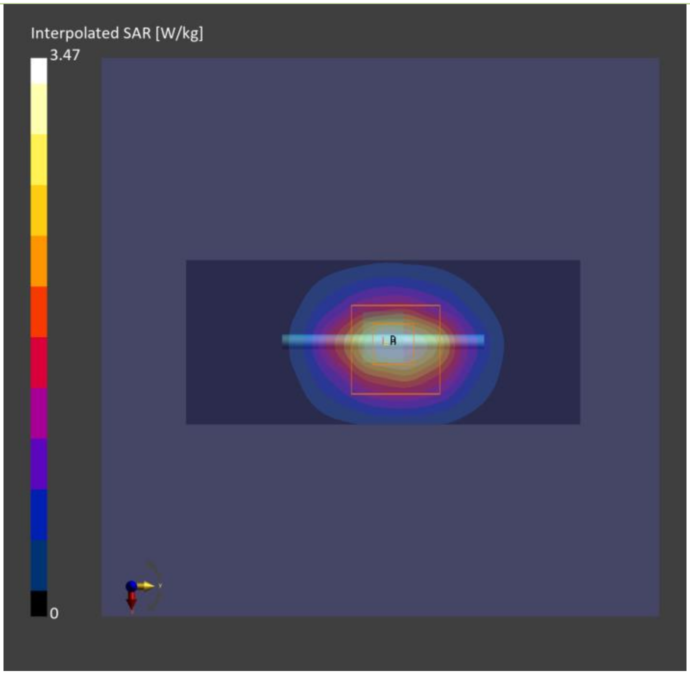
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-20	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-20	2024-05-20
psSAR1g [W/kg]	2.61	2.60
psSAR10g [W/kg]	1.17	1.16
Power Drift [dB]	-0.00	-0.01



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Measurement Report

S71 System Check H750_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.89	43.2

Hardware Setup

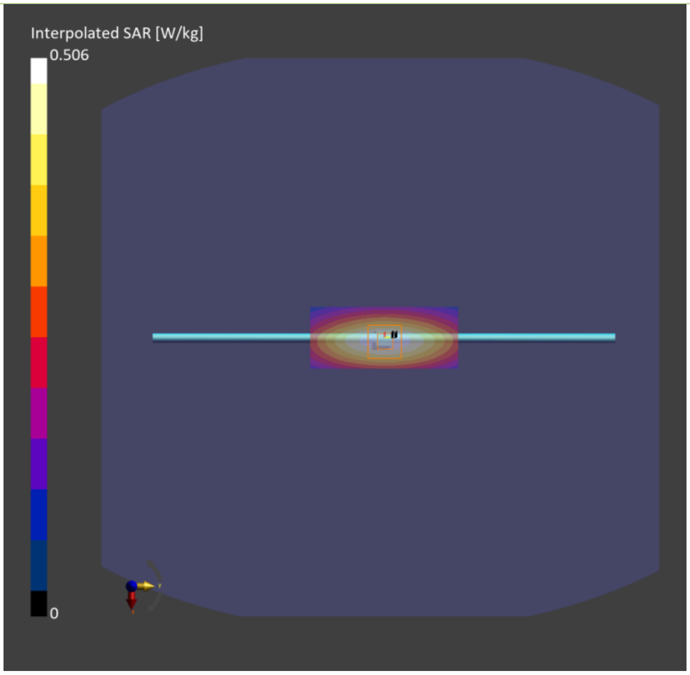
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	0.439	0.436
psSAR10g [W/kg]	0.294	0.289
Power Drift [dB]	0.02	0.01



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Measurement Report

S72 System Check H750_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.89	43.2

Hardware Setup

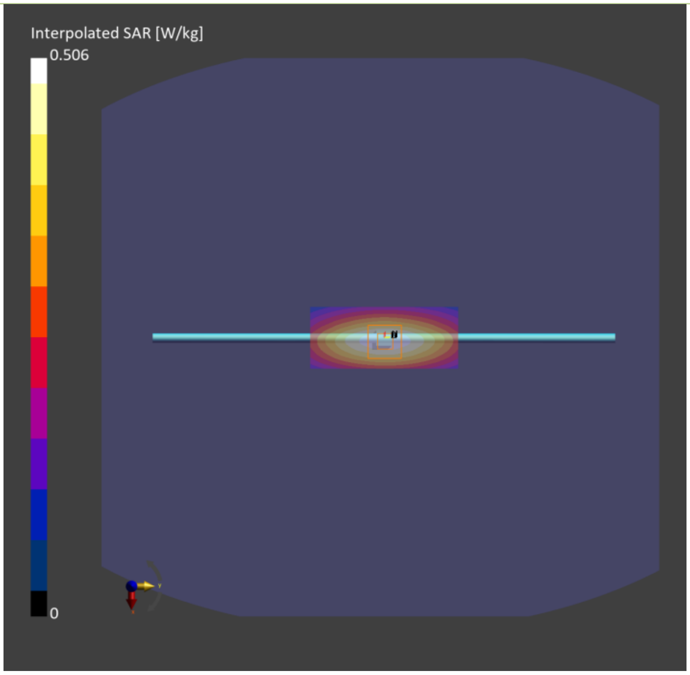
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	0.439	0.436
psSAR10g [W/kg]	0.294	0.289
Power Drift [dB]	0.02	0.01



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Measurement Report

S73 System Check H1900_240521

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.2

Hardware Setup

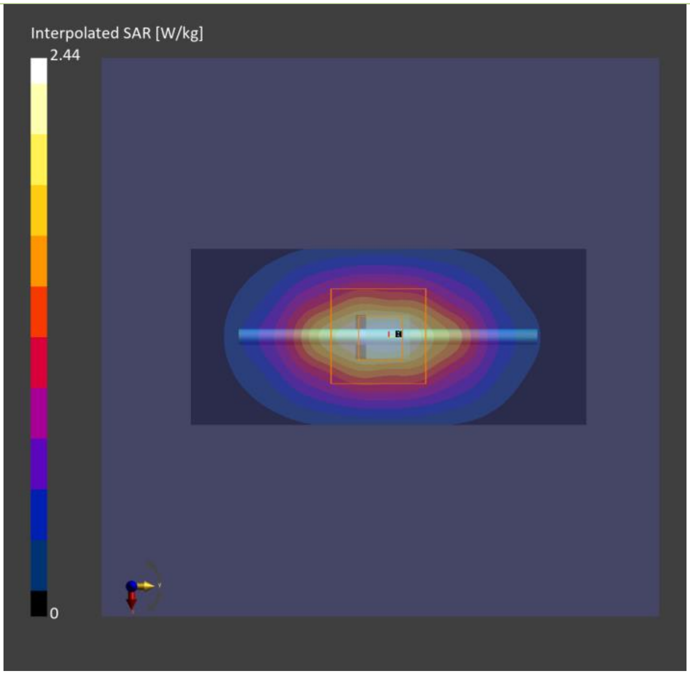
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-21	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-21	2024-05-21
psSAR1g [W/kg]	1.94	1.93
psSAR10g [W/kg]	0.998	1.02
Power Drift [dB]	0.01	0.01



Measurement Report
S74 System Check_H835_240520
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Dipole,	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.0, 0	10.39	0.93	40.7

Hardware Setup

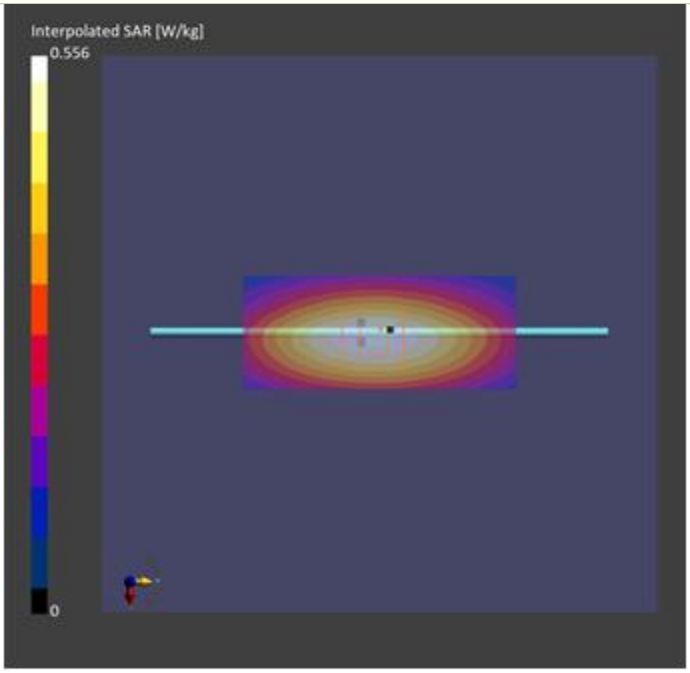
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-20	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-20	2024-05-20
psSAR1g [W/kg]	0.480	0.477
psSAR10g [W/kg]	0.316	0.313
Power Drift [dB]	0.01	0.07



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Measurement Report

S75 System Check_H2600_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	37.1

Hardware Setup

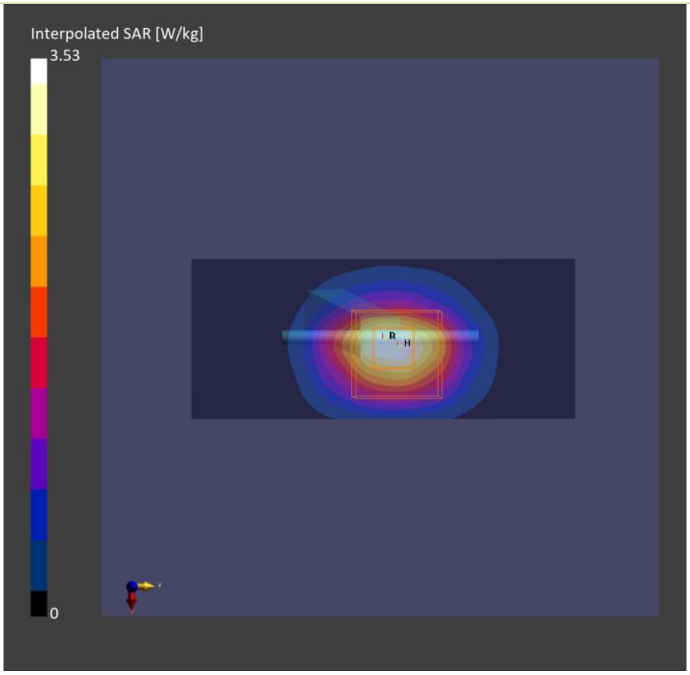
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	2.68	2.72
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	0.00	-0.00



Measurement Report

S76 System Check_H2600_240521

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Dipole	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	,			2600.000,	7.58	1.93	37.1

Hardware Setup

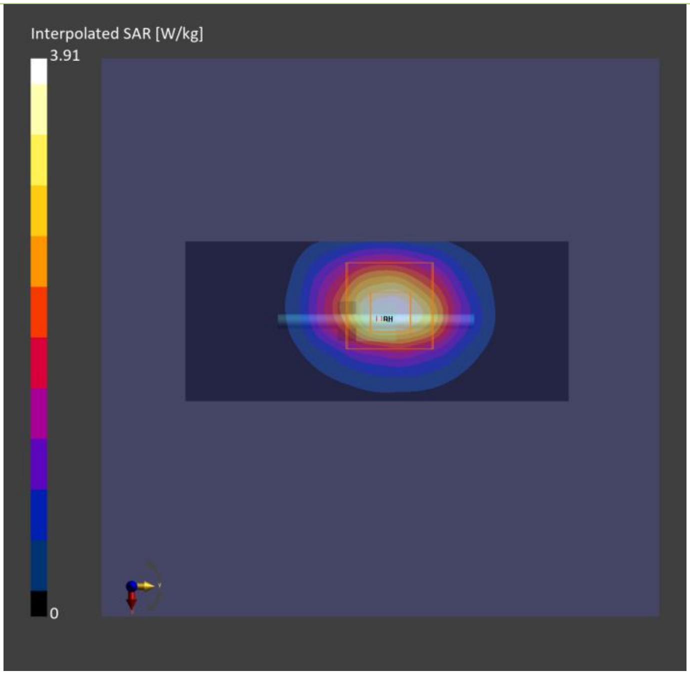
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-21	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-21	2024-05-21
psSAR1g [W/kg]	1.99	2.61
psSAR10g [W/kg]	1.38	1.36
Power Drift [dB]	-0.02	0.01



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Measurement Report

S77a System Check H3500_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	39.5

Hardware Setup

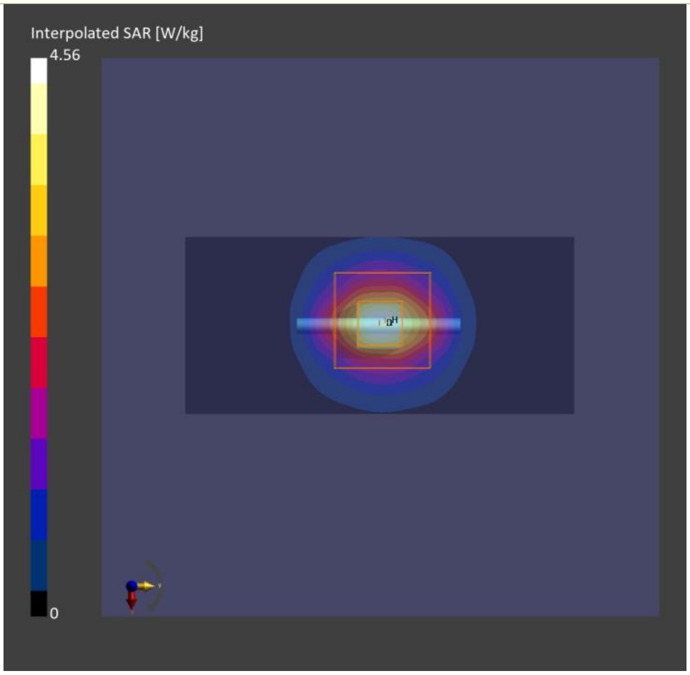
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.12	3.01
psSAR10g [W/kg]	1.17	1.12
Power Drift [dB]	0.01	-0.01



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Measurement Report

S77b System Check H3700_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.99	39.2

Hardware Setup

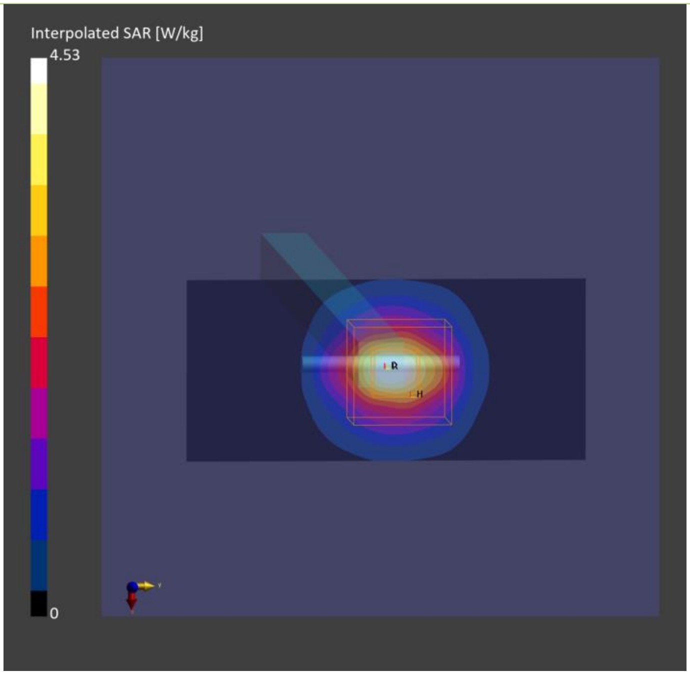
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.13	3.08
psSAR10g [W/kg]	1.11	1.14
Power Drift [dB]	-0.02	-0.01



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Measurement Report

S78 System Check H1750_240520

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.37	38.8

Hardware Setup

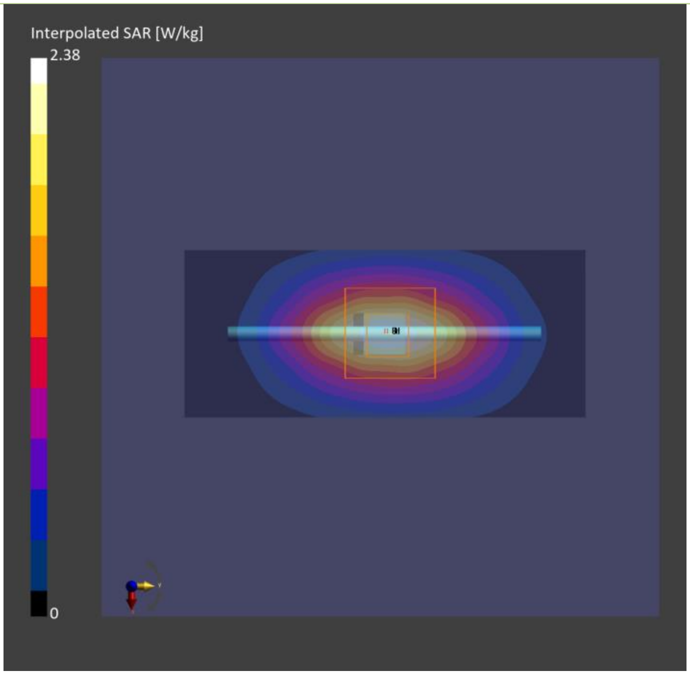
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-20	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-20	2024-05-20
psSAR1g [W/kg]	1.89	1.86
psSAR10g [W/kg]	1.00	0.985
Power Drift [dB]	0.00	0.00



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Measurement Report

S79 System Check H750_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.93	41.4

Hardware Setup

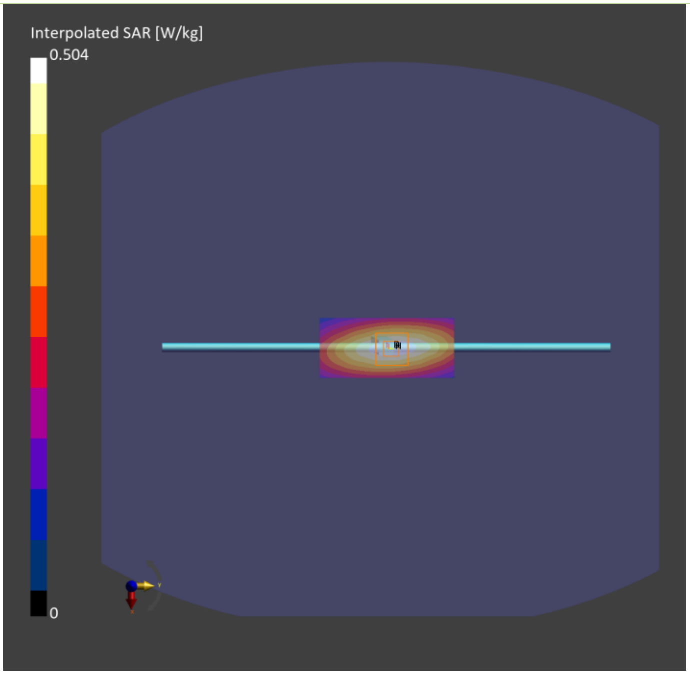
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	0.437	0.433
psSAR10g [W/kg]	0.290	0.286
Power Drift [dB]	-0.00	0.02



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Measurement Report
S80a System Check H3500_240524
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

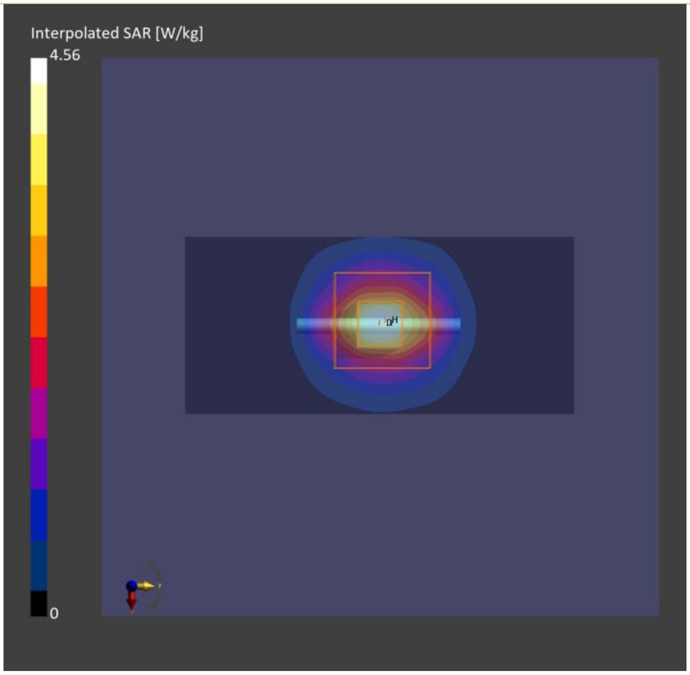
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.14	3.08
psSAR10g [W/kg]	1.17	1.16
Power Drift [dB]	0.01	-0.01



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Measurement Report

S80b System Check H3700_240524

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

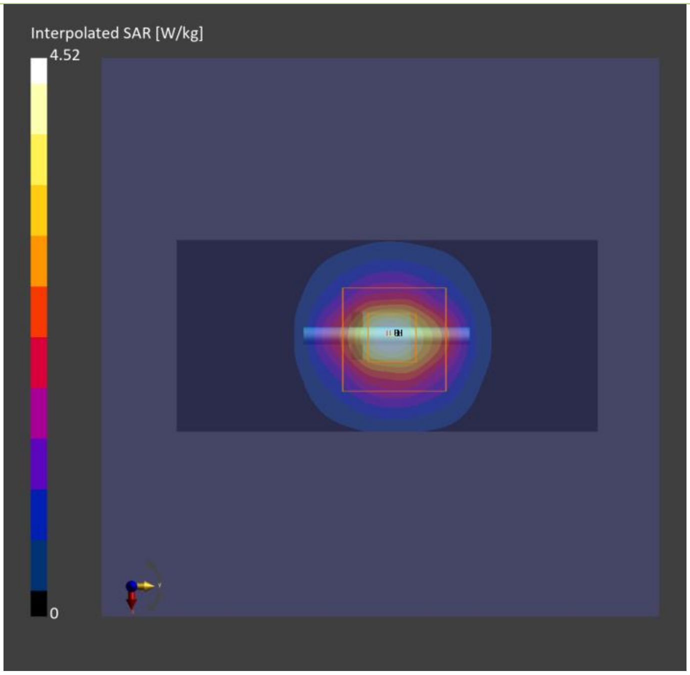
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.06	3.08
psSAR10g [W/kg]	1.14	1.14
Power Drift [dB]	0.01	0.00



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Measurement Report

S80c System Check H3900_240524

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	n/a x n/a x n/a		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	,		CW, 0--	3900.0, 0	6.53	3.17	38.8

Hardware Setup

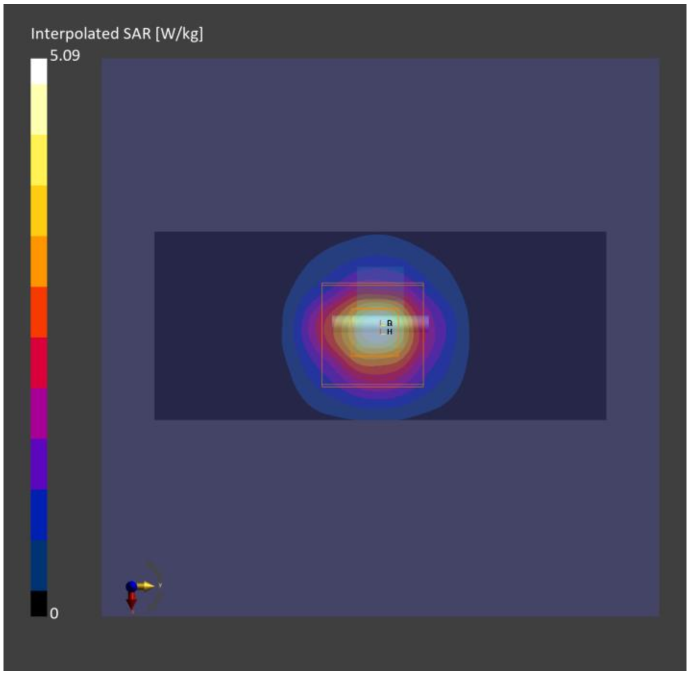
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.34	3.38
psSAR10g [W/kg]	1.19	1.21
Power Drift [dB]	0.02	-0.02



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Measurement Report

S82a System Check H3500_240524

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

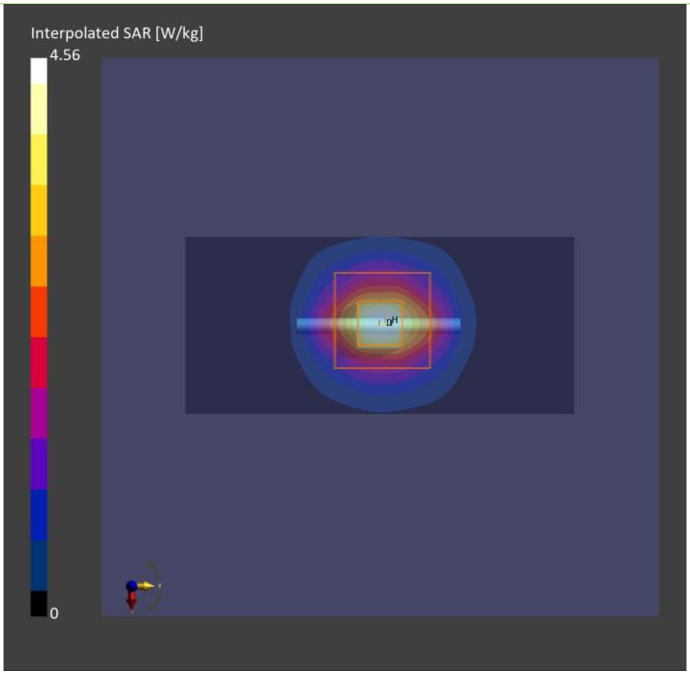
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.14	3.08
psSAR10g [W/kg]	1.17	1.16
Power Drift [dB]	0.01	-0.01



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Measurement Report

S82b System Check H3700_240524

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

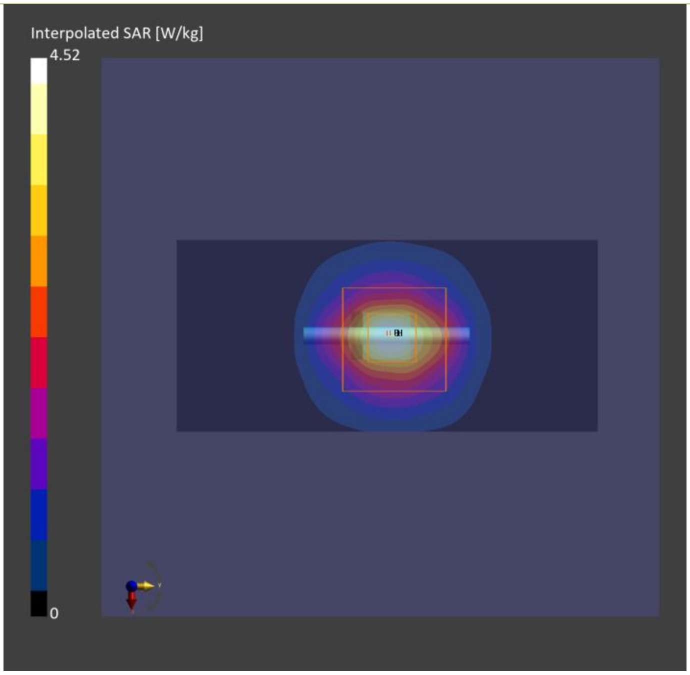
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.06	3.08
psSAR10g [W/kg]	1.14	1.14
Power Drift [dB]	0.01	0.00



Measurement Report
S84 System Check H2450_240430
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.0, 0	7.65	1.83	40.1

Hardware Setup

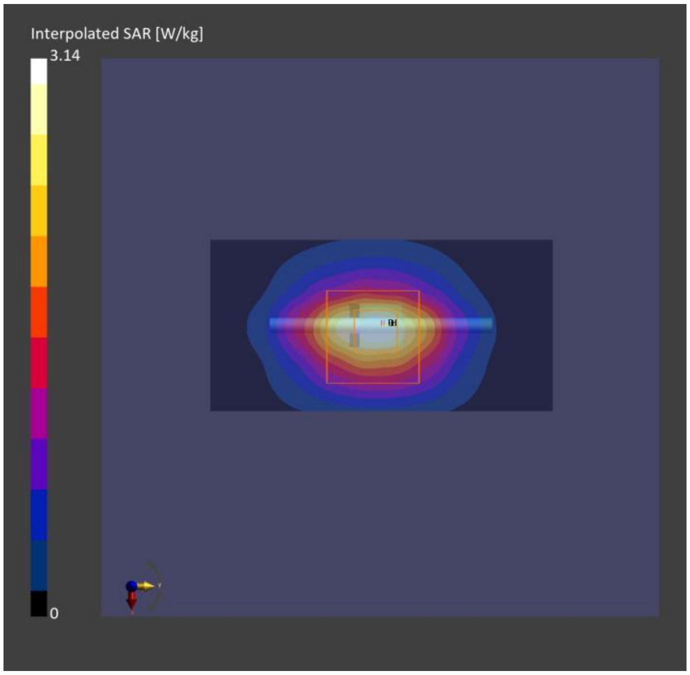
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-30	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 84.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-30	2024-04-30
psSAR1g [W/kg]	2.37	2.39
psSAR10g [W/kg]	1.09	1.14
Power Drift [dB]	-0.06	-0.05



Measurement Report
S85 System Check_H5250_240430
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5250

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5250.000, 0	5.52	4.49	37.2

Hardware Setup

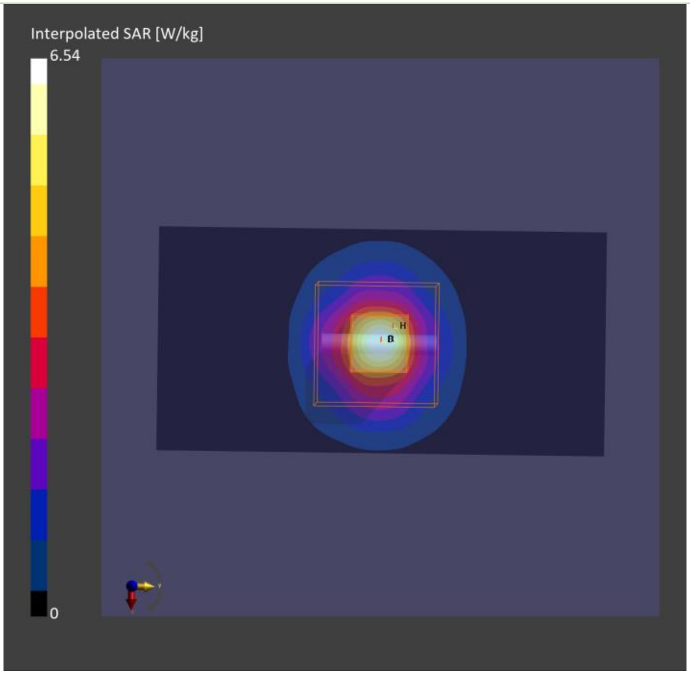
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-30	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-30	2024-04-30
psSAR1g [W/kg]	3.97	4.14
psSAR10g [W/kg]	1.11	1.16
Power Drift [dB]	-0.00	0.03



Measurement Report

S86 System Check_H5600_240502

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5600.0, 0	4.8	4.88	34.7

Hardware Setup

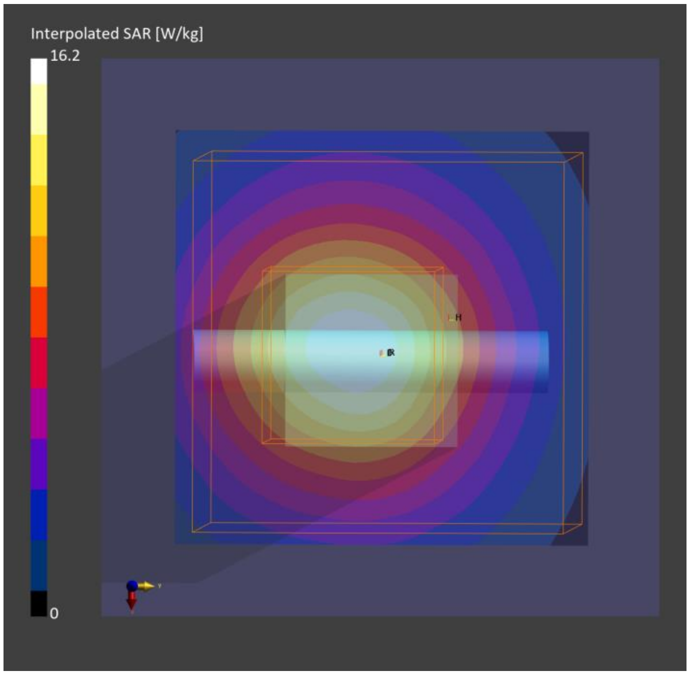
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-02	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-02	2024-05-02
psSAR1g [W/kg]	3.65	3.93
psSAR10g [W/kg]	1.07	1.17
Power Drift [dB]	0.03	-0.03



Measurement Report

S87 System Check_H5750_240502

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5800

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5750.000, 0	4.96	5.04	34.5

Hardware Setup

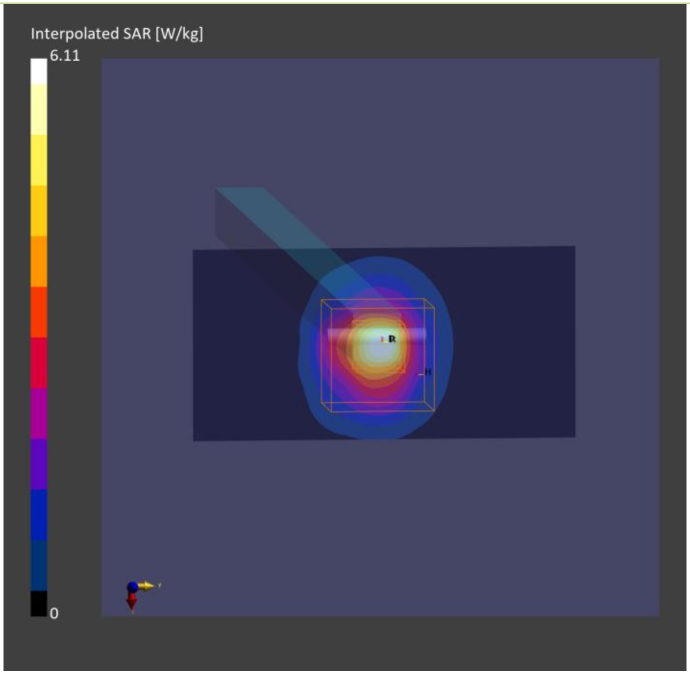
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-02	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-02	2024-05-02
psSAR1g [W/kg]	3.96	4.24
psSAR10g [W/kg]	1.17	1.23
Power Drift [dB]	0.01	-0.03



Measurement Report

S88 System Check H2450_240430

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.0, 0	7.65	1.83	40.1

Hardware Setup

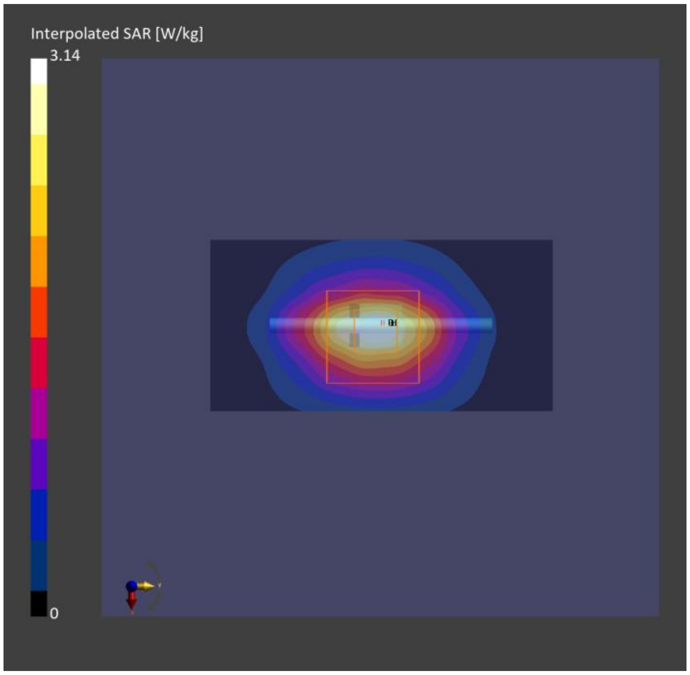
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-30	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 84.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-30	2024-04-30
psSAR1g [W/kg]	2.37	2.39
psSAR10g [W/kg]	1.09	1.14
Power Drift [dB]	-0.06	-0.05



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Test Laboratory: Bureau Veritas ADT SAR/HAC Testing Lab Date: 2024/05/01

S89 System Check_H13MHz_240501

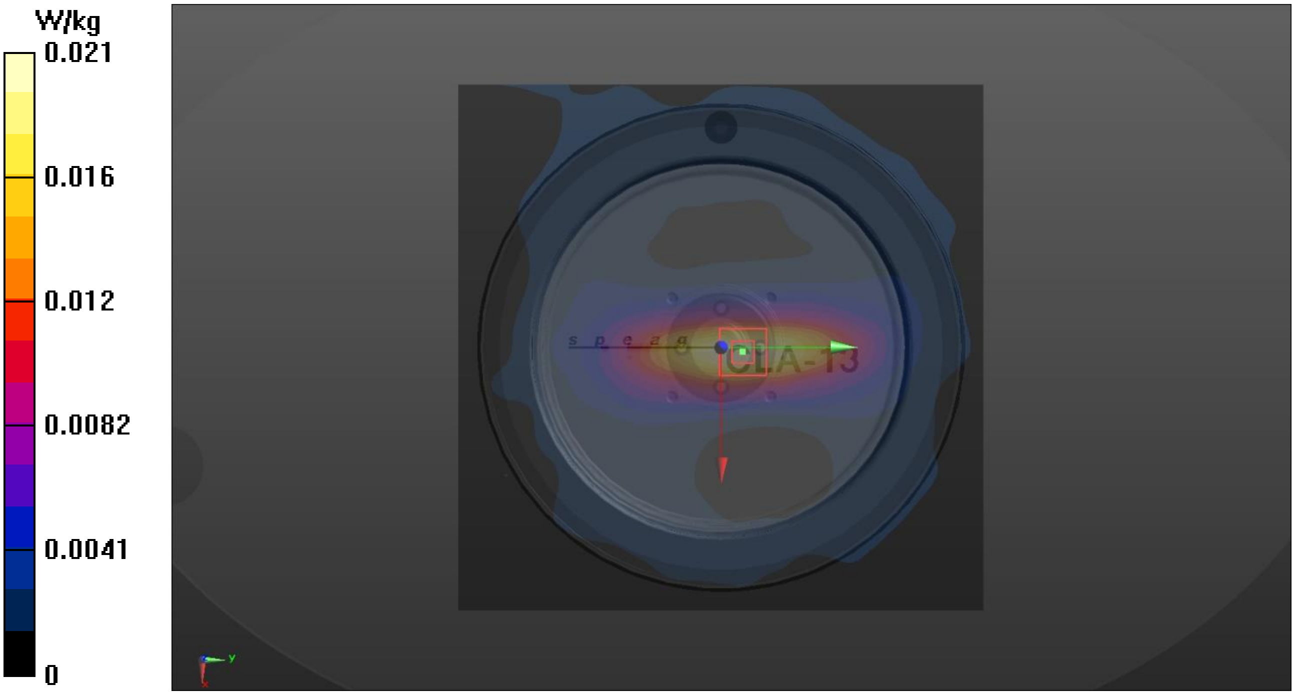
DUT: CLA-13 MHz ;Type: CLA-13 ;SN: 1018

Communication System: UID 10453 - AAD, Validation (Square, 10ms, 1ms); Frequency: 13 MHz;Duty Cycle: 1:10
Medium: H13_0501 Medium parameters used: f = 13 MHz; σ = 0.731 S/m; ε_r = 55.21; ρ = 1000 kg/m^3
Ambient Temperature : 22.6 ℃ ; Liquid Temperature : 21.7 ℃

DASY5 Configuration:
- Probe: EX3DV4 – SN3650; ConvF(16.01, 16.01, 16.01) @ 13 MHz; Calibrated: 2024/03/19
- Sensor-Surface: 1.4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn1431; Calibrated: 2023/08/24
- Phantom: SAM Phantom_1987; Type: QD 000 P40 CD Ax; Serial: 1987
- Measurement SW: DASY52, Version 52.10 (4); SEMCAD X Version 14.6.14 (7501)

Pin=1W/Area Scan (241x241x1): Interpolated grid: dx=1.000 mm, dy=1.000 mm
Maximum value of SAR (interpolated) = 0.0205 W/kg

Pin=1W/Zoom Scan (7x7x16)/Cube 0: Measurement grid: dx=4mm, dy=4mm, dz=1.4mm
Reference Value = 5.167 V/m; Power Drift = -0.03 dB
Peak SAR (extrapolated) = 0.0300 W/kg
SAR(1 g) = 0.025 W/kg; SAR(10 g) = 0.017 W/kg (SAR corrected for target medium)
Maximum value of SAR (measured) = 0.0203 W/kg



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Measurement Report

S105 System Check H2300_240517

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2300

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2300.000, 0	7.95	1.75	37.6

Hardware Setup

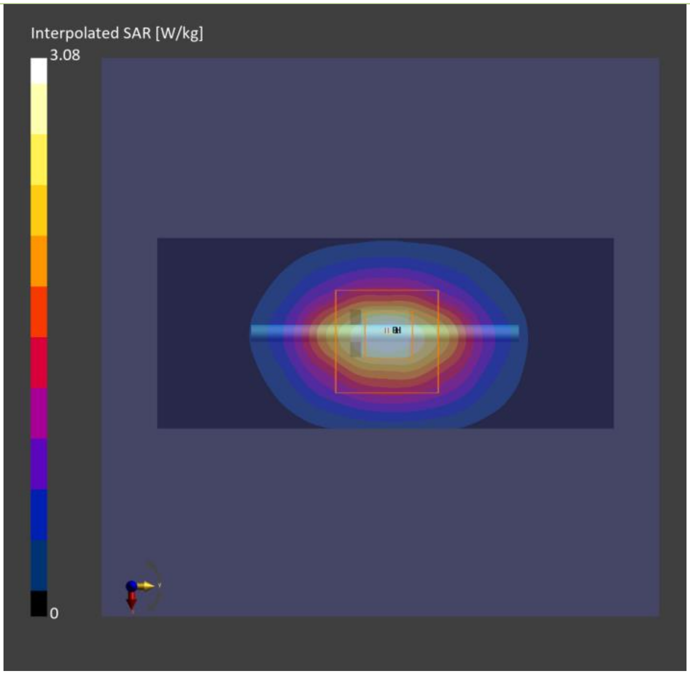
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-17	2024-05-17
psSAR1g [W/kg]	2.35	2.33
psSAR10g [W/kg]	1.12	1.11
Power Drift [dB]	0.02	0.01



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Measurement Report

S106 System Check_H2600_240517

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

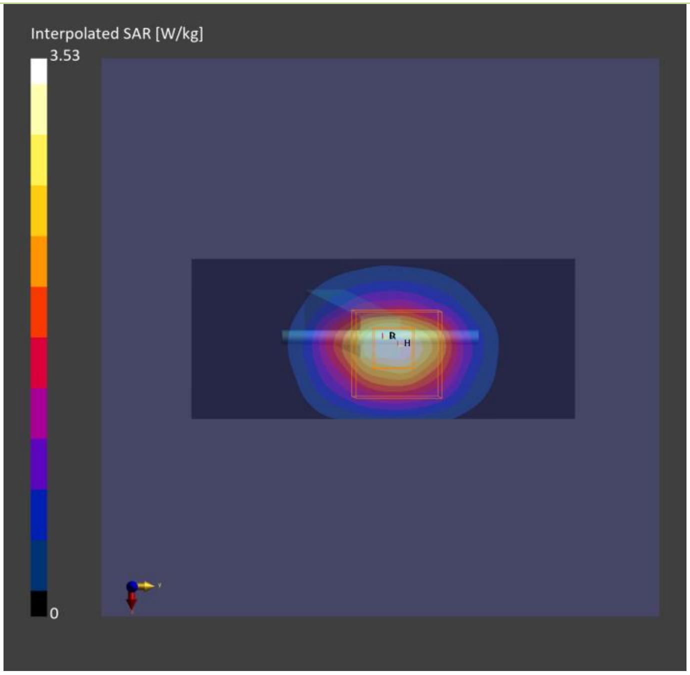
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-017	2024-05-17
psSAR1g [W/kg]	2.68	2.72
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	0.00	-0.00



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Measurement Report

S109 System Check H3700_240517

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

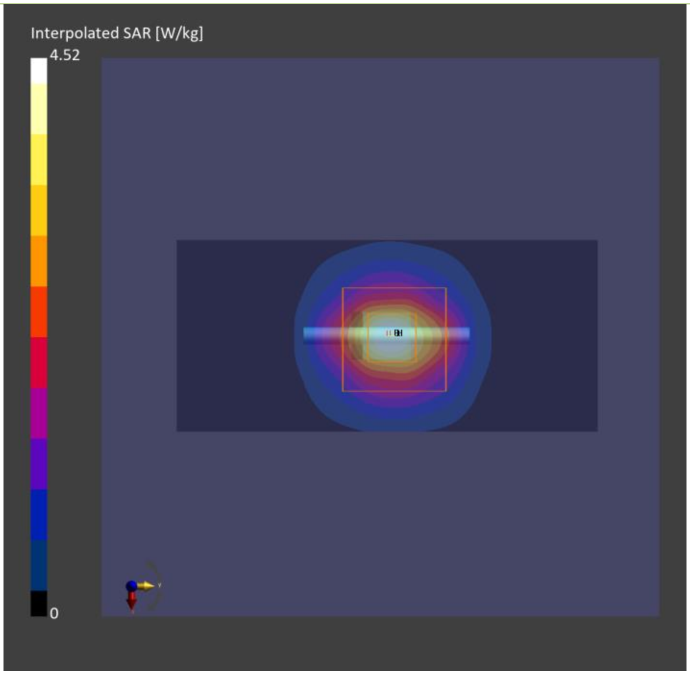
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-17	2024-05-17
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00



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Measurement Report

S113 System Check H1900_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.5

Hardware Setup

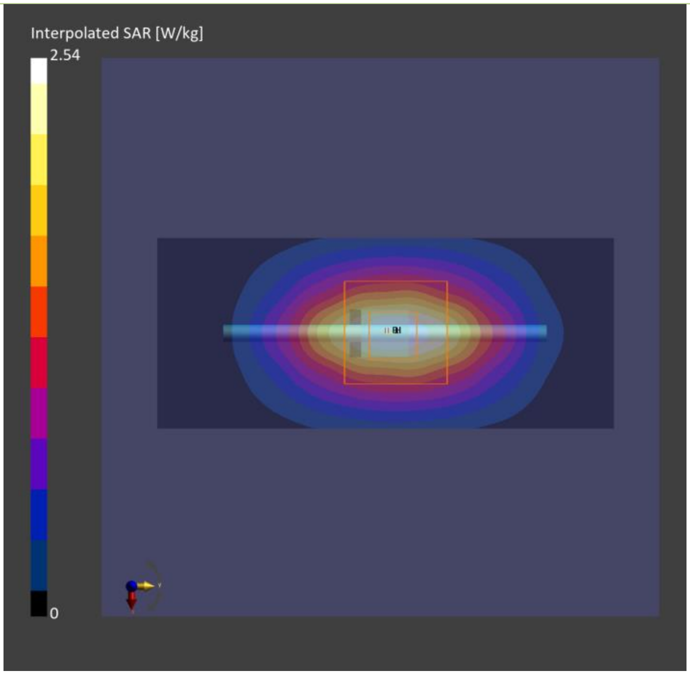
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	2.02	1.98
psSAR10g [W/kg]	1.04	1.03
Power Drift [dB]	-0.01	0.02



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Measurement Report

S118 System Check H1900_240523

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.40	39.7

Hardware Setup

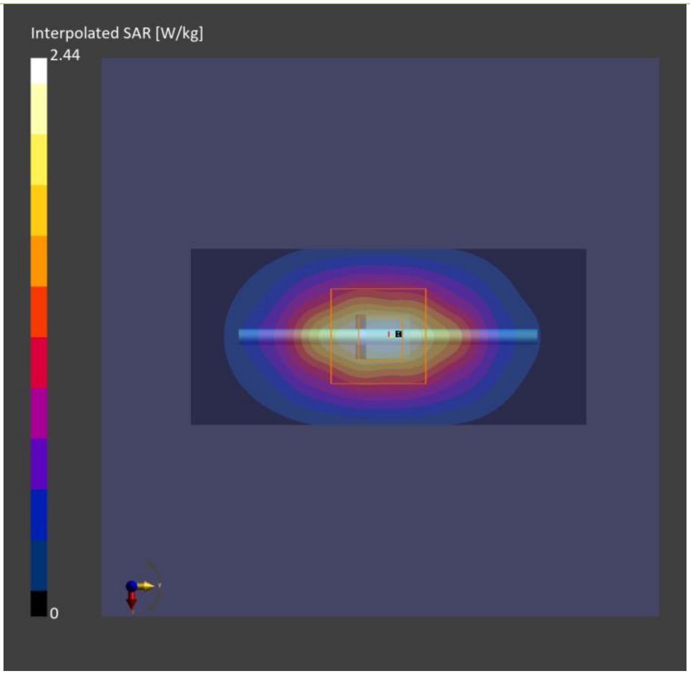
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	1.93	1.91
psSAR10g [W/kg]	0.996	1.00
Power Drift [dB]	0.01	0.01



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Measurement Report

S120 System Check_H2600_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	37.1

Hardware Setup

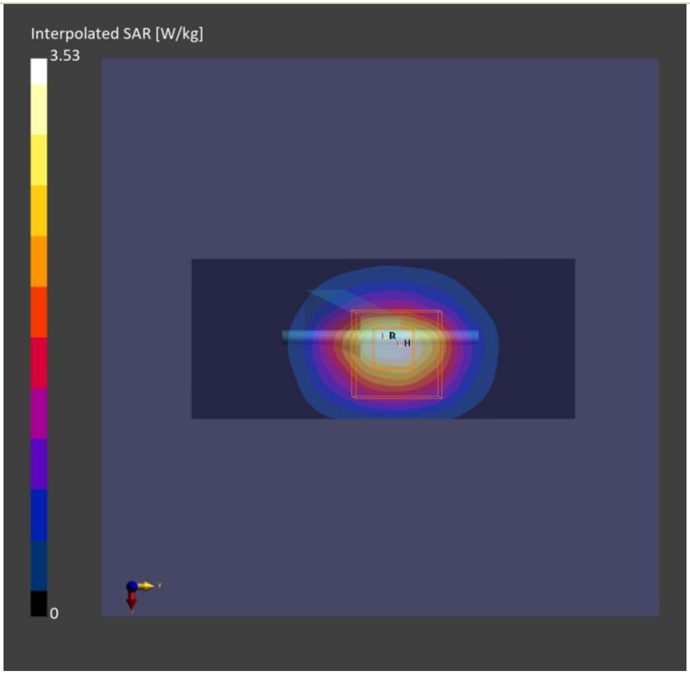
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	2.68	2.72
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	0.00	-0.00



Measurement Report

S121 System Check_H2600_240521

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Dipole	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	,			2600	7.58	1.93	37.1

Hardware Setup

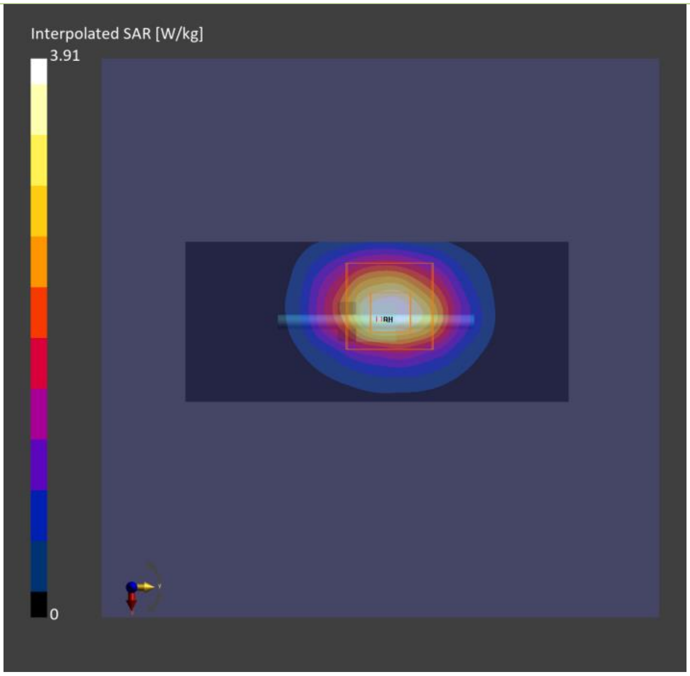
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-21	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-21	2024-05-21
psSAR1g [W/kg]	1.99	2.61
psSAR10g [W/kg]	1.38	1.36
Power Drift [dB]	-0.02	0.01



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Measurement Report

S122a System Check H3500_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	39.5

Hardware Setup

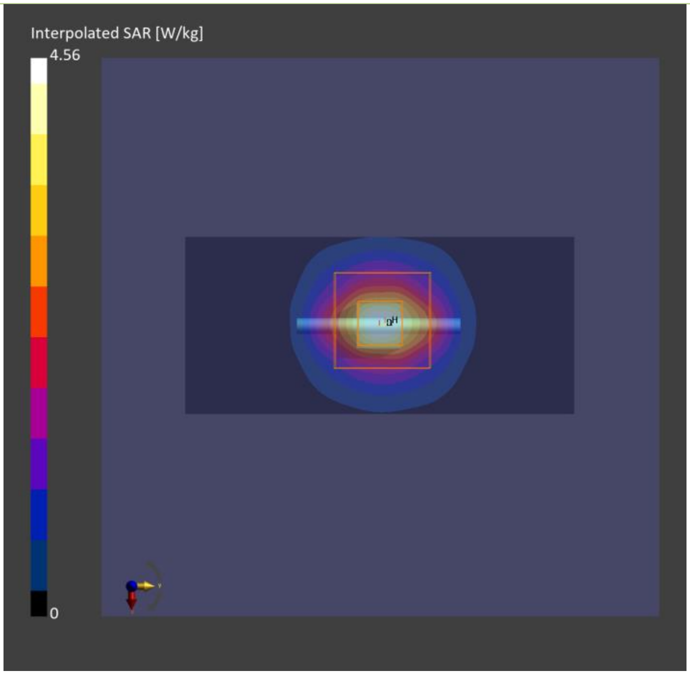
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.12	3.01
psSAR10g [W/kg]	1.17	1.12
Power Drift [dB]	0.01	-0.01



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Measurement Report

S122b System Check H3700_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.99	39.2

Hardware Setup

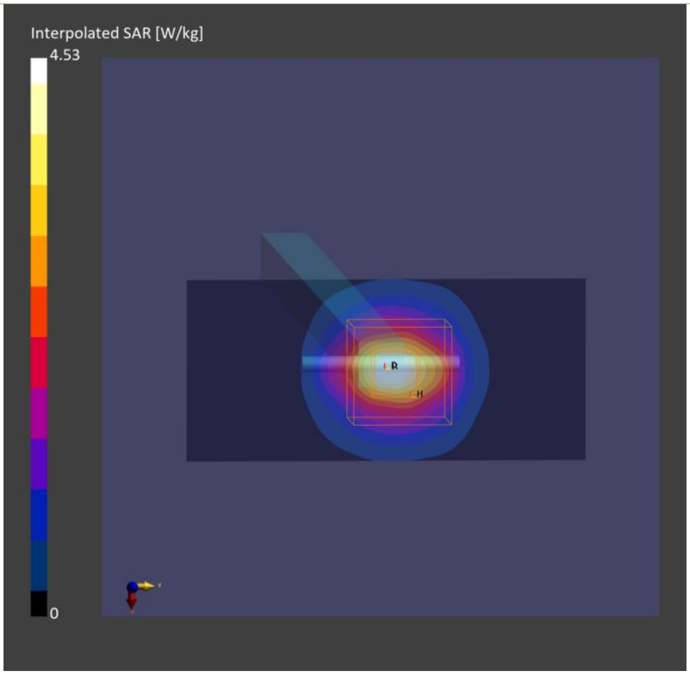
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.13	3.08
psSAR10g [W/kg]	1.11	1.14
Power Drift [dB]	-0.02	-0.01



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Measurement Report

S124 System Check H750_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.93	41.4

Hardware Setup

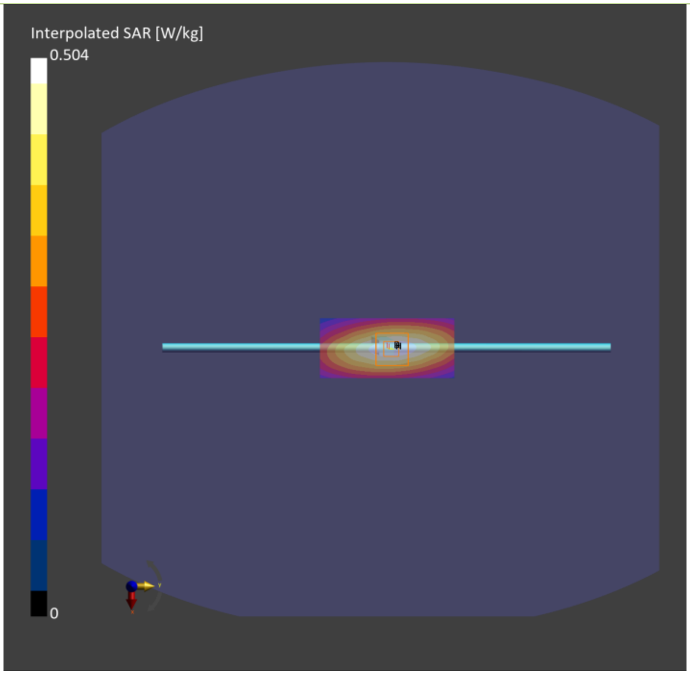
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	0.437	0.433
psSAR10g [W/kg]	0.290	0.286
Power Drift [dB]	-0.00	0.02



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Measurement Report

S125a System Check H3500_240523

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.85	38.4

Hardware Setup

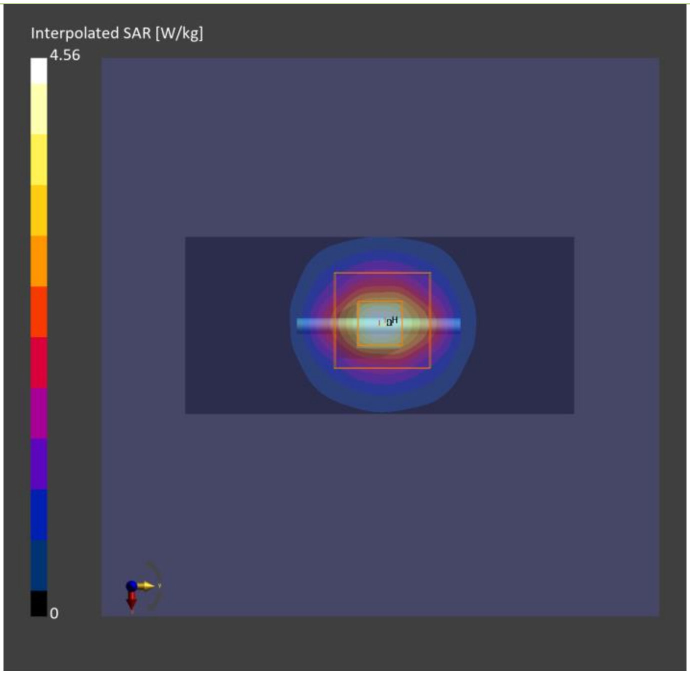
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.16	3.10
psSAR10g [W/kg]	1.19	1.18
Power Drift [dB]	0.01	-0.01



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Measurement Report

S125b System Check H3700_240523

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.03	38.1

Hardware Setup

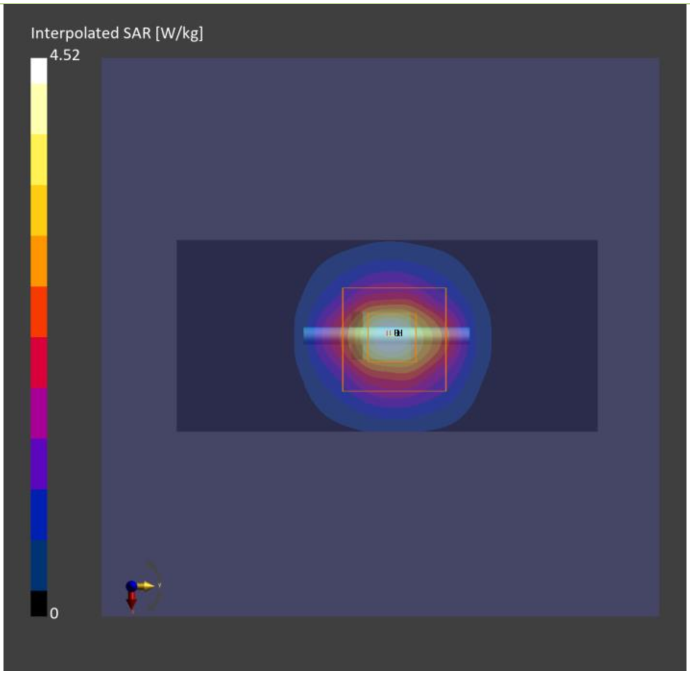
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00



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Measurement Report

S125c System Check H3900_240523

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	n/a x n/a x n/a		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	,		CW, 0--	3900.0, 0	6.53	3.23	37.8

Hardware Setup

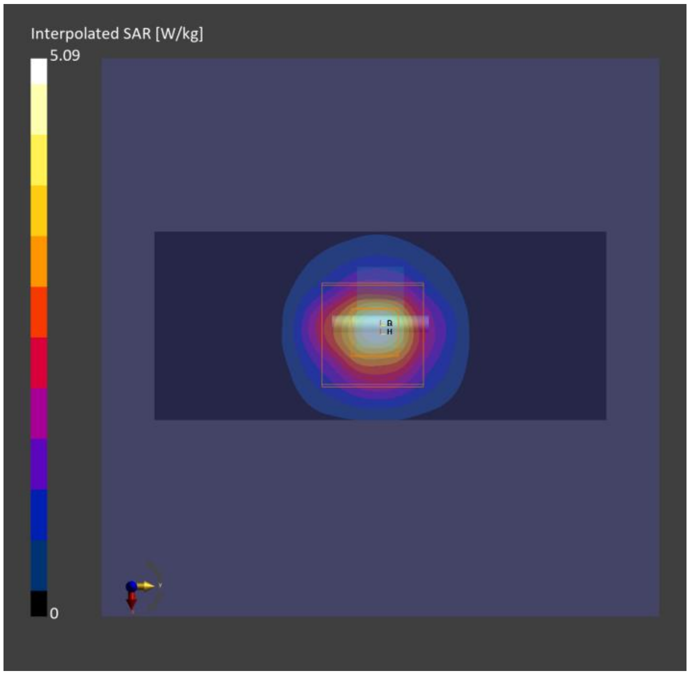
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.42	3.42
psSAR10g [W/kg]	1.21	1.23
Power Drift [dB]	0.02	-0.02



Measurement Report
S127a System Check H3500_240523
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.85	38.4

Hardware Setup

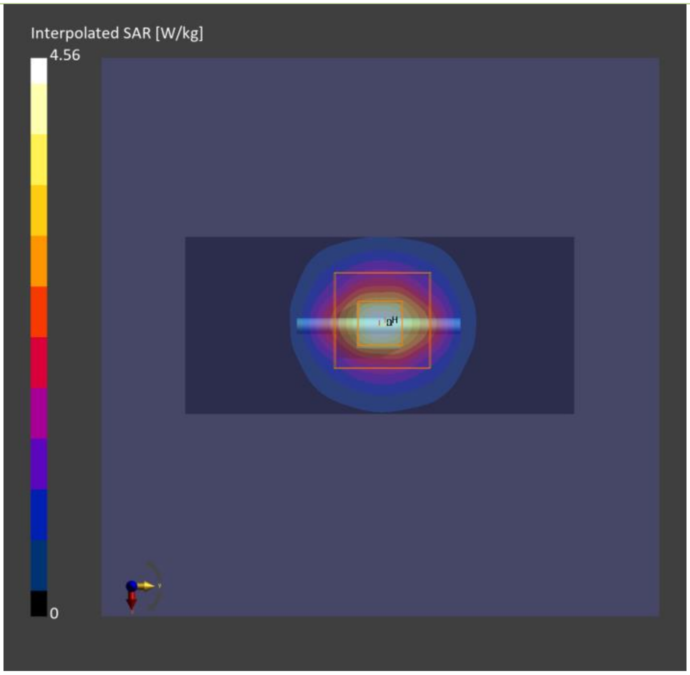
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.16	3.10
psSAR10g [W/kg]	1.19	1.18
Power Drift [dB]	0.01	-0.01



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Measurement Report

S127b System Check H3700_240523

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.03	38.1

Hardware Setup

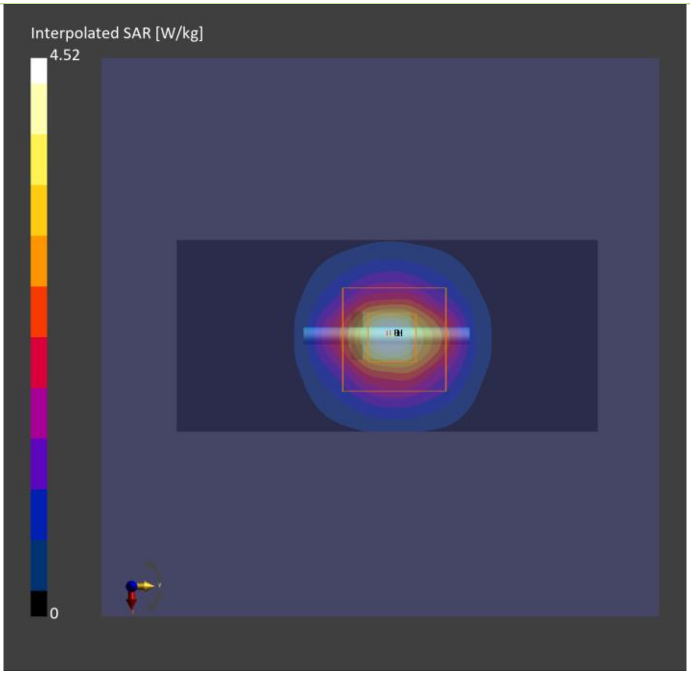
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00



Measurement Report

S129 System Check H2450_240502

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.0, 0	7.65	1.72	40.6

Hardware Setup

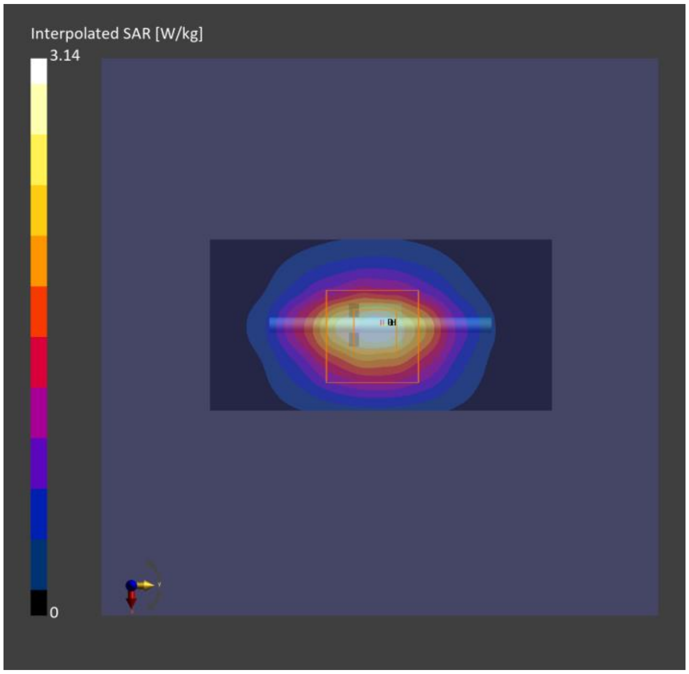
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-02	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 84.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-02	2024-05-02
psSAR1g [W/kg]	2.39	2.41
psSAR10g [W/kg]	1.10	1.12
Power Drift [dB]	-0.06	-0.05



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Measurement Report

S135 System Check H6500_240506

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	6500.000, 0	5.4	6.07	34.5

Hardware Setup

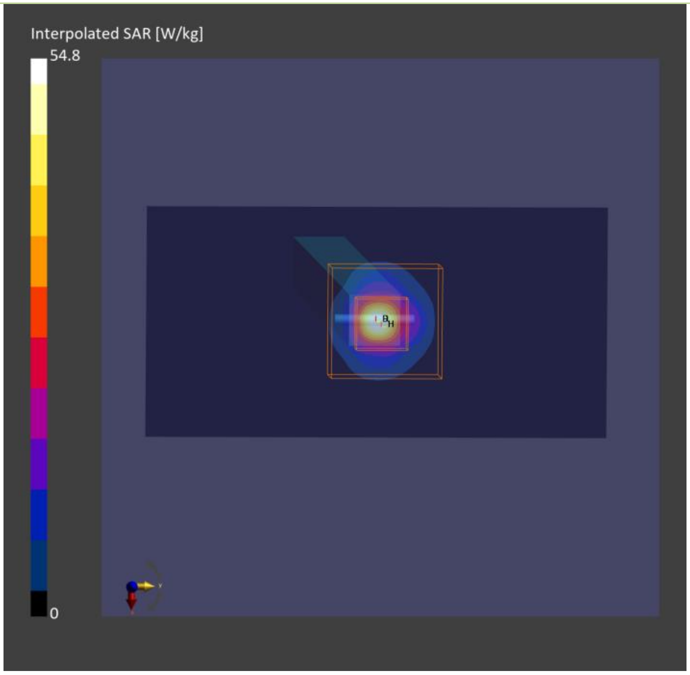
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	27.5	30.7
psSAR10g [W/kg]	5.29	5.63
psAPD (1.0cm2, sq) [W/m2]		307
psAPD (4.0cm2, sq) [W/m2]		137
Power Drift [dB]	0.02	-0.02
M2/M1 [%]		50.6
Dist 3dB Peak [mm]		4.4



Measurement Report

S130 System Check H5250_240504

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5250.000, 0	5.52	4.40	36.0

Hardware Setup

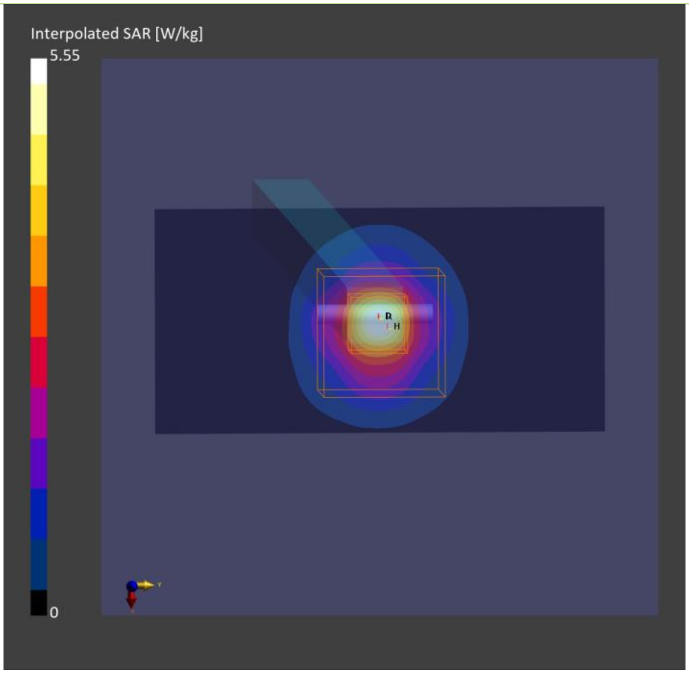
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-04	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-04	2024-05-04
psSAR1g [W/kg]	3.36	3.63
psSAR10g [W/kg]	0.950	1.05
Power Drift [dB]	-0.06	0.09



Measurement Report

S131 System Check H5600_240504

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5600.000, 0	4.8	4.94	35.9

Hardware Setup

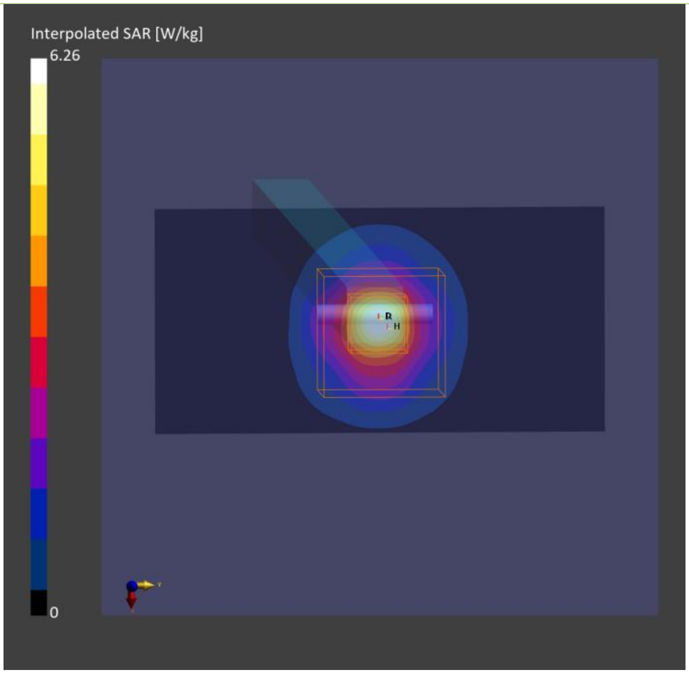
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-04	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-04	2024-05-04
psSAR1g [W/kg]	3.85	4.05
psSAR10g [W/kg]	1.08	1.15
Power Drift [dB]	0.01	0.06



Measurement Report
S132 System Check H5750_240504

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5750.000, 0	4.96	5.12	35.7

Hardware Setup

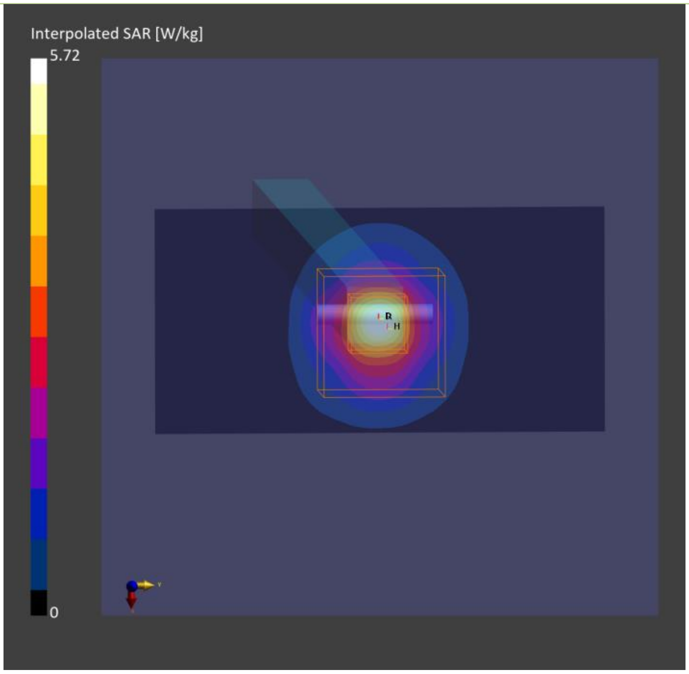
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-04	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-04	2024-05-04
psSAR1g [W/kg]	3.54	3.75
psSAR10g [W/kg]	0.987	1.06
Power Drift [dB]	-0.00	0.06



Plots of System Verification

Test Laboratory: Bureau Veritas ADT SAR/HAC Testing Lab　　　　Date: 2024/05/01

S134 System Check_H13MHz_240501

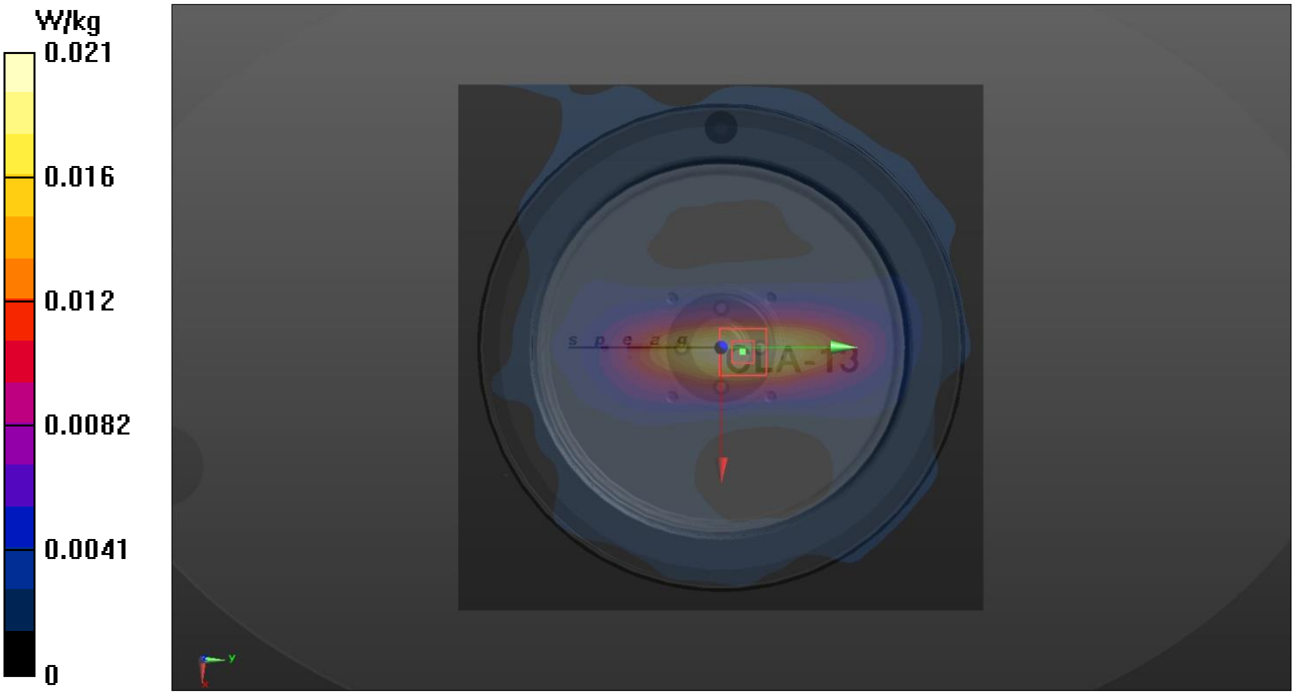
DUT: CLA-13 MHz ;Type: CLA-13 ;SN: 1018

Communication System: UID 10453 - AAD, Validation (Square, 10ms, 1ms); Frequency: 13 MHz;Duty Cycle: 1:10
Medium: H13_0501 Medium parameters used: f = 13 MHz; σ = 0.731 S/m; ε_r = 55.21; ρ = 1000 kg/m^3
Ambient Temperature：22.6 ℃； Liquid Temperature：21.7 ℃

DASY5 Configuration:
- Probe: EX3DV4 – SN3650; ConvF(16.01, 16.01, 16.01) @ 13 MHz; Calibrated: 2024/03/19
- Sensor-Surface: 1.4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn1431; Calibrated: 2023/08/24
- Phantom: SAM Phantom_1987; Type: QD 000 P40 CD Ax; Serial: 1987
- Measurement SW: DASY52, Version 52.10 (4); SEMCAD X Version 14.6.14 (7501)

Pin=1W/Area Scan (241x241x1): Interpolated grid: dx=1.000 mm, dy=1.000 mm
Maximum value of SAR (interpolated) = 0.0201 W/kg

Pin=1W/Zoom Scan (7x7x16)/Cube 0: Measurement grid: dx=4mm, dy=4mm, dz=1.4mm
Reference Value = 5.167 V/m; Power Drift = -0.01 dB
Peak SAR (extrapolated) = 0.0300 W/kg
SAR(1 g) = 0.025 W/kg; SAR(10 g) = 0.017 W/kg (SAR corrected for target medium)
Maximum value of SAR (measured) = 0.0203 W/kg



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Measurement Report

S136 System Check H6500_240506

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	6500.000, 0	5.4	6.07	34.5

Hardware Setup

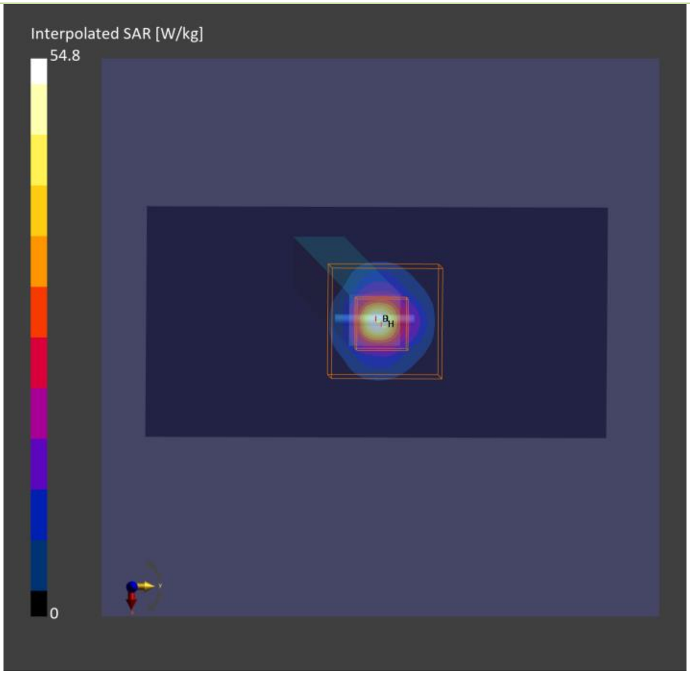
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	27.5	30.7
psSAR10g [W/kg]	5.29	5.63
psAPD (1.0cm2, sq) [W/m2]		307
psAPD (4.0cm2, sq) [W/m2]		137
Power Drift [dB]	0.02	-0.02
M2/M1 [%]		50.6
Dist 3dB Peak [mm]		4.4



Measurement Report
S135 PD_System Check_10 GHz_2024.05.22
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
SPEAG, 5G Verification Source 10 GHz	100.0 x 100.0 x 170.0	SN: 1025	Phone

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	FRONT, 10.00	Validation band	CW, 0--	10000.0, 10000	1.0

Hardware Setup

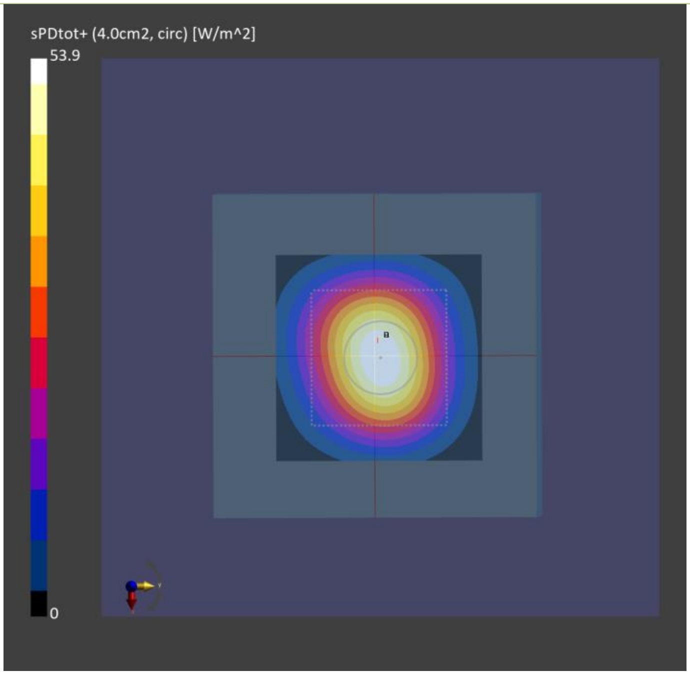
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	--Air--	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan
Grid Extents [mm]	60.0 x 60.0
Grid Steps [lambda]	0.125 x 0.125
Sensor Surface [mm]	10.0

Measurement Results

	5G Scan
Date	2024-05-22
Avg. Area [cm²]	4.00
psPDn+ [W/m²]	53.7
psPDtot+ [W/m²]	53.9
psPDmod+ [W/m²]	54.1
E_{max} [V/m]	149
Power Drift [dB]	-0.04



Measurement Report

S136 PD_System Check_10 GHz_2024.05.22

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
SPEAG, 5G Verification Source 10 GHz	100.0 x 100.0 x 170.0	SN: 1025	Phone

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	FRONT, 10.00	Validation band	CW, 0--	10000.0, 10000	1.0

Hardware Setup

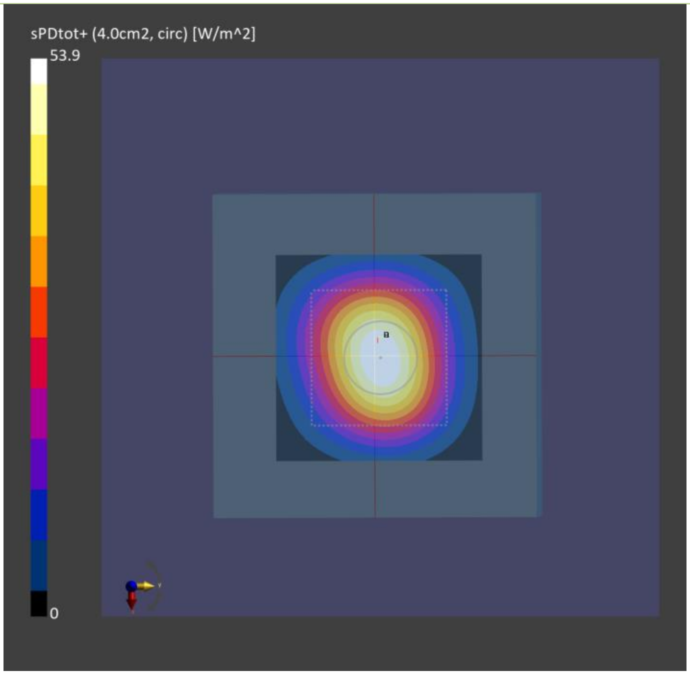
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	--Air--	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan
Grid Extents [mm]	60.0 x 60.0
Grid Steps [lambda]	0.125 x 0.125
Sensor Surface [mm]	10.0

Measurement Results

	5G Scan
Date	2024-05-22
Avg. Area [cm²]	4.00
psPDn+ [W/m²]	53.7
psPDtot+ [W/m²]	53.9
psPDmod+ [W/m²]	54.1
E_{max} [V/m]	149
Power Drift [dB]	-0.04



Appendix B. Plots of Measurement

The SAR plots for highest measured SAR in each exposure configuration, wireless mode and frequency band combination are shown as follows.

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Measurement Report

P01 GSM850_GPRS 4Tx Slot_Left Cheek_Ch189_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	GSM 850	GSM, 10028-DAC	836.400, 189	10.39	0.92	42.5

Hardware Setup

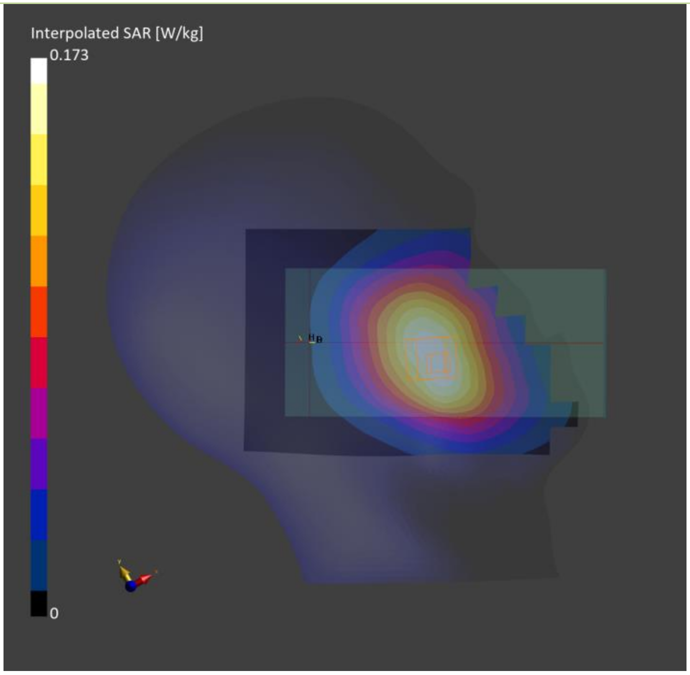
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.150	0.163
psSAR10g [W/kg]	0.104	0.128
Power Drift [dB]	-0.06	0.02
M2/M1 [%]		79.9
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P02 GSM1900_GPRS 4Tx Slot_Left Cheek_Ch512_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	PCS 1900	GSM, 10028-DAC	1850.200, 512	8.31	1.42	41.2

Hardware Setup

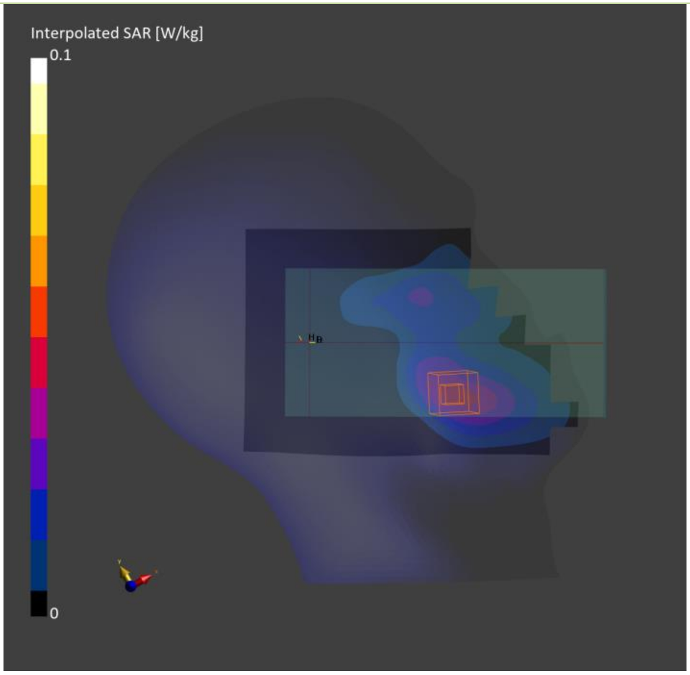
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.037	0.040
psSAR10g [W/kg]	0.021	0.025
Power Drift [dB]	0.18	0.06
M2/M1 [%]		64.8
Dist 3dB Peak [mm]		12.2



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Measurement Report

P03 WCDMA II_RMC12.2K_Left Cheek_0mm_Ch9262_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 2	WCDMA, 10011-CAC	1852.400, 9262	8.31	1.43	40.9

Hardware Setup

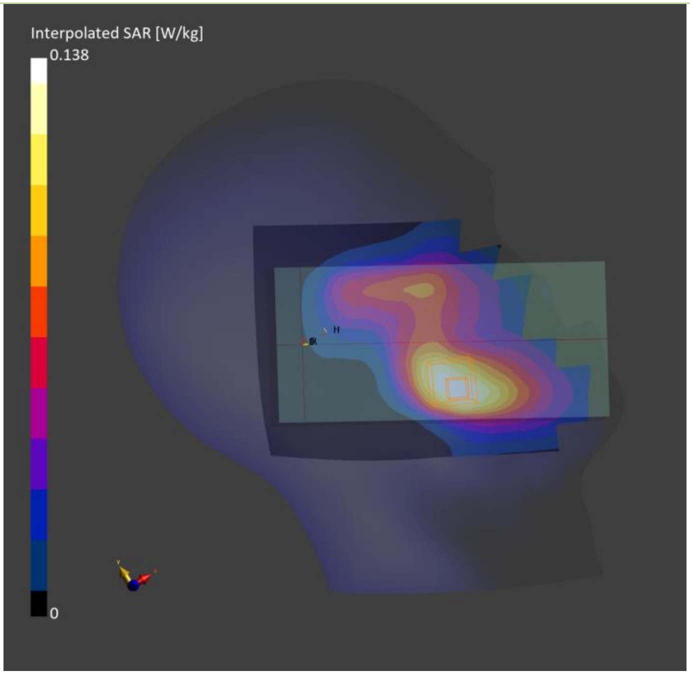
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.112	0.118
psSAR10g [W/kg]	0.067	0.074
Power Drift [dB]	0.00	0.03
M2/M1 [%]		84.8
Dist 3dB Peak [mm]		11.9



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Measurement Report

P04 WCDMA IV_RMC12.2K_Left Cheek_0mm_Ch1513_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 4	WCDMA, 10011-CAC	1752.600, 1513	8.74	1.37	41.0

Hardware Setup

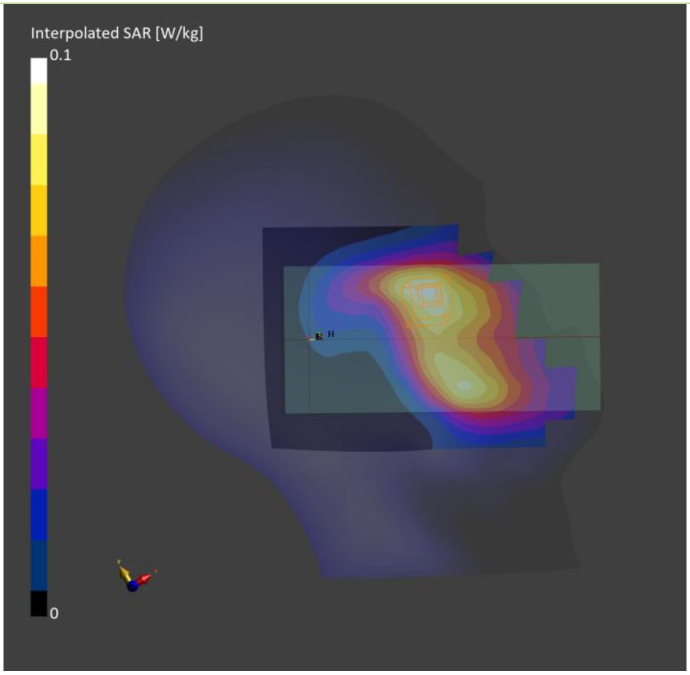
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.077	0.083
psSAR10g [W/kg]	0.048	0.057
Power Drift [dB]	-0.04	0.00
M2/M1 [%]		86.6
Dist 3dB Peak [mm]		16.2



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Measurement Report
P05 WCDMA V_RMC12.2K_Left Cheek_0mm_Ch4182_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 5	WCDMA, 10011-CAC	836.400, 4182	10.39	0.95	43.1

Hardware Setup

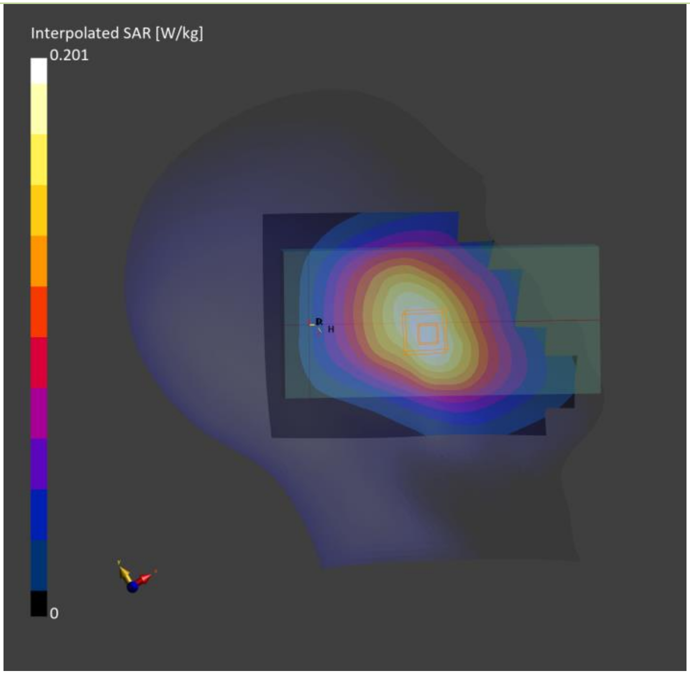
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.176	0.193
psSAR10g [W/kg]	0.121	0.147
Power Drift [dB]	0.04	0.07
M2/M1 [%]		76.2
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P06 LTE 2_QPSK20M_Left Cheek_0mm_Ch19100_1RB_OS0_Reader_4100_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 2	LTE-FDD, 10169-CAF	1900.000, 19100	8.31	1.45	40.7

Hardware Setup

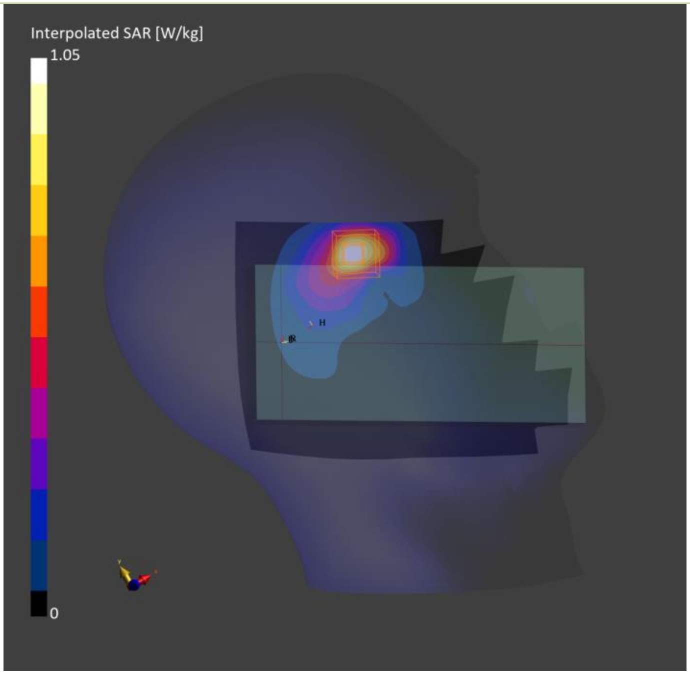
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	0.807	0.809
psSAR10g [W/kg]	0.412	0.393
Power Drift [dB]	-0.40	0.02
M2/M1 [%]		50.7
Dist 3dB Peak [mm]		8.3



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Measurement Report

P07 LTE 4_QPSK20M_Left Cheek_0mm_Ch20300_1RB_OS0_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 4	LTE-FDD, 10169-CAF	1745.000, 20300	8.74	1.35	40.9

Hardware Setup

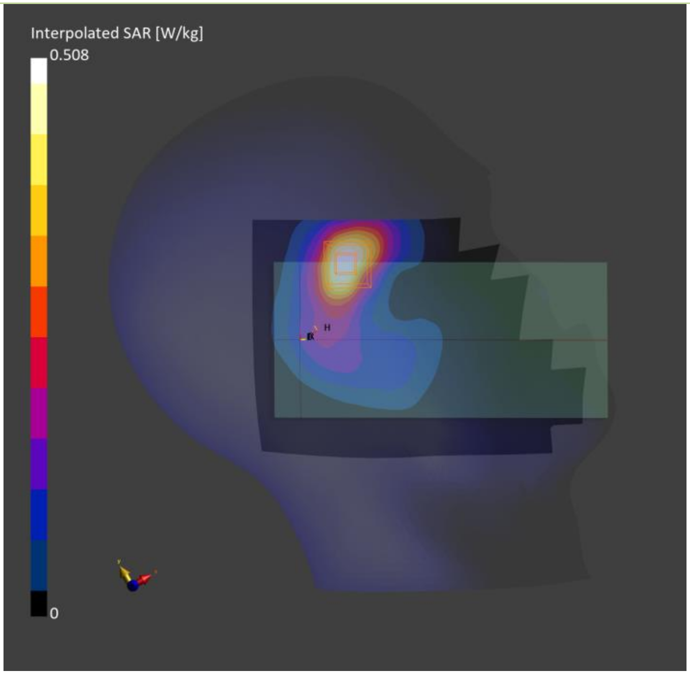
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	0.414	0.423
psSAR10g [W/kg]	0.236	0.237
Power Drift [dB]	-0.10	-0.14
M2/M1 [%]		55.3
Dist 3dB Peak [mm]		13.0



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Measurement Report

P08 LTE 5_QPSK10M_Right Cheek_Ch20525_1RB_OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band 5	LTE-FDD, 10175-CAH	836.500, 20525	10.39	0.927	42.7

Hardware Setup

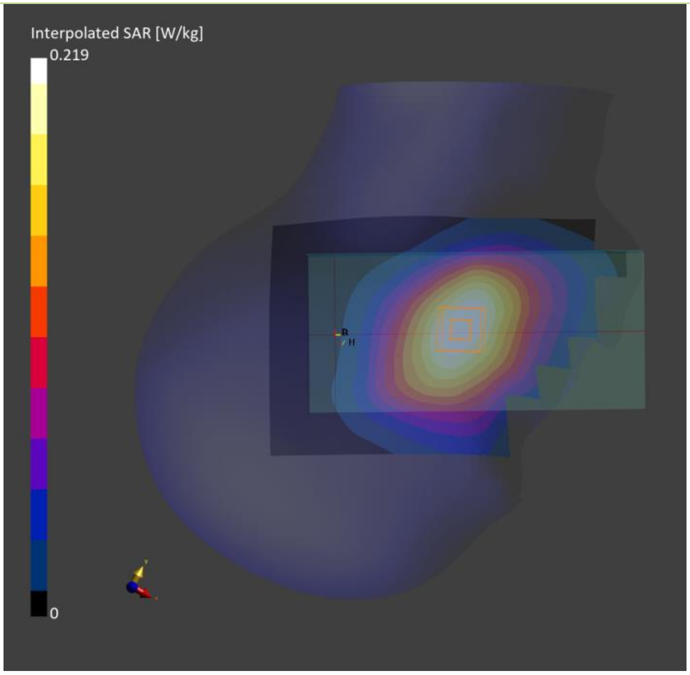
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.192	0.204
psSAR10g [W/kg]	0.133	0.158
Power Drift [dB]	-0.06	0.01
M2/M1 [%]		79.6
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P09 LTE 7_QPSK20M_Left Cheek_0mm_Ch21100_1RB_OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 7	LTE-FDD, 10169-CAF	2535.000, 21100	7.58	1.89	39.8

Hardware Setup

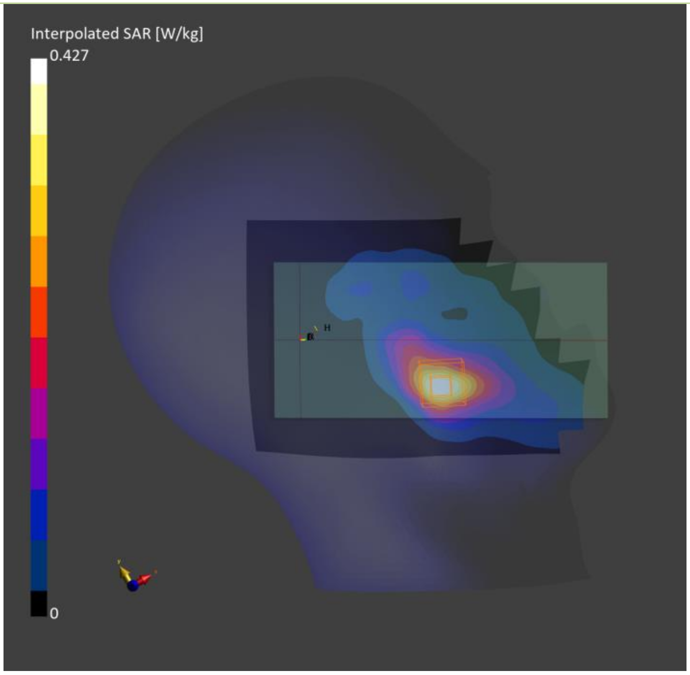
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	0.324	0.331
psSAR10g [W/kg]	0.158	0.171
Power Drift [dB]	-0.14	-0.01
M2/M1 [%]		82.6
Dist 3dB Peak [mm]		9.1



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Measurement Report

P10 LTE 12_QPSK10M_Left Tilted_Ch23095_1RB_OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 12	LTE-FDD, 10175-CAH	707.500, 23095	10.71	0.895	43.4

Hardware Setup

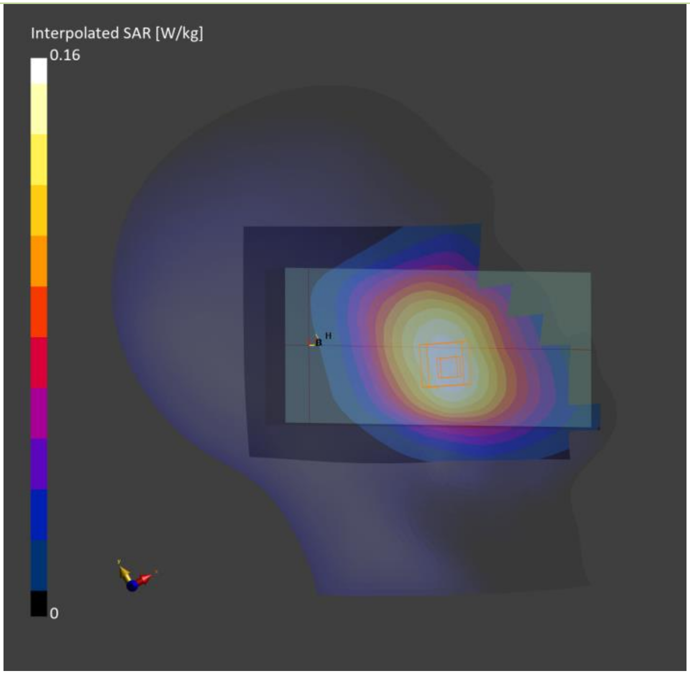
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.141	0.145
psSAR10g [W/kg]	0.098	0.115
Power Drift [dB]	-0.17	-0.06
M2/M1 [%]		80.5
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P11 LTE 13_QPSK10M_Left Tilted_Ch23230_1RB_OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 13	LTE-FDD, 10175-CAH	782.000, 23230	10.71	0.922	43.3

Hardware Setup

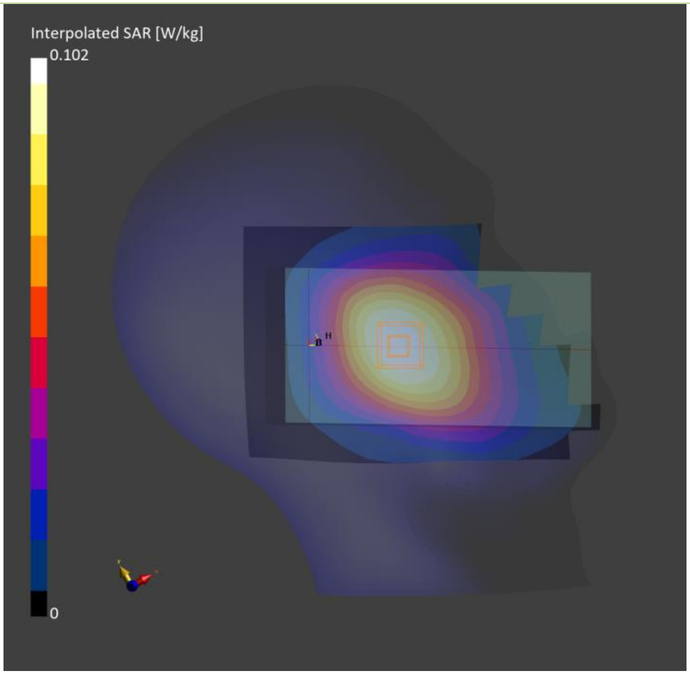
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.089	0.091
psSAR10g [W/kg]	0.063	0.072
Power Drift [dB]	-0.09	-0.05
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P12 LTE 14_QPSK10M_Left Tilted_Ch23330_1RB_OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 14	LTE-FDD, 10175-CAH	793.000, 23330	10.71	0.926	43.2

Hardware Setup

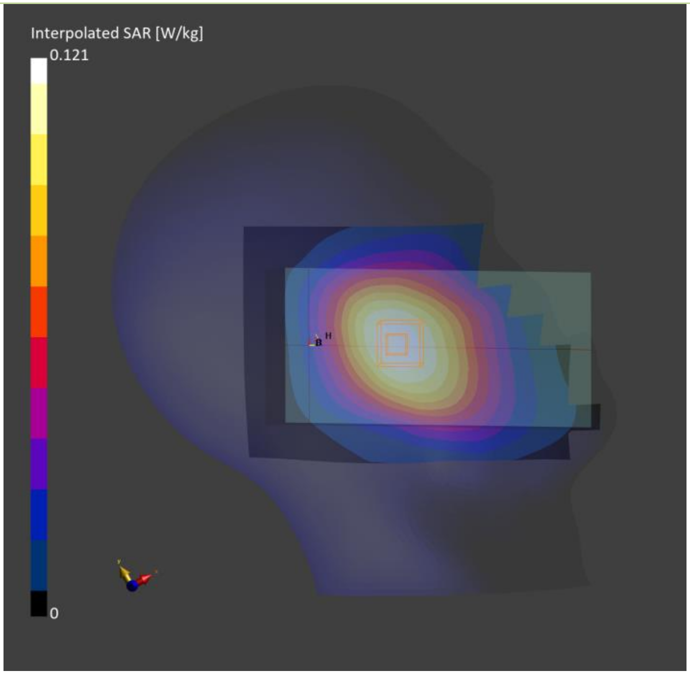
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.106	0.111
psSAR10g [W/kg]	0.074	0.087
Power Drift [dB]	0.03	-0.01
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P13 LTE 17_QPSK10M_Left Tilted_Ch23790_1RB_OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 17	LTE-FDD, 10175-CAH	710.000, 23790	10.71	0.896	43.4

Hardware Setup

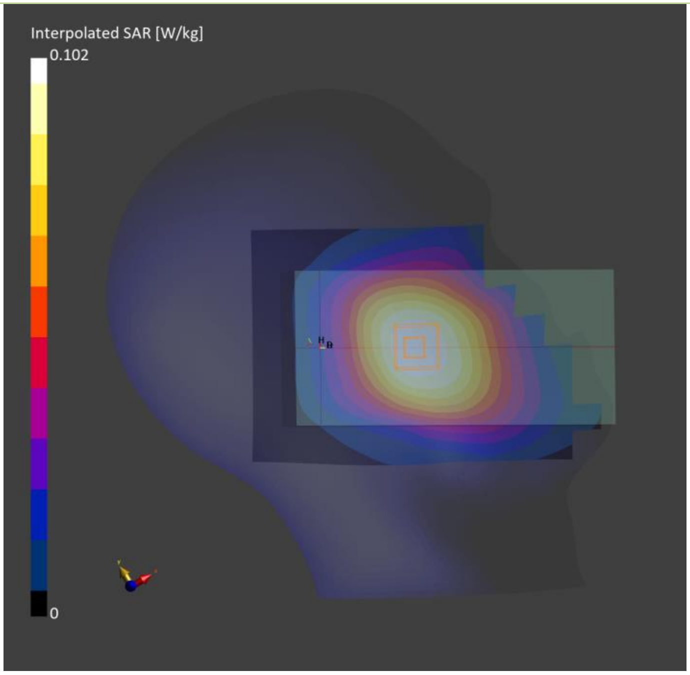
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.090	0.094
psSAR10g [W/kg]	0.064	0.077
Power Drift [dB]	0.01	-0.12
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P14 LTE 25_QPSK20M_Left Cheek_Ch26590_1RB_OS0_Reader_4100_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 25	LTE-FDD, 10169-CAF	1905.000, 26590	8.31	1.35	40.0

Hardware Setup

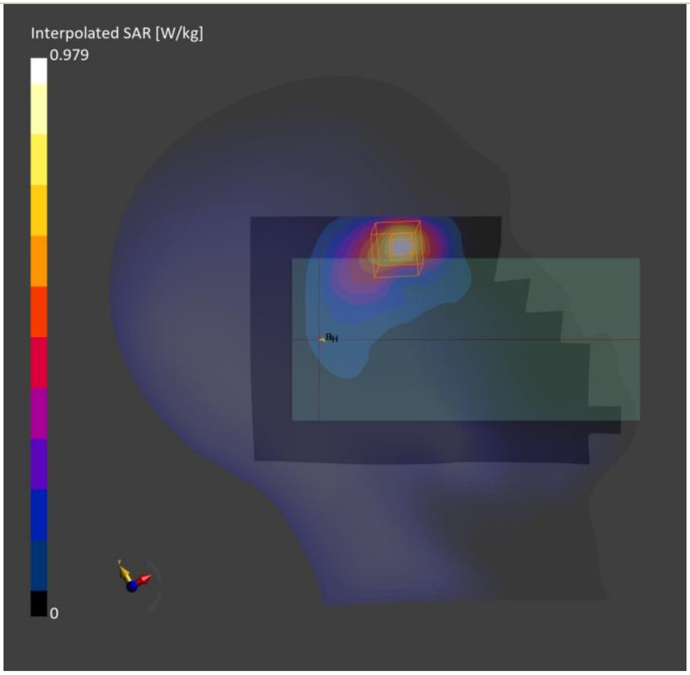
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-18	2024-05-18
psSAR1g [W/kg]	0.741	0.874
psSAR10g [W/kg]	0.382	0.417
Power Drift [dB]	-0.17	-0.18
M2/M1 [%]		48.6
Dist 3dB Peak [mm]		8.7



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Measurement Report

P15 LTE 26_QPSK15M_Left Tilted_Ch26965_1RB_OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 26	LTE-FDD, 10181-CAF	841.500, 26965	10.39	0.93	42.7

Hardware Setup

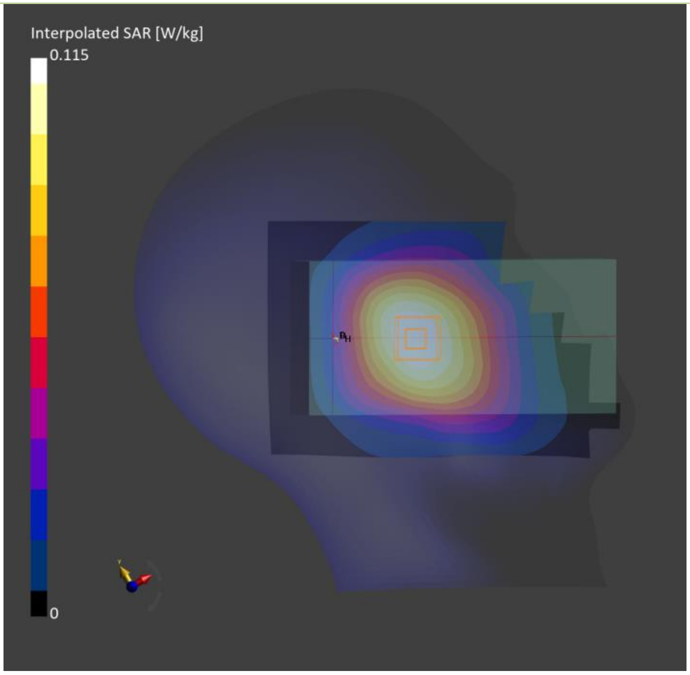
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.102	0.108
psSAR10g [W/kg]	0.071	0.085
Power Drift [dB]	-0.06	-0.01
M2/M1 [%]		78.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

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Measurement Report

P16 LTE 30_QPSK10M_Right Cheek_Ch27710_1RB_OS0_Reader_4100_Ant 5

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band 30	LTE-FDD, 10175-CAH	2310.000, 27710	8.12	1.73	39.0

Hardware Setup

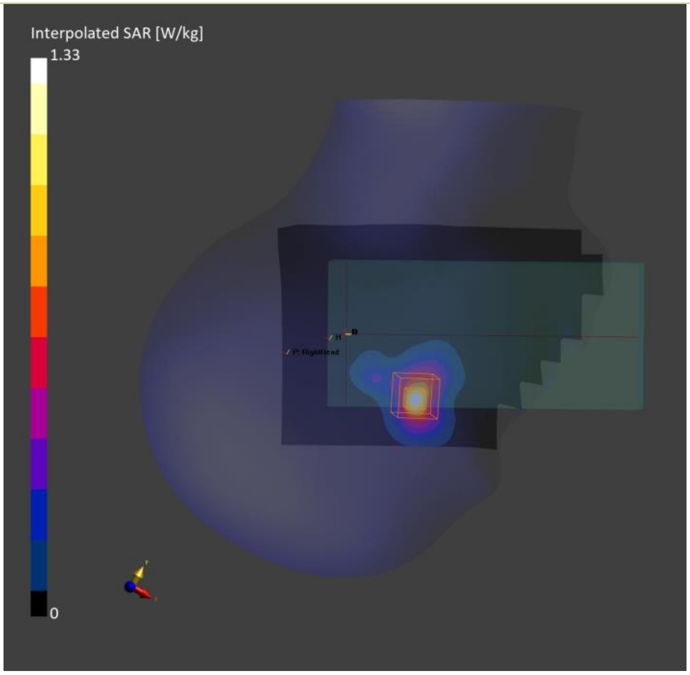
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	0.924	0.899
psSAR10g [W/kg]	0.400	0.388
Power Drift [dB]	-0.05	-0.09
M2/M1 [%]		45.4
Dist 3dB Peak [mm]		8.1



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Measurement Report

P17 LTE 38_QPSK20M_Left Cheek_0mm_Ch38150_1RB_OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 38	LTE-TDD, 10172-CAH	2610.000, 38150	7.58	1.93	37.5

Hardware Setup

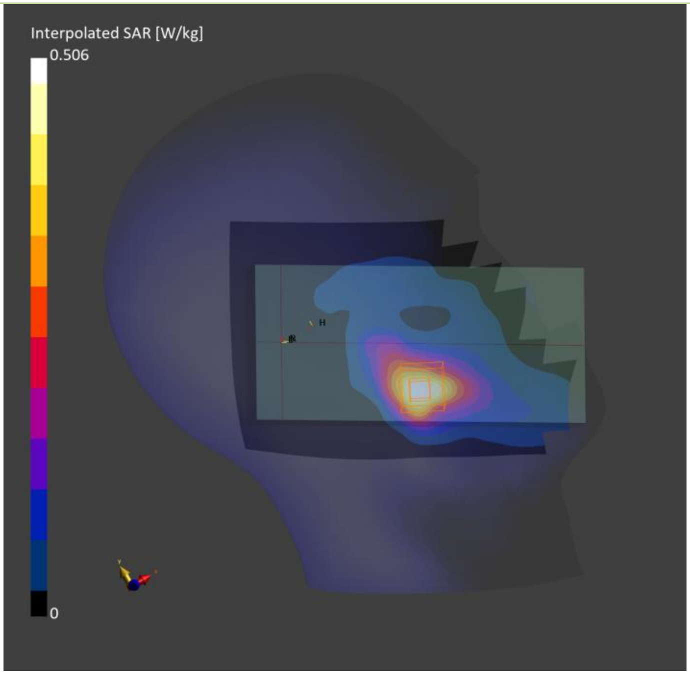
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-19	2024-04-19
psSAR1g [W/kg]	0.395	0.418
psSAR10g [W/kg]	0.196	0.220
Power Drift [dB]	0.08	0.01
M2/M1 [%]		56.5
Dist 3dB Peak [mm]		11.3



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Measurement Report

P18 LTE 41_QPSK20M_Left Cheek_Ch40185_1RB_OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 41	LTE-TDD, 10172-CAH	2549.500, 40185	7.58	1.93	40.2

Hardware Setup

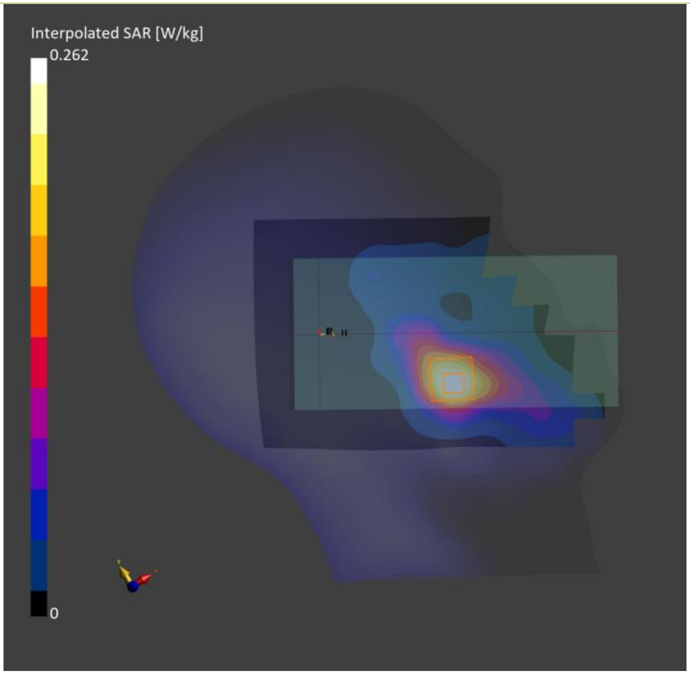
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	0.205	0.199
psSAR10g [W/kg]	0.107	0.053
Power Drift [dB]	0.08	-0.16
M2/M1 [%]		55.4
Dist 3dB Peak [mm]		5.1



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Measurement Report

P19 LTE 42_QPSK20M_Left Cheek_Ch43490_1RB_OS0_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 42	LTE-TDD, 10172-CAH	3590.000, 43490	6.65	2.87	38.4

Hardware Setup

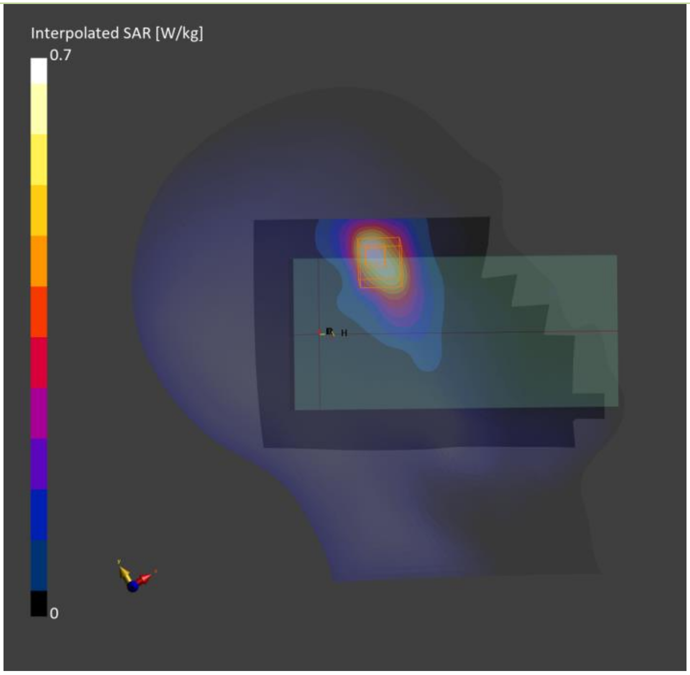
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	0.514	0.655
psSAR10g [W/kg]	0.241	0.272
Power Drift [dB]	-0.15	-0.02
M2/M1 [%]		62.5
Dist 3dB Peak [mm]		8.7



Plots of Measurement

Measurement Report
P20 LTE 43_QPSK20M_Left Cheek_Ch44240_1RB_OS0_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 43	LTE-TDD, 10172-CAH	3665.000, 44240	6.6	2.94	38.3

Hardware Setup

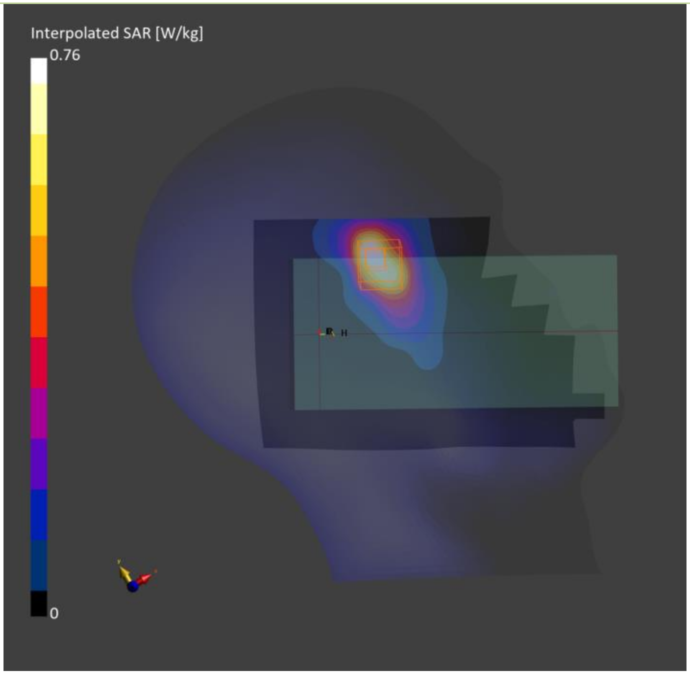
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	0.563	0.716
psSAR10g [W/kg]	0.263	0.293
Power Drift [dB]	-0.03	-0.02
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		8.1



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Measurement Report

P21 LTE 48_QPSK20M_Left Cheek_Ch55340_1RB_OS0_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 48	LTE-TDD, 10172-CAH	3560.000, 55340	6.65	2.85	38.8

Hardware Setup

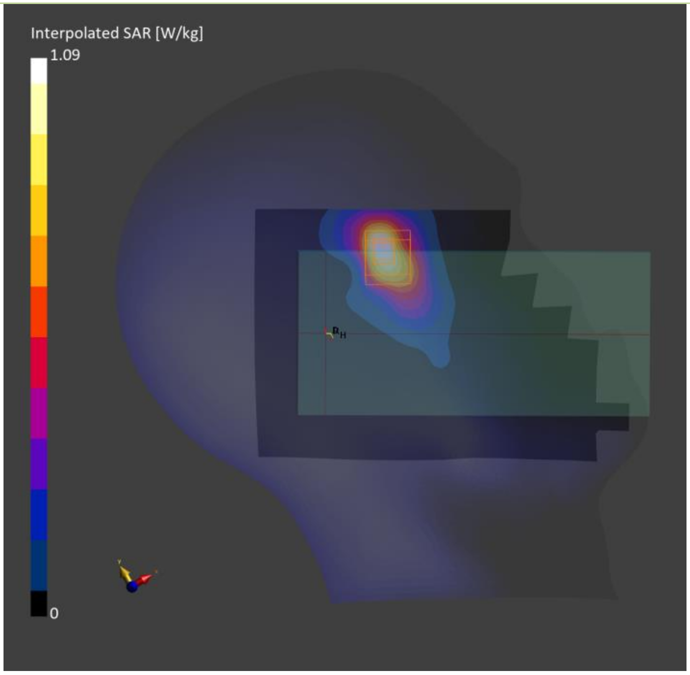
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	0.799	0.956
psSAR10g [W/kg]	0.361	0.401
Power Drift [dB]	0.01	-0.13
M2/M1 [%]		64.1
Dist 3dB Peak [mm]		8.4



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Measurement Report

P22 LTE 66_QPSK20M_Left Cheek_Ch132572_1RB_OS0_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	9.0	1.38	39.8

Hardware Setup

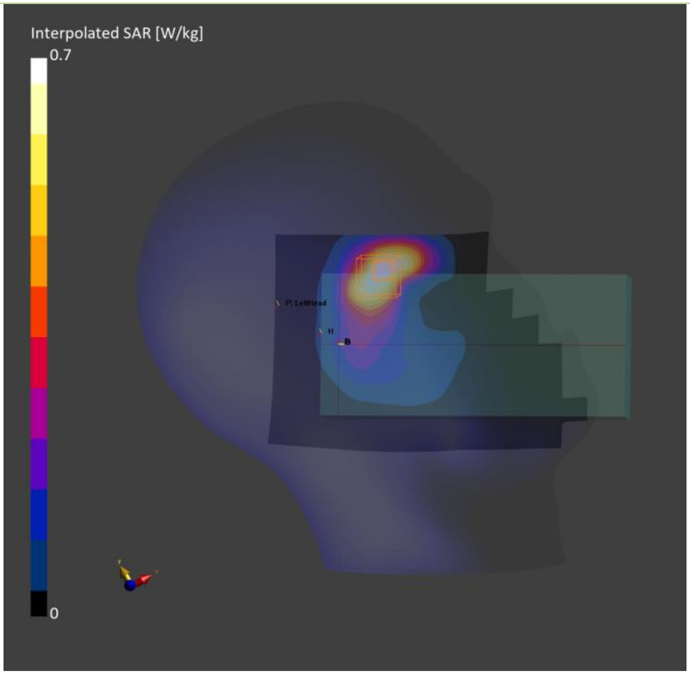
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	0.567	0.620
psSAR10g [W/kg]	0.327	0.349
Power Drift [dB]	-0.09	-0.11
M2/M1 [%]		57.9
Dist 3dB Peak [mm]		12.6



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Measurement Report

P23 LTE 71_QPSK10M_Right Cheek_Ch133297_1RB_OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band 71	LTE-FDD, 10169-CAF	680.500, 133297	10.71	0.885	43.5

Hardware Setup

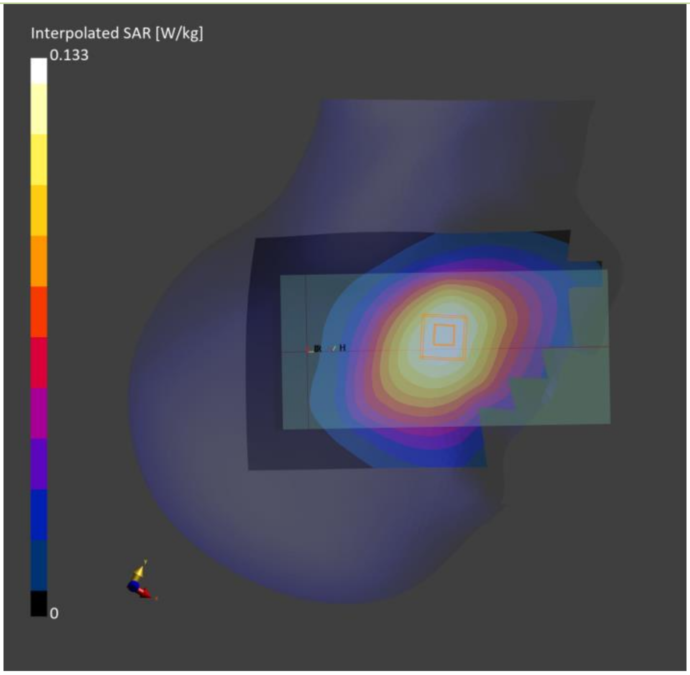
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.117	0.123
psSAR10g [W/kg]	0.082	0.096
Power Drift [dB]	0.02	-0.06
M2/M1 [%]		79.6
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P24 5GNR-n2_DFT-s QPSK20M_Left Cheek_Ch380000_1RB_OS1_Reader_4100_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n2	5G NR FR1 FDD, 10931-AAC	1900.000, 380000	8.37	1.45	39.6

Hardware Setup

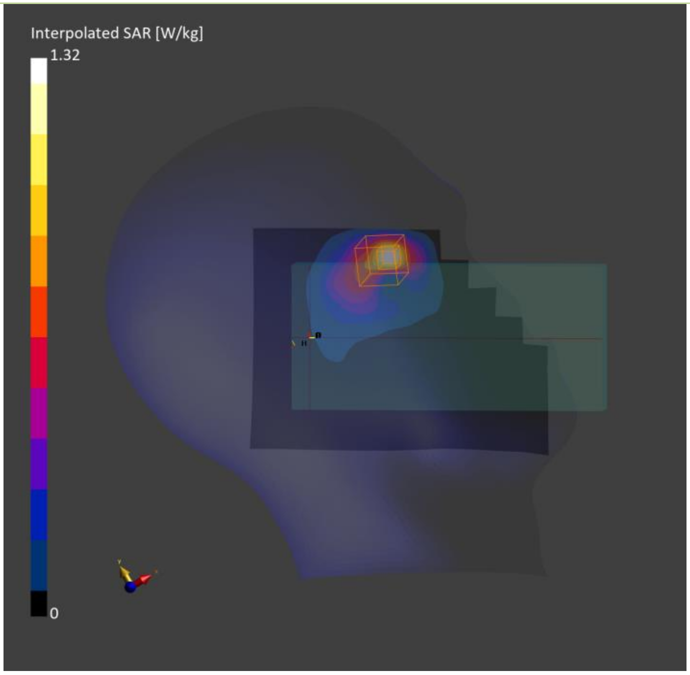
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	0.938	1.01
psSAR10g [W/kg]	0.452	0.496
Power Drift [dB]	-0.15	-0.05
M2/M1 [%]		59.3
Dist 3dB Peak [mm]		8.4



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Measurement Report

P25 5GNR-n5_DFT-s QPSK20M_Left Cheek_Ch166800_1RB_OS1_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n5	5G NR FR1 FDD, 10931-AAC	834.000, 166800	10.39	0.926	42.7

Hardware Setup

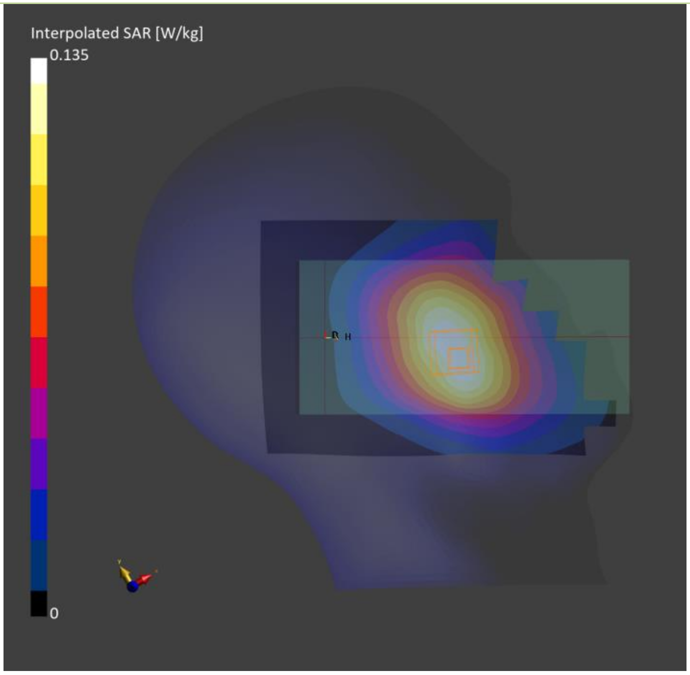
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.118	0.127
psSAR10g [W/kg]	0.081	0.098
Power Drift [dB]	-0.01	0.01
M2/M1 [%]		77.8
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P26 5GNR-n7_DFT-s QPSK20M_Left Cheek_Ch512000_1RB_OS1_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n7	5G NR FR1 FDD, 10931-AAC	2560.000, 512000	7.58	1.94	40.2

Hardware Setup

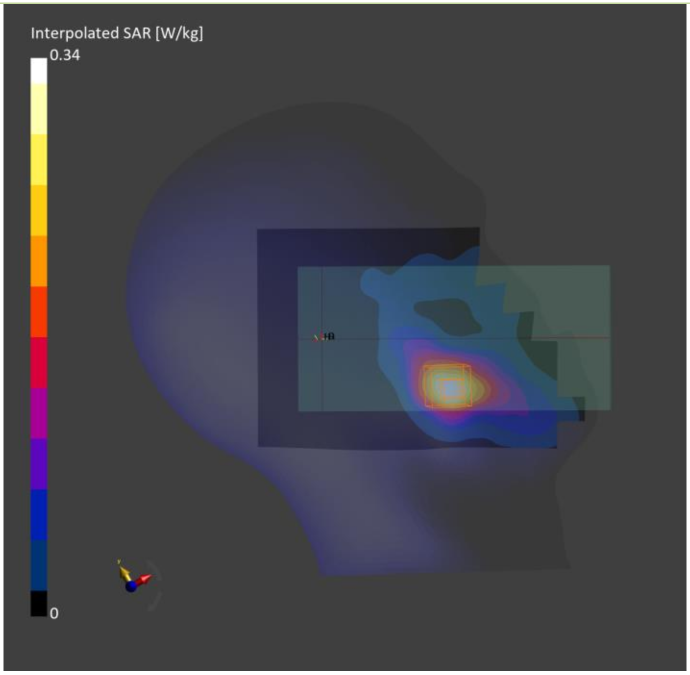
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	0.263	0.287
psSAR10g [W/kg]	0.133	0.154
Power Drift [dB]	0.09	0.01
M2/M1 [%]		56.8
Dist 3dB Peak [mm]		10.9



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Measurement Report

P27 5GNR-n12_DFT-s QPSK15M_Right Cheek_Ch141700_1RB_OS1_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n12	5G NR FR1 FDD, 10930-AAC	708.500, 141700	10.35	0.877	40.2

Hardware Setup

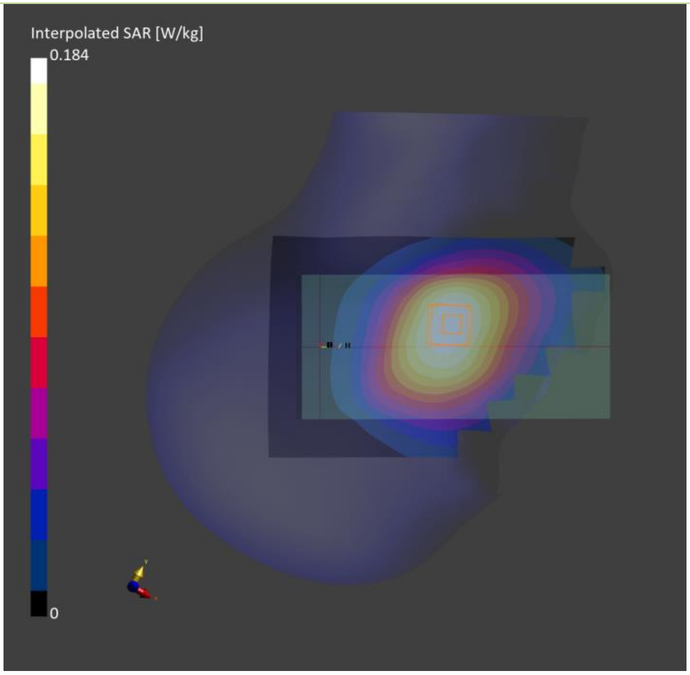
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.162	0.166
psSAR10g [W/kg]	0.114	0.133
Power Drift [dB]	-0.01	-0.05
M2/M1 [%]		81.9
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P28 5GNR-n14_DFT-s QPSK10M_Right Cheek_Ch158600_1RB_OS1_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n14	5G NR FR1 FDD, 10929-AAD	793.000, 158600	10.35	0.905	40.2

Hardware Setup

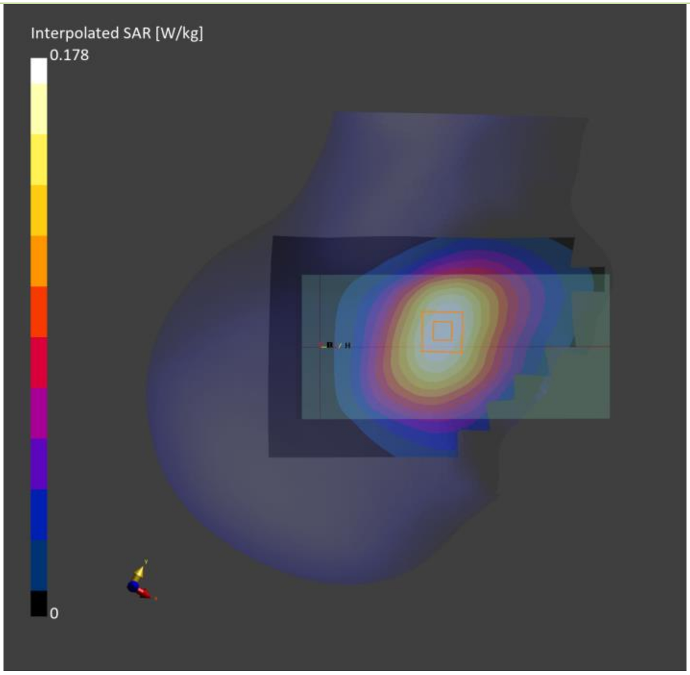
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.157	0.166
psSAR10g [W/kg]	0.110	0.131
Power Drift [dB]	0.07	-0.01
M2/M1 [%]		81.9
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P29 5GNR-n25_DFT-s QPSK20M_Left Cheek_Ch381000_1RB_OS1_Reader_4100_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n25	5G NR FR1 FDD, 10931-AAC	1905.000, 381000	8.37	1.45	39.6

Hardware Setup

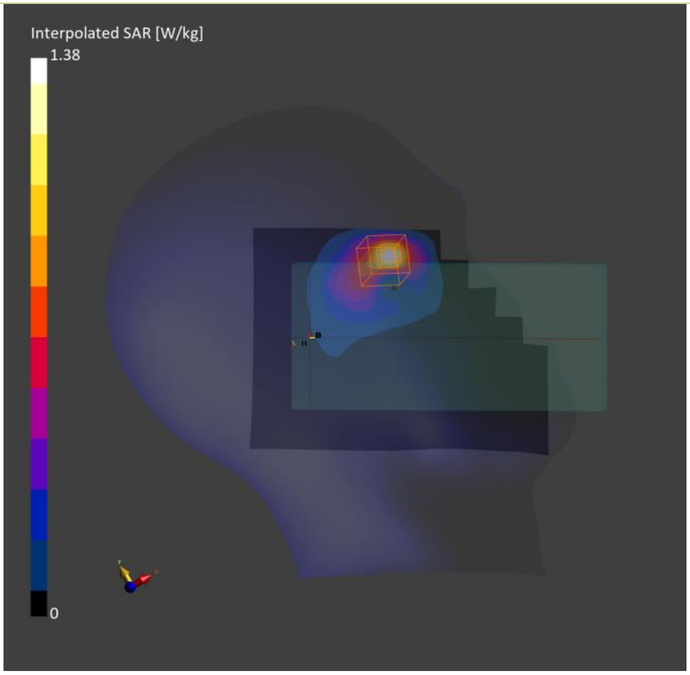
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	0.975	1.04
psSAR10g [W/kg]	0.465	0.506
Power Drift [dB]	-0.03	0.01
M2/M1 [%]		58.8
Dist 3dB Peak [mm]		8.4



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Measurement Report

P30 5GNR-n26_DFT-s QPSK20M_Right Cheek_Ch167800_1RB_OS1_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n26	5G NR FR1 FDD, 10931-AAC	839.000, 167800	10.39	0.928	42.7

Hardware Setup

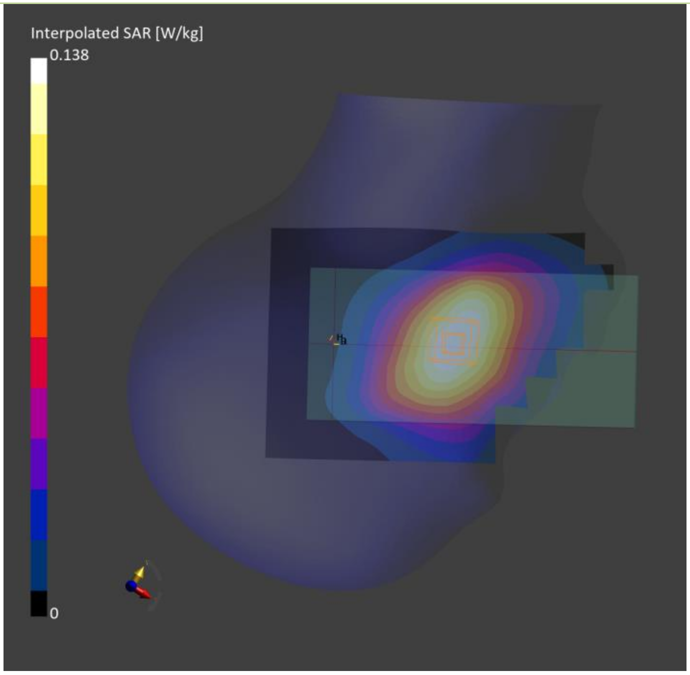
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.121	0.133
psSAR10g [W/kg]	0.084	0.104
Power Drift [dB]	0.13	-0.06
M2/M1 [%]		80.0
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P31 5GNR-n38_DFT-s QPSK40M_Right Cheek_Ch520000_1RB_OS1_Reader_4770_Ant 5

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n38	5G NR FR1 TDD, 10903-AAD	2600.000, 520000	7.58	1.93	40.2

Hardware Setup

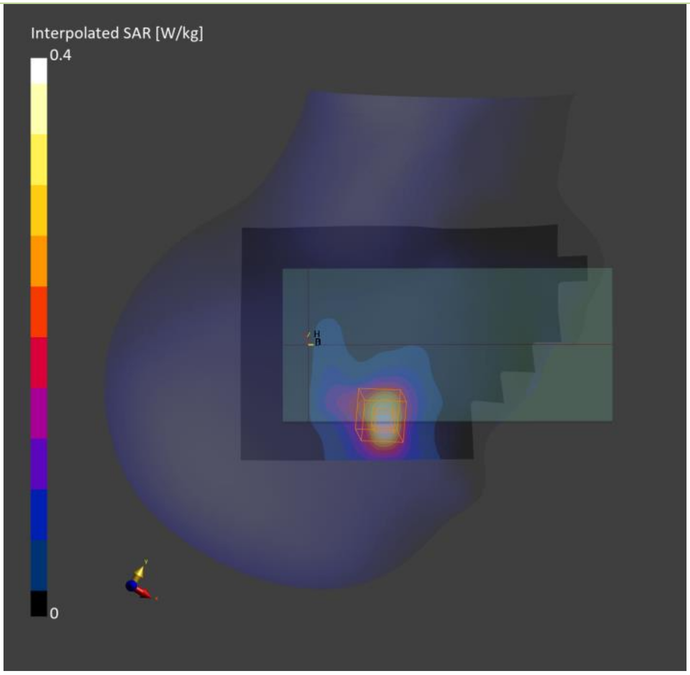
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.302	0.382
psSAR10g [W/kg]	0.147	0.169
Power Drift [dB]	0.05	-0.01
M2/M1 [%]		47.2
Dist 3dB Peak [mm]		8.1



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Measurement Report

P32 5GNR-n41_HPUE_DFT-s QPSK1000M_Right Cheek_Ch523302_1RB_OS1_Reader_4770_Ant 5

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n41	5G NR FR1 TDD, 10866-AAF	2616.510, 523302	7.58	1.94	40.1

Hardware Setup

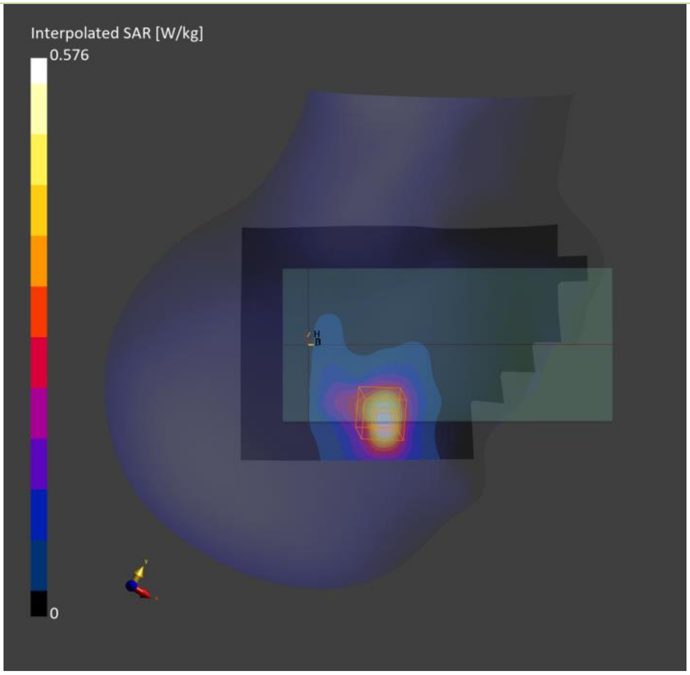
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.437	0.556
psSAR10g [W/kg]	0.214	0.251
Power Drift [dB]	0.01	-0.01
M2/M1 [%]		47.7
Dist 3dB Peak [mm]		8.6



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Measurement Report

P33 5GNR-n48_DFT-s QPSK40M_Left Cheek_Ch642888_1RB_OS1_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n48	5G NR FR1 TDD, 10903-AAD	3643.32, 642888	6.6	2.93	38.6

Hardware Setup

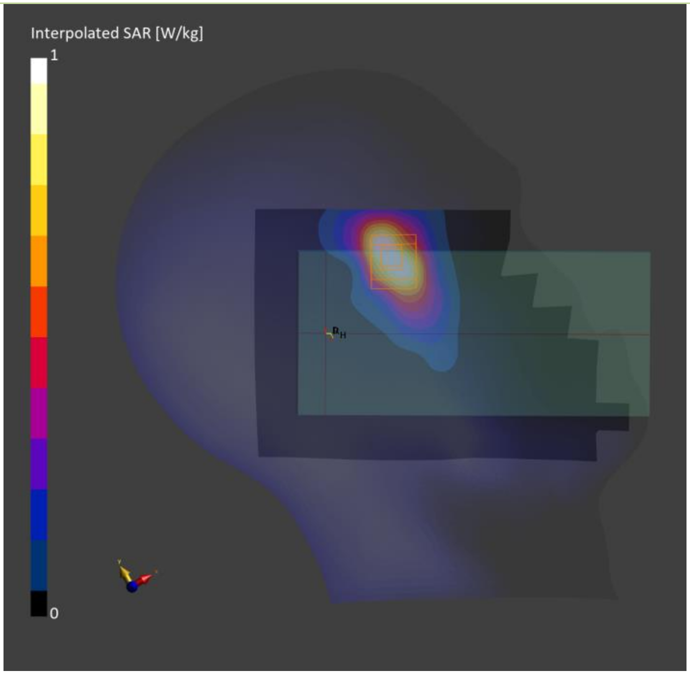
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	0.752	0.995
psSAR10g [W/kg]	0.356	0.415
Power Drift [dB]	0.06	0.03
M2/M1 [%]		63.5
Dist 3dB Peak [mm]		8.2



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Measurement Report

P34 5GNR-n66_DFT-s QPSK20M_Left Cheek_Ch349000_1RB_OS104_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n66	5G NR FR1 FDD, 10931-AAC	1745.000, 349000	8.74	1.37	37.9

Hardware Setup

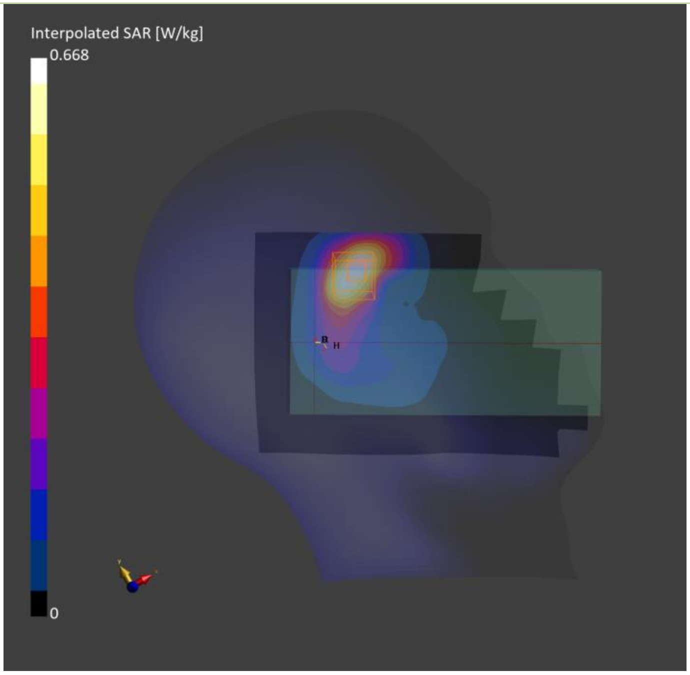
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-14	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-14	2024-05-14
psSAR1g [W/kg]	0.542	0.582
psSAR10g [W/kg]	0.315	0.335
Power Drift [dB]	-0.10	-0.07
M2/M1 [%]		56.7
Dist 3dB Peak [mm]		12.6



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Measurement Report

P35 5GNR-n71_DFT-s QPSK20M_Right Cheek_Ch136100_1RB_OS1_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n71	5G NR FR1 FDD, 10931-AAC	680.500, 136100	10.35	0.867	40.4

Hardware Setup

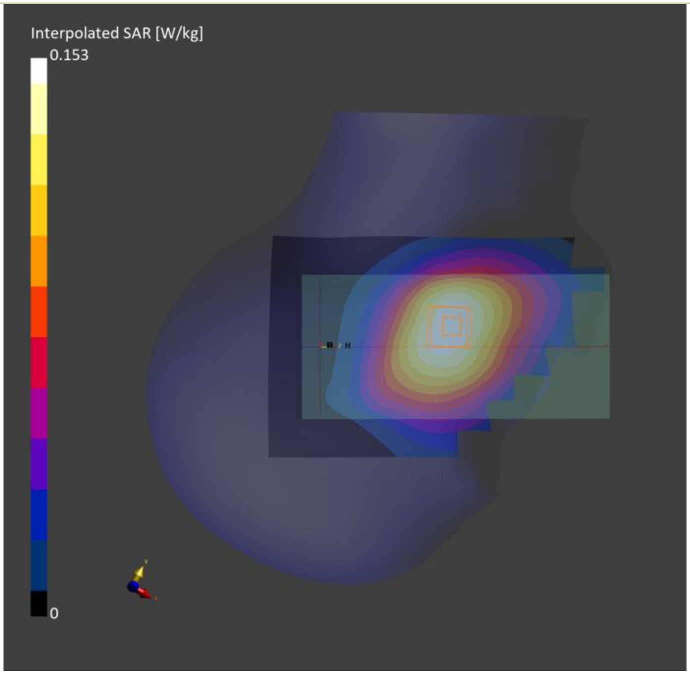
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.135	0.138
psSAR10g [W/kg]	0.096	0.110
Power Drift [dB]	0.03	-0.13
M2/M1 [%]		77.0
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P36 5GNR-n77_HPUE_DFT-s QPSK100M_Left Cheek_Ch633332_1RB_OS1_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n77	5G NR FR1 TDD, 10866-AAF	3499.980, 633332	6.65	2.83	39.2

Hardware Setup

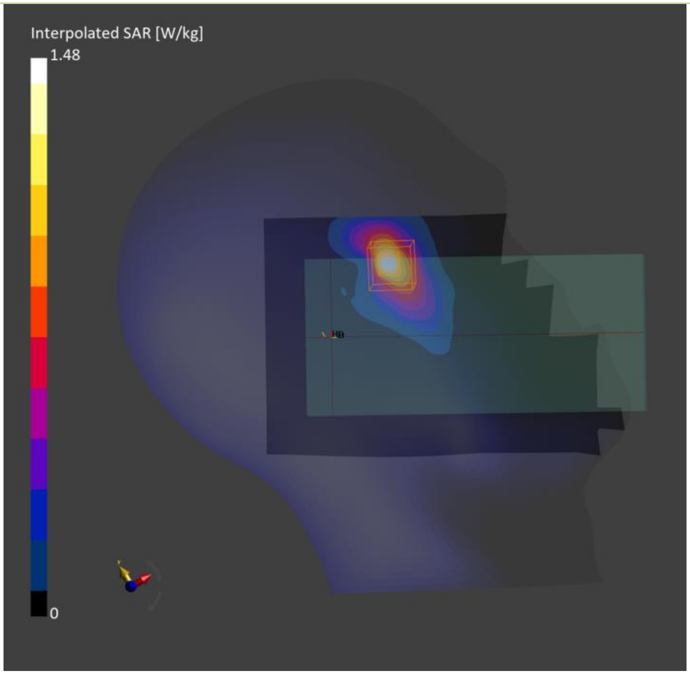
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	1.03	1.12
psSAR10g [W/kg]	0.428	0.470
Power Drift [dB]	0.03	-0.05
M2/M1 [%]		64.3
Dist 3dB Peak [mm]		7.3



Measurement Report

P38 5GNR-n78_DFT-s QPSK100M_Left Cheek_Ch633332_1RB_OS1_Reader_4770_Ant 7+5

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n78	5G NR FR1 TDD, 10866-AAF	3499.980, 633332	6.65	2.79	39.6

Hardware Setup

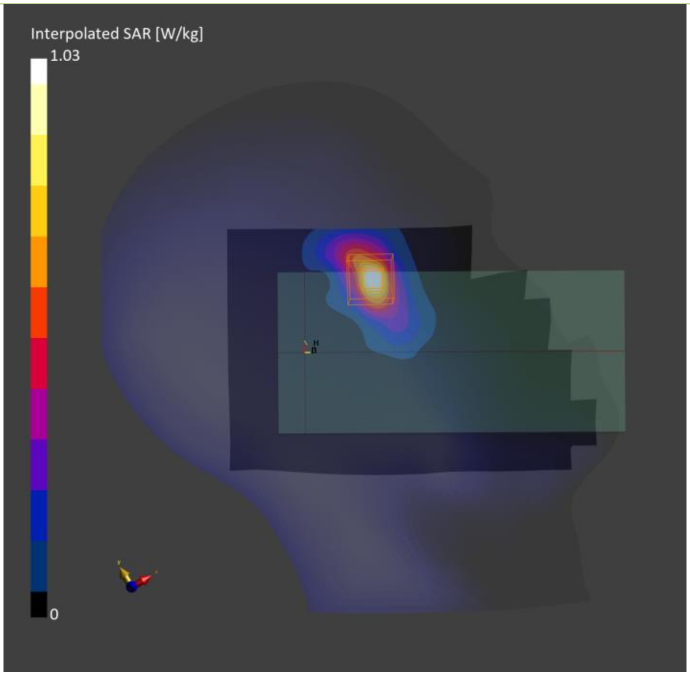
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-10	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-10	2024-05-10
psSAR1g [W/kg]	0.712	0.764
psSAR10g [W/kg]	0.284	0.309
Power Drift [dB]	0.18	0.03
M2/M1 [%]		64.0
Dist 3dB Peak [mm]		7.7



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Measurement Report
P40 WLAN 2.4G_802.11b_Left Cheek_Ch6_Reader_4770_Ant 2
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 2.4GHz	WLAN, 10012-CAB	2437.000, 6	7.65	1.82	39.8

Hardware Setup

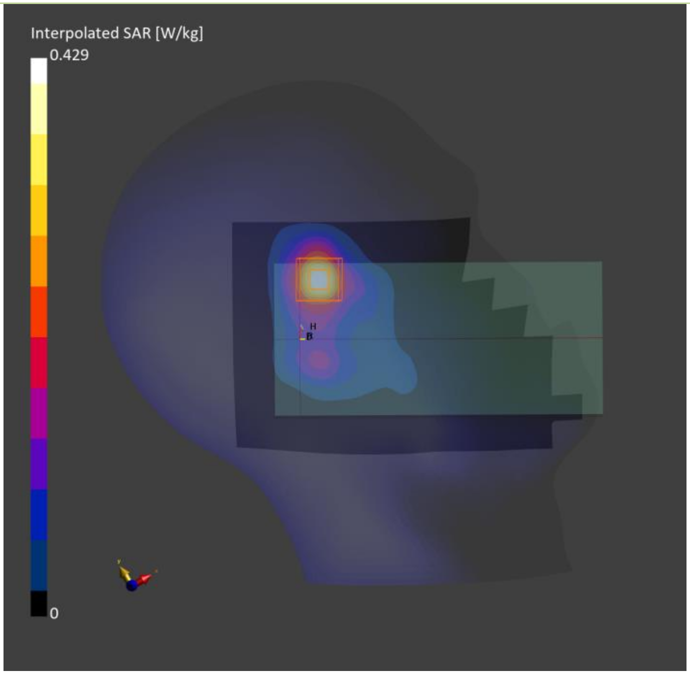
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	0.321	0.333
psSAR10g [W/kg]	0.153	0.159
Power Drift [dB]	-0.01	-0.03
M2/M1 [%]		43.9
Dist 3dB Peak [mm]		9.9



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Measurement Report

P41 WLAN 5.3G_802.11ac VHT40_Left Cheek_Ch54_Reader_4770_Ant 2

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 5GHz	WLAN, 10534-AAD	5270.000, 54	5.52	4.66	37.2

Hardware Setup

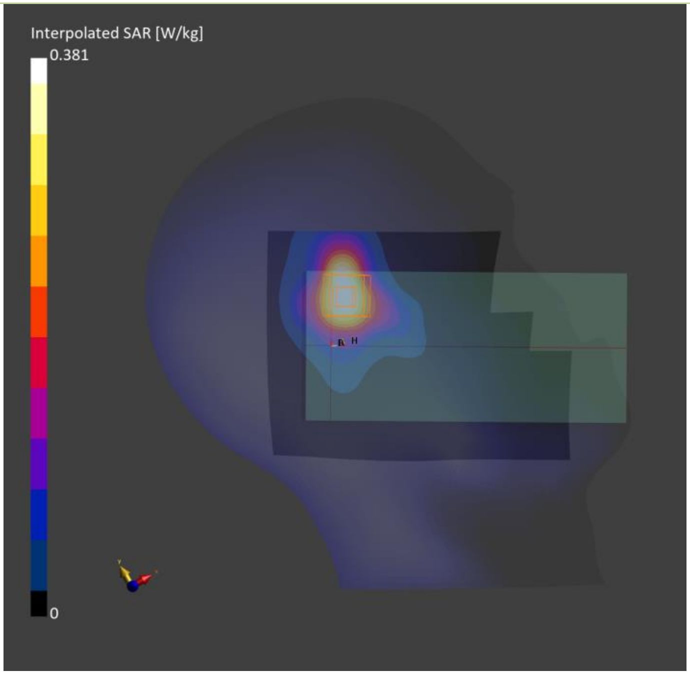
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	0.286	0.346
psSAR10g [W/kg]	0.121	0.128
Power Drift [dB]	0.17	-0.01
M2/M1 [%]		67.8
Dist 3dB Peak [mm]		8.6



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Measurement Report

P42 WLAN 5.6G_802.11ac VHT40_Left Cheek_Ch110_Reader_4770_Ant 2

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 5GHz	WLAN, 10534-AAD	5550.000, 110	4.8	4.90	35.3

Hardware Setup

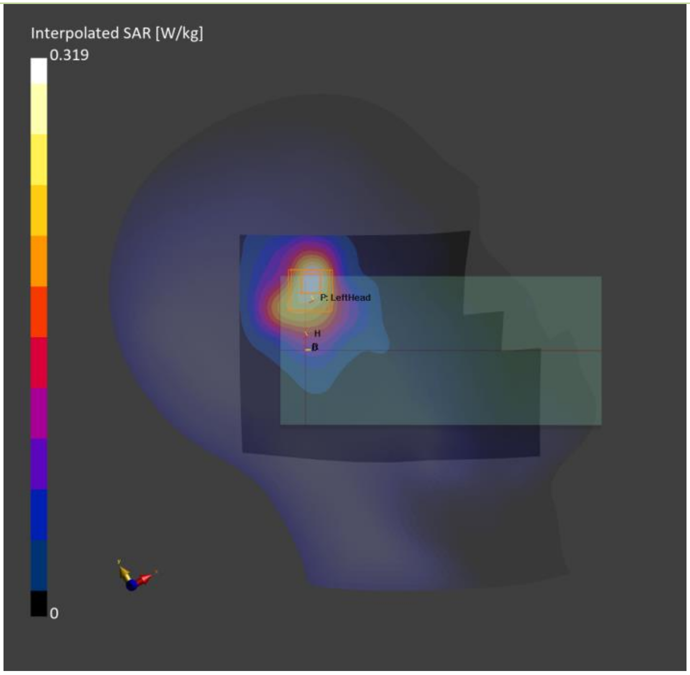
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	0.229	0.356
psSAR10g [W/kg]	0.098	0.126
Power Drift [dB]	0.17	-0.11
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		8.0



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Measurement Report

P43 WLAN 5.8G_802.11ac VHT40_Left Cheek_Ch159_Reader_4770_Ant 2

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 5GHz	WLAN, 10534-AAD	5795.000, 159	4.96	5.19	34.9

Hardware Setup

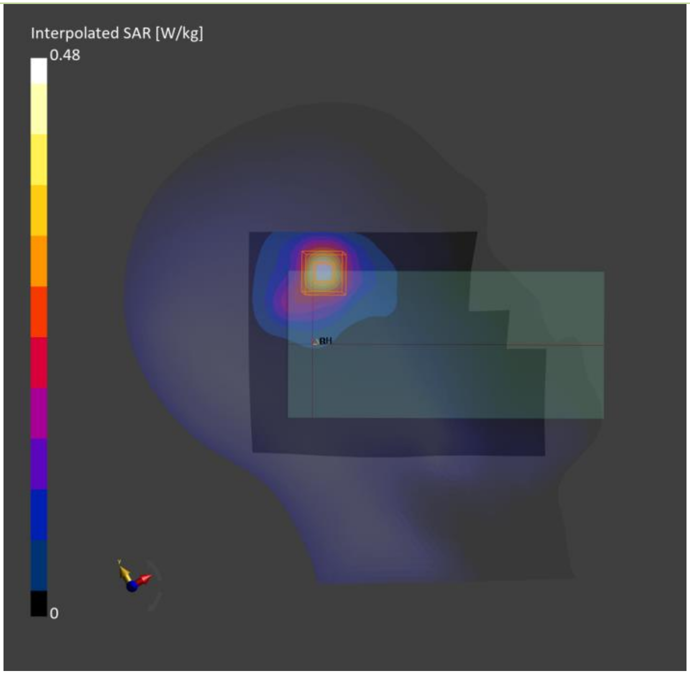
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	0.329	0.364
psSAR10g [W/kg]	0.127	0.134
Power Drift [dB]	0.12	-0.11
M2/M1 [%]		59.8
Dist 3dB Peak [mm]		6.6



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Measurement Report

P44 BT_BDR_Left Cheek_Ch0_Reader_4770_Ant 2

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2402.000, 0	7.65	1.79	39.8

Hardware Setup

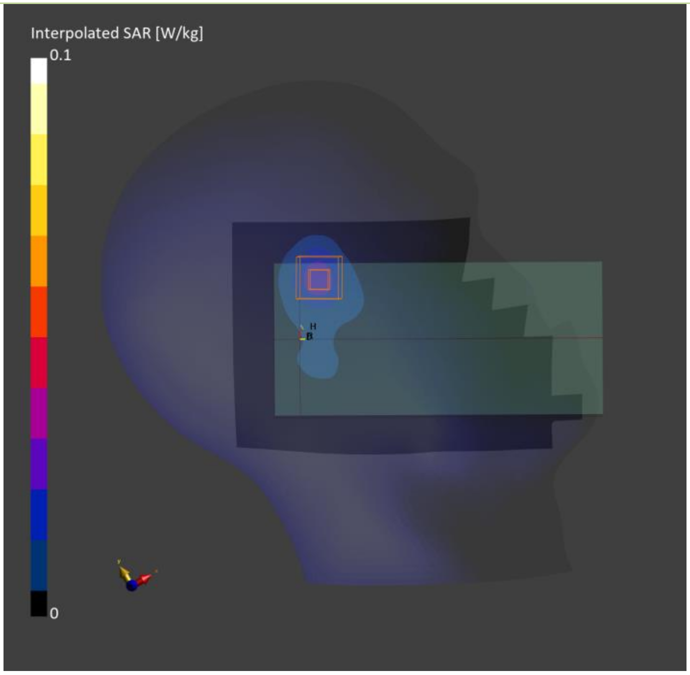
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	0.025	0.026
psSAR10g [W/kg]	0.012	0.012
Power Drift [dB]	0.17	-0.18
M2/M1 [%]		43.8
Dist 3dB Peak [mm]		10.0



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Measurement Report
P137 UNII-5_802.11ax HE160_Right Tilted_Ch79_Reader_4770_Ant 2

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Tilted, 0.00	U-NII-5	WLAN, 10755-AAC	6345.000, 79	5.4	5.77	35.4

Hardware Setup

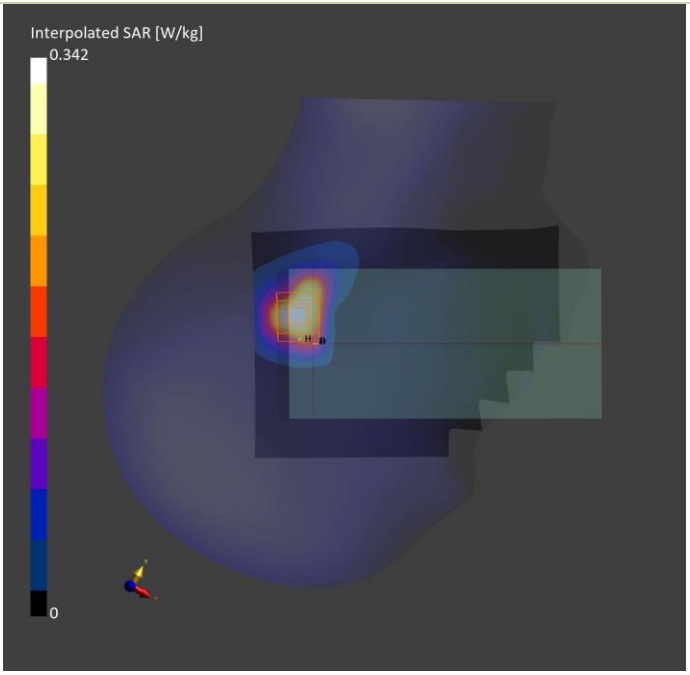
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-29	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 180.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-29	2024-04-29
psSAR1g [W/kg]	0.265	0.324
psSAR10g [W/kg]	0.105	0.107
Power Drift [dB]	-0.18	-0.13
M2/M1 [%]		57.9
Dist 3dB Peak [mm]		8.8



Measurement Report

P137 PD UNII-5_802.11ax HE160_Right Tilted_Ch79_Reader_4770_Ant 2

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
, P23100614	165.0 x 80.0 x 19.0		Phone

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	Right Tilted, 2.00	U-NII-5	WLAN, 10755-AAC	6345.0, 79	1.0

Hardware Setup

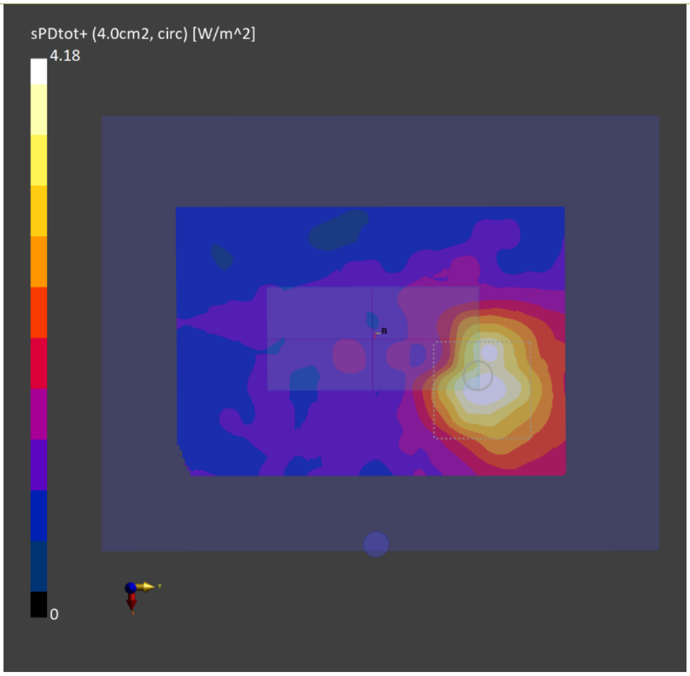
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	---Air	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan
Grid Extents [mm]	95.0 x 95.0
Grid Steps [lambda]	0.0529 x 0.0529
Sensor Surface [mm]	2.0
MAIA	Y

Measurement Results

	5G Scan
Date	2024-05-15
Avg. Area [cm^2]	4.00
psPDn+ [W/m^2]	2.60
psPDtot+ [W/m^2]	4.18
psPDmod+ [W/m^2]	5.6
E$_{max}$ [V/m]	40.2
Power Drift [dB]	0.04



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Measurement Report

P45 GSM850_GPRS 4Tx Slot_Rear Face_10mm_Ch128_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	GSM 850	GSM, 10028-DAC	824.200, 128	10.39	0.88	43.3

Hardware Setup

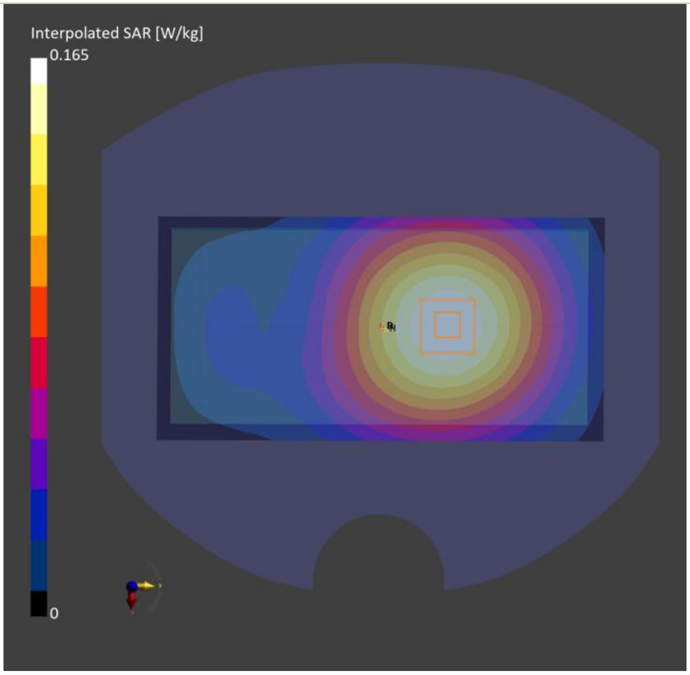
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	0.145	0.153
psSAR10g [W/kg]	0.102	0.114
Power Drift [dB]	0.01	-0.08
M2/M1 [%]		75.1
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P46 GSM1900_GPRS 4Tx Slot_Rear Face_10mm_Ch512_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	PCS 1900	GSM, 10028-DAC	1850.200, 512	8.31	1.38	41.5

Hardware Setup

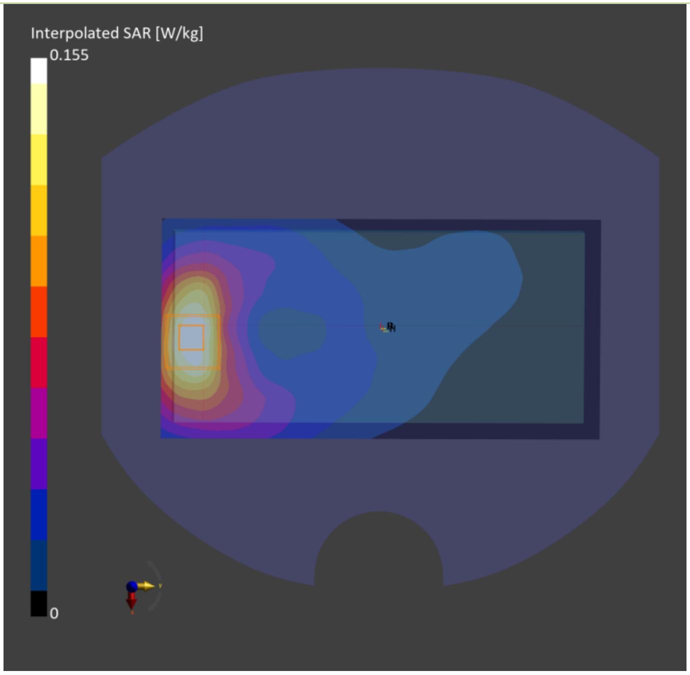
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	0.128	0.121
psSAR10g [W/kg]	0.075	0.072
Power Drift [dB]	0.04	-0.09
M2/M1 [%]		60.0
Dist 3dB Peak [mm]		14.4



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Measurement Report

P47 WCDMAII_RMC12.2K_Rear Face_10mm_Ch9262_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 2	WCDMA, 10011-CAC	1852.400, 9262	8.31	1.39	41.2

Hardware Setup

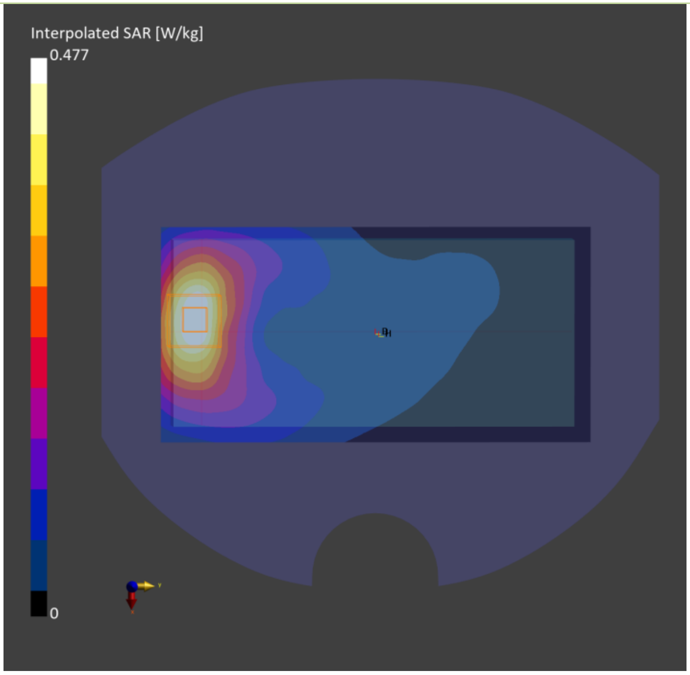
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.400	0.409
psSAR10g [W/kg]	0.235	0.249
Power Drift [dB]	0.05	0.01
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		14.5



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Measurement Report

P48 WCDMA IV_RMC12.2K_Rear Face_10mm_Ch1513_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 4	WCDMA, 10011-CAC	1752.600, 1513	8.74	1.34	41.3

Hardware Setup

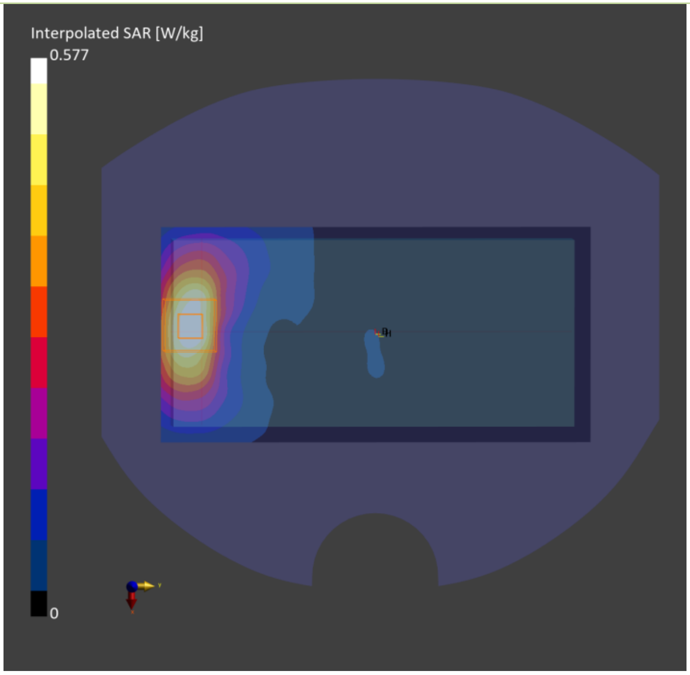
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.480	0.499
psSAR10g [W/kg]	0.277	0.301
Power Drift [dB]	0.03	0.01
M2/M1 [%]		63.4
Dist 3dB Peak [mm]		12.8



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Measurement Report
P49 WCDMA V_RMC12.2K_Rear Face_10mm_Ch4132_Reader_4100_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 5	WCDMA, 10011-CAC	826.400, 4132	10.39	0.93	43.1

Hardware Setup

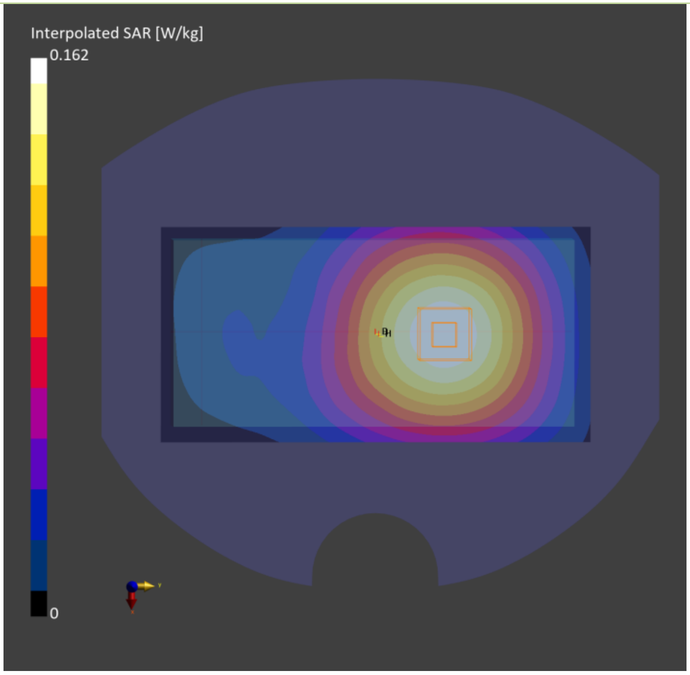
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.143	0.154
psSAR10g [W/kg]	0.100	0.116
Power Drift [dB]	0.09	-0.01
M2/M1 [%]		72.8
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P50 LTE 2_QPSK20M_Rear Face_10mm_Ch18700_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 2	LTE-FDD, 10169-CAF	1860.000, 18700	8.31	1.43	38.2

Hardware Setup

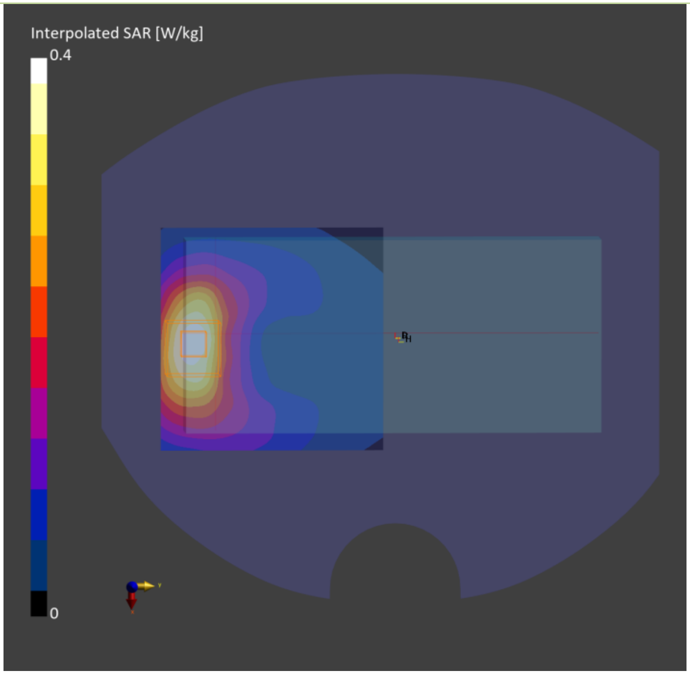
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	0.330	0.341
psSAR10g [W/kg]	0.191	0.204
Power Drift [dB]	0.05	0.01
M2/M1 [%]		62.0
Dist 3dB Peak [mm]		14.4



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Measurement Report

P51 LTE 4_QPSK20M_Rear Face_10mm_Ch20300_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 4	LTE-FDD, 10169-CAF	1745.000, 20300	8.74	1.37	38.4

Hardware Setup

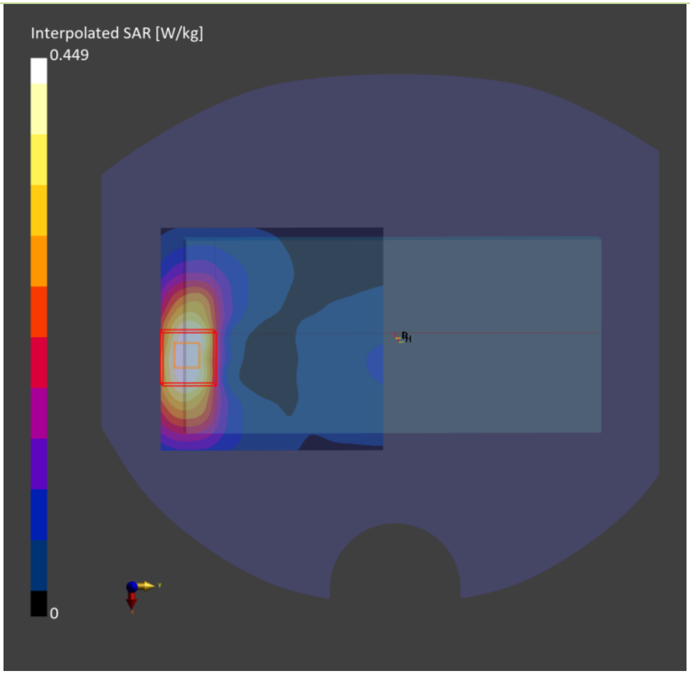
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	0.380	0.397
psSAR10g [W/kg]	0.217	0.233
Power Drift [dB]	0.04	0.02
M2/M1 [%]		61.8
Dist 3dB Peak [mm]		12.8



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Measurement Report

P52 LTE 5_QPSK10M_Rear Face_10mm_Ch20600_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 5	LTE-FDD, 10175-CAH	844.000, 20600	10.39	0.95	43.2

Hardware Setup

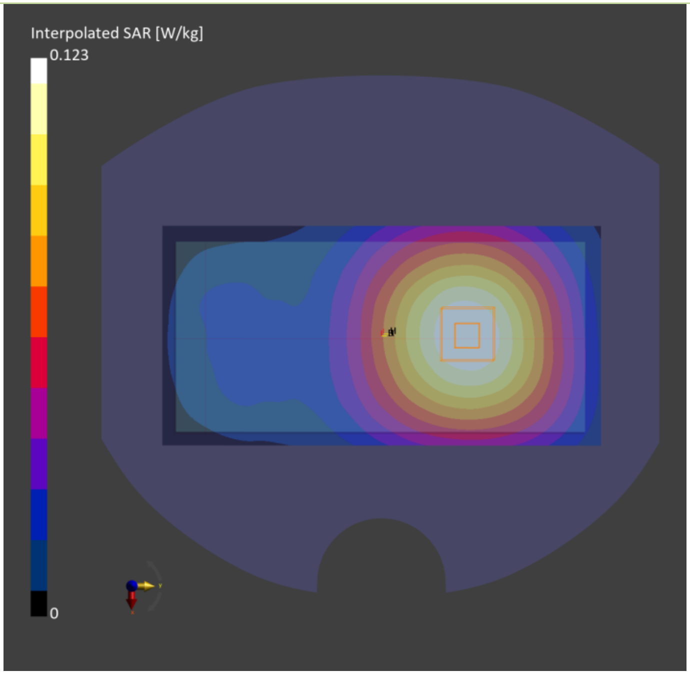
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.109	0.114
psSAR10g [W/kg]	0.076	0.086
Power Drift [dB]	0.08	0.06
M2/M1 [%]		75.5
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P53 LTE 7_QPSK20M_Front Face_10mm_Ch21350_1RB OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 7	LTE-FDD, 10169-CAF	2560.000, 21350	7.58	1.97	37.2

Hardware Setup

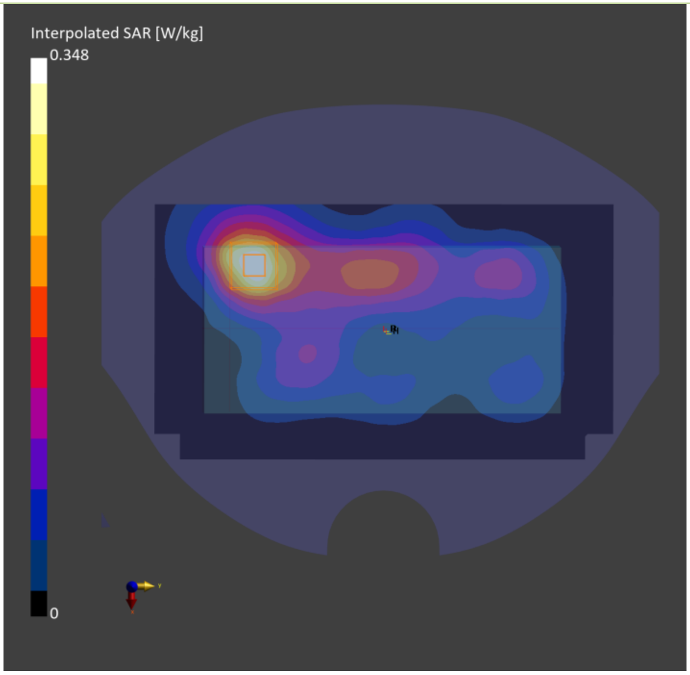
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.283	0.299
psSAR10g [W/kg]	0.150	0.157
Power Drift [dB]	0.10	0.09
M2/M1 [%]		79.3
Dist 3dB Peak [mm]		12.8



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Measurement Report

P54 LTE 12_QPSK10M_Rear Face_10mm_Ch23130_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 12	LTE-FDD, 10175-CAH	711.000, 23130	10.71	0.89	43.5

Hardware Setup

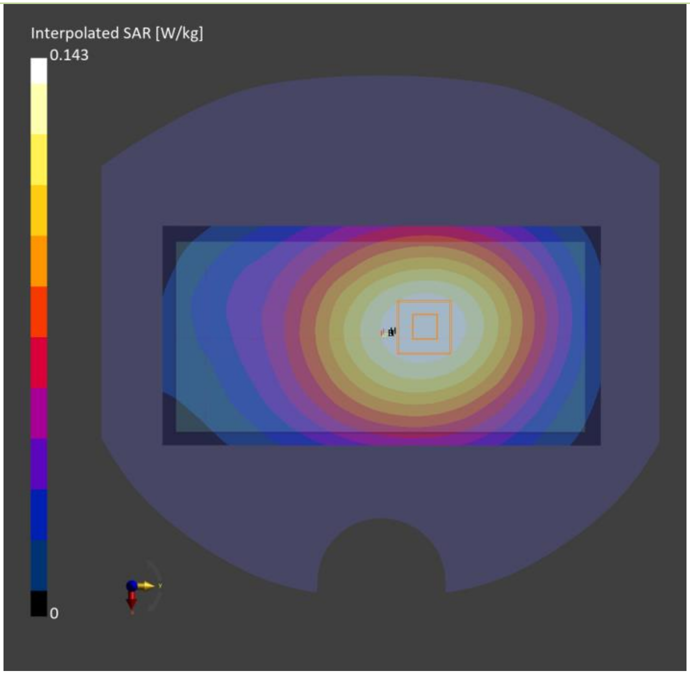
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.127	0.133
psSAR10g [W/kg]	0.091	0.102
Power Drift [dB]	0.05	0.04
M2/M1 [%]		77.6
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P55 LTE 13_QPSK10M_Rear Face_10mm_Ch23230_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 13	LTE-FDD, 10175-CAH	782.000, 23230	10.71	0.92	43.5

Hardware Setup

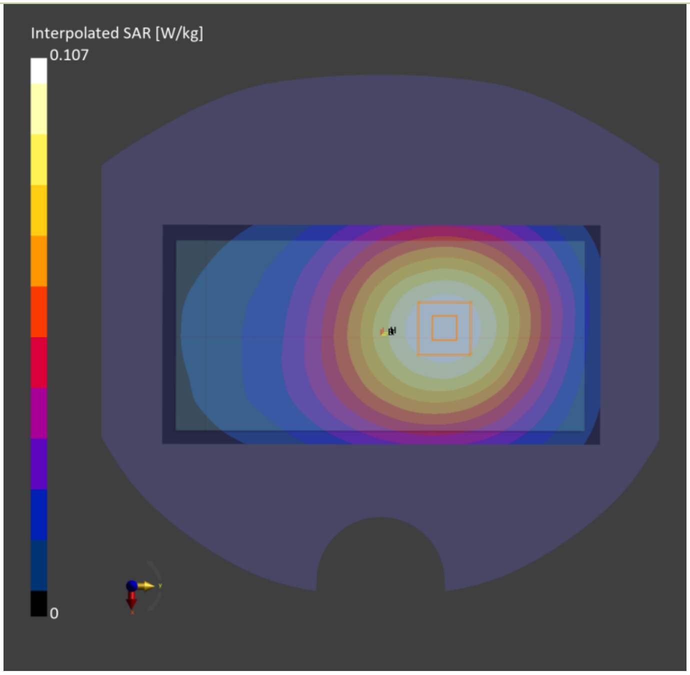
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.094	0.098
psSAR10g [W/kg]	0.067	0.075
Power Drift [dB]	0.03	0.07
M2/M1 [%]		76.8
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P56 LTE 14_QPSK10M_Rear Face_10mm_Ch23330_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 14	LTE-FDD, 10175-CAH	793.000, 23330	10.71	0.92	43.4

Hardware Setup

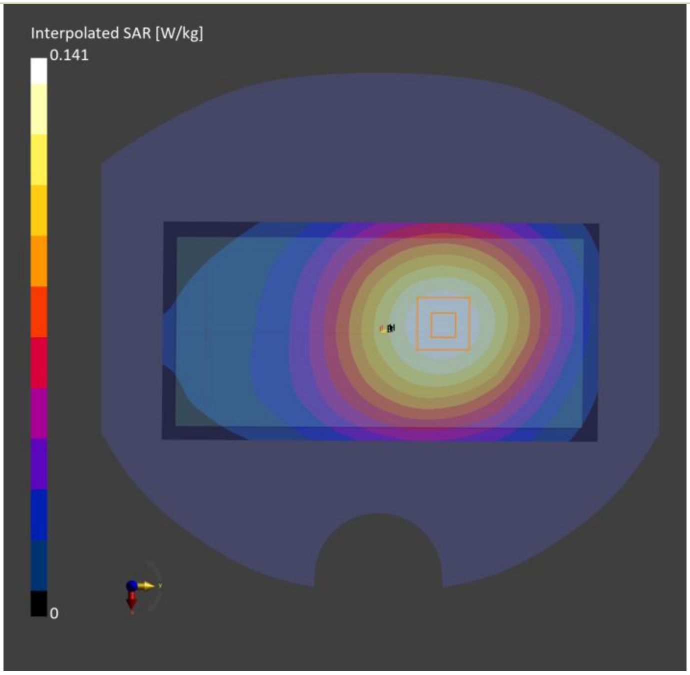
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.124	0.132
psSAR10g [W/kg]	0.088	0.101
Power Drift [dB]	0.03	0.05
M2/M1 [%]		76.9
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P57 LTE 17_QPSK10M_Rear Face_10mm_Ch23800_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 17	LTE-FDD, 10175-CAH	711.000, 23800	10.71	0.89	43.5

Hardware Setup

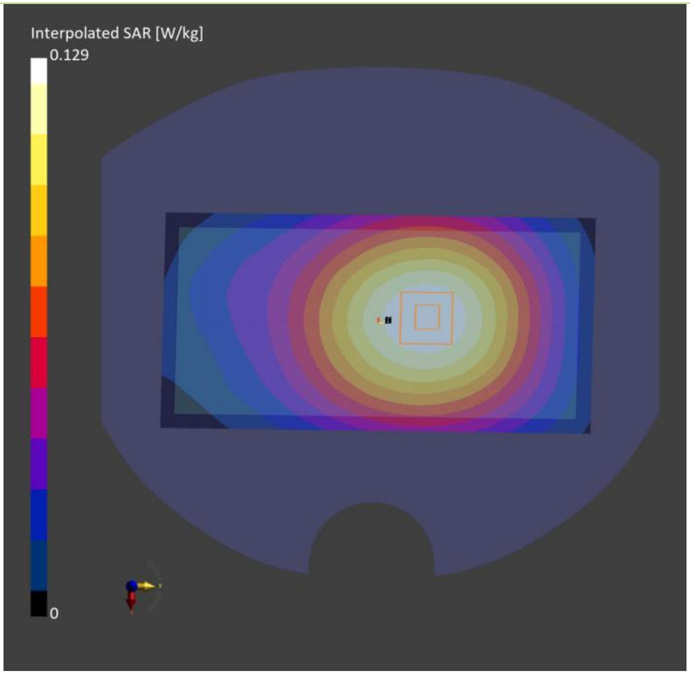
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.115	0.119
psSAR10g [W/kg]	0.082	0.092
Power Drift [dB]	0.05	0.04
M2/M1 [%]		90.3
Dist 3dB Peak [mm]		> 18.0



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Measurement Report

P58 LTE 25_QPSK20M_Rear Face_10mm_Ch26590_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 25	LTE-FDD, 10169-CAF	1905.000, 26590	8.31	1.46	38.2

Hardware Setup

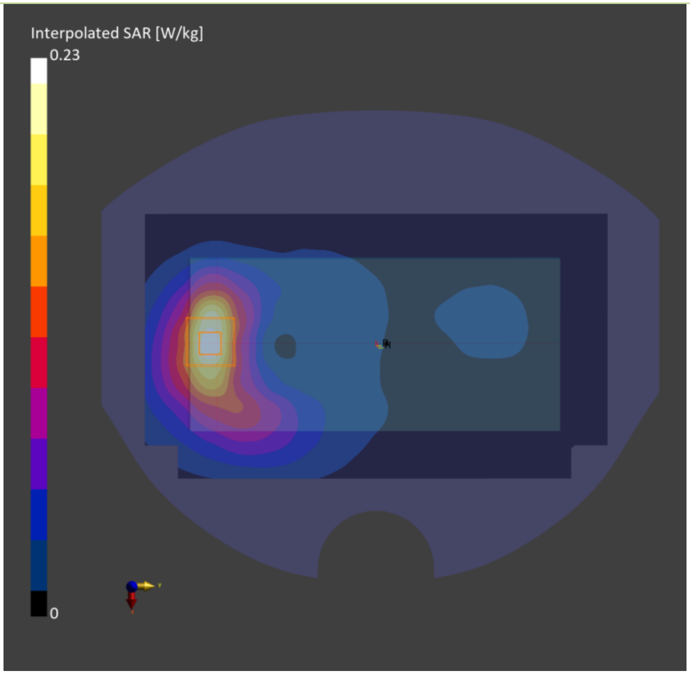
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	0.185	0.192
psSAR10g [W/kg]	0.103	0.111
Power Drift [dB]	0.10	0.00
M2/M1 [%]		58.3
Dist 3dB Peak [mm]		12.9



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Measurement Report

P59 LTE 26_QPSK15M_Rear Face_10mm_Ch26865_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 26	LTE-FDD, 10181-CAF	831.500, 26865	10.39	0.87	42.8

Hardware Setup

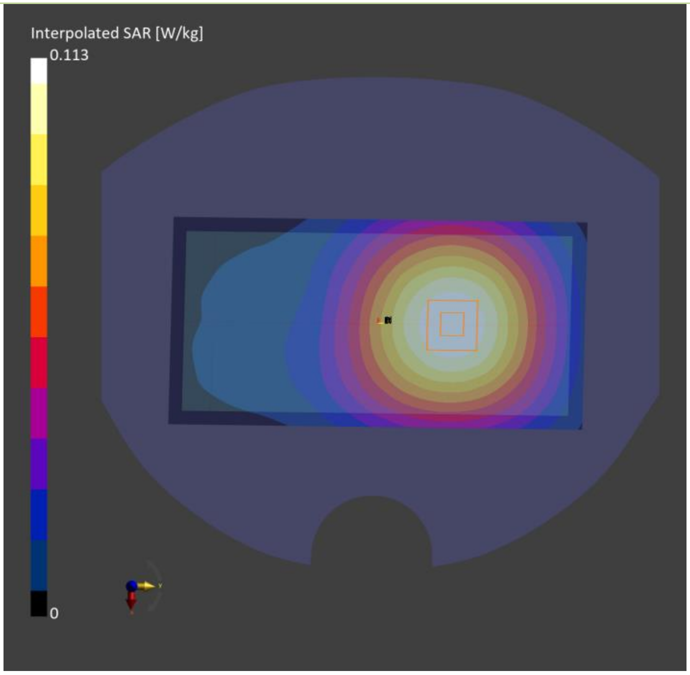
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.100	0.106
psSAR10g [W/kg]	0.071	0.080
Power Drift [dB]	0.09	0.09
M2/M1 [%]		76.2
Dist 3dB Peak [mm]		> 16.0



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Measurement Report

P60 LTE 30_QPSK10M_Front Face_10mm_Ch27710_1RB OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 30	LTE-FDD, 10175-CAH	2310.000, 27710	7.95	1.76	37.6

Hardware Setup

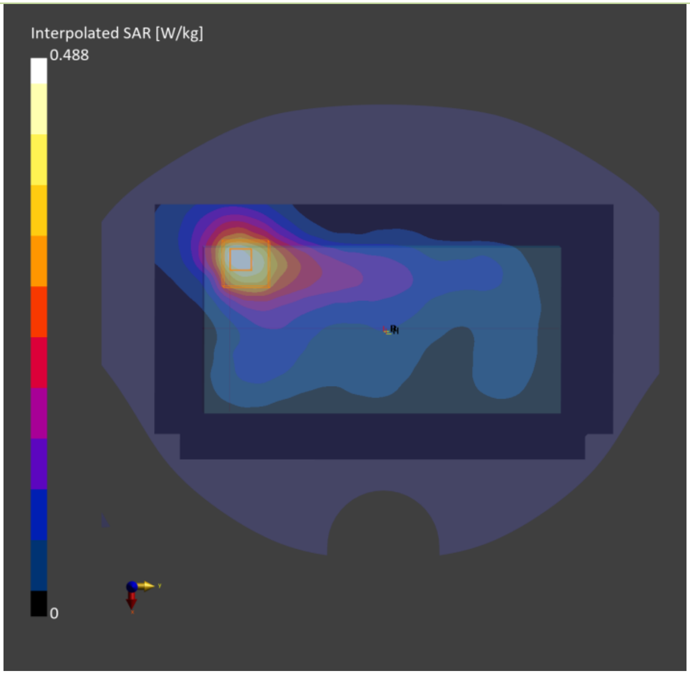
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.393	0.418
psSAR10g [W/kg]	0.210	0.222
Power Drift [dB]	0.02	-0.16
M2/M1 [%]		53.6
Dist 3dB Peak [mm]		11.7



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Measurement Report

P61 LTE 38_QPSK20M_Front Face_10mm_Ch37850_1RB OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 38	LTE-TDD, 10172-CAH	2580.000, 37850	7.58	1.99	37.1

Hardware Setup

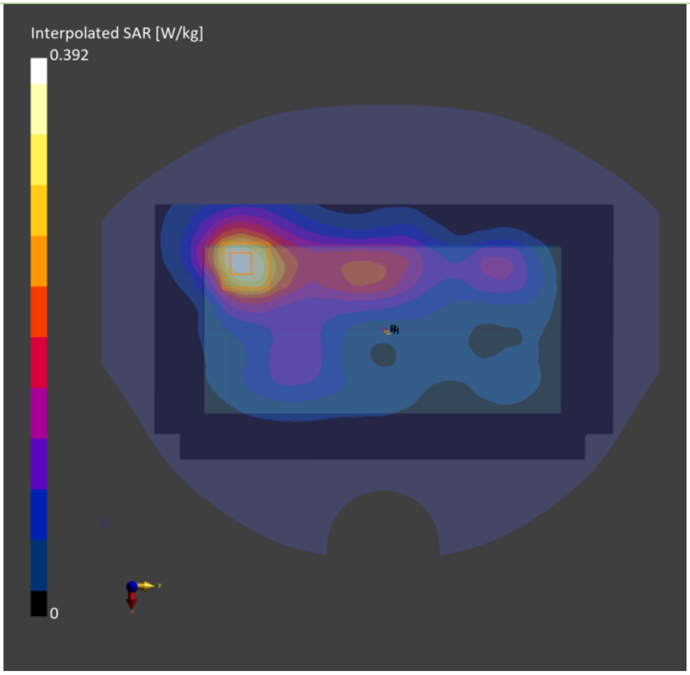
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.314	0.333
psSAR10g [W/kg]	0.166	0.173
Power Drift [dB]	0.09	0.00
M2/M1 [%]		50.0
Dist 3dB Peak [mm]		12.3



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Measurement Report

P62 LTE 41_QPSK20M_Front Face_10mm_Ch40185_1RB OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 41	LTE-TDD, 10172-CAH	2549.500, 40185	7.58	1.97	37.2

Hardware Setup

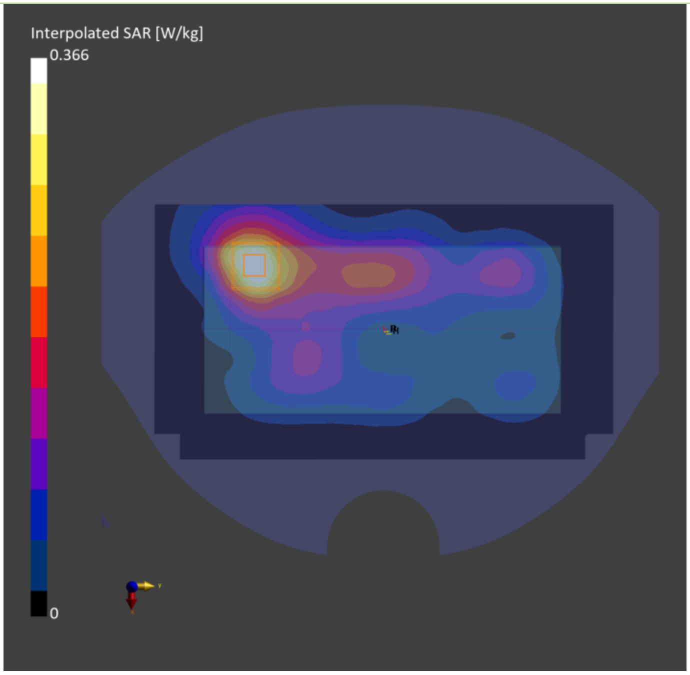
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.298	0.317
psSAR10g [W/kg]	0.158	0.165
Power Drift [dB]	0.15	0.04
M2/M1 [%]		50.2
Dist 3dB Peak [mm]		12.3



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Measurement Report
P63 LTE 42_QPSK20M_Rear Face_10mm_Ch43340_1RB OS50_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 42	LTE-TDD, 10172-CAH	3575.000, 43340	6.65	2.85	39.3

Hardware Setup

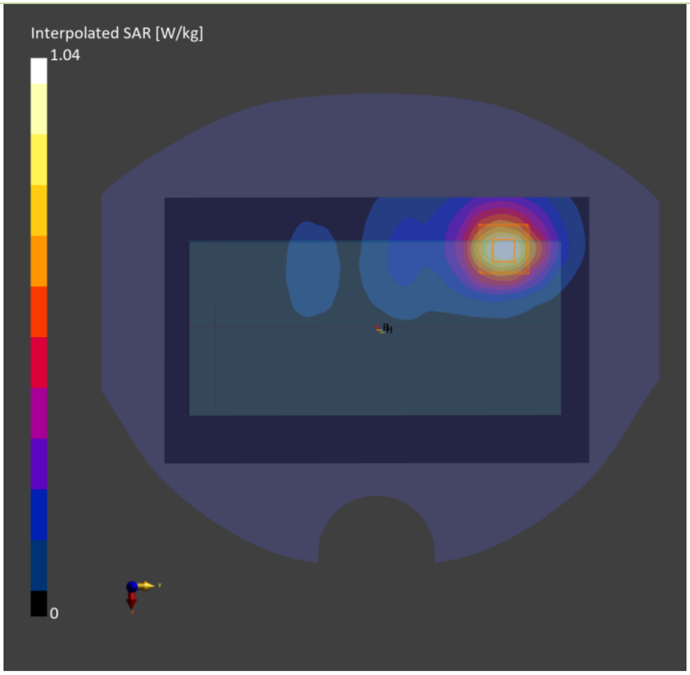
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 192.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.779	0.813
psSAR10g [W/kg]	0.355	0.380
Power Drift [dB]	0.11	0.05
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		13.1



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Measurement Report

P64 LTE 43_QPSK20M_Rear Face_10mm_Ch44190_1RB OS0_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 43	LTE-TDD, 10172-CAH	3660.000, 44190	6.6	2.93	39.1

Hardware Setup

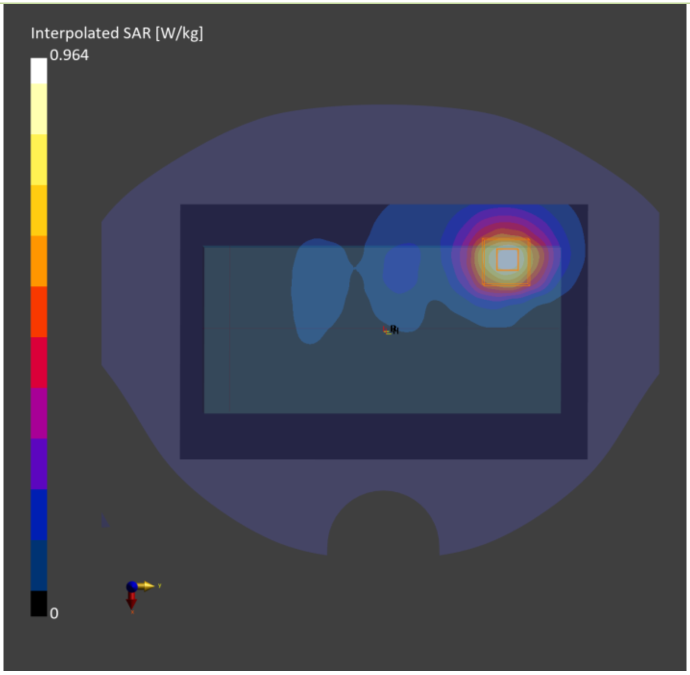
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 192.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.735	0.806
psSAR10g [W/kg]	0.337	0.372
Power Drift [dB]	-0.09	0.04
M2/M1 [%]		78.1
Dist 3dB Peak [mm]		12.2



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Measurement Report

P65 LTE 48_QPSK20M_Rear Face_10mm_Ch55780_1RB OS0_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 48	LTE-TDD, 10172-CAH	3603.000, 55780	6.6	2.92	39.4

Hardware Setup

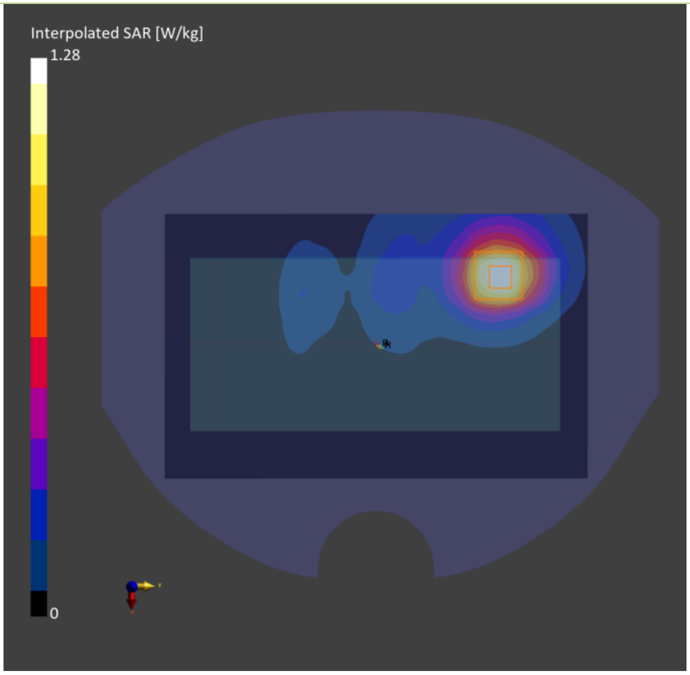
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 192.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	0.719	0.736
psSAR10g [W/kg]	0.371	0.324
Power Drift [dB]	0.07	-0.00
M2/M1 [%]		62.2
Dist 3dB Peak [mm]		13.7



Plots of Measurement

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Measurement Report

P66 LTE 66_QPSK20M_Rear Face_10mm_Ch132572_1RB OS0_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	8.74	1.43	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	0.410	0.436
psSAR10g [W/kg]	0.235	0.266
Power Drift [dB]	0.06	-0.01
M2/M1 [%]		63.5
Dist 3dB Peak [mm]		14.4